Kelvin probe force microscopy

DOI: 10.1063/1.105227
Applied Physics Letters, 1991, 58, 2921-2923.

Source: https://exaly.com/paper-pdf/22470777/citation-report.pdf
Version: 2024-04-24

#	Paper	IF	Citations
1998	Probing the Intrinsic Thermal and Photochemical Stability of Hybrid and Inorganic Lead Halide Perovskites.		
1997	Work-function anisotropies as an origin of long-range surface forces. **1992**, 69, 144-147		86
1996	Scanning probe microscopy of thermal conductivity and subsurface properties. *Applied Physics Letters*, **1992**, 61, 168-170	3.4	149
1995	Surface investigations with a Kelvin probe force microscope. **1992**, 42-44, 268-273		86
1994	Optical absorption spectroscopy by scanning force microscopy. **1992**, 42-44, 351-354		17
1993	Shallow trench isolation double-diobe electrostatic discharge circuit and interaction with DRAM output circuitry. **1993**, 31, 237-262		31
1992	The scanning Kelvin microscope. **1993**, 64, 694-699		40
1991	Heterodyne Force-Detection for High Frequency Local Dielectric Spectroscopy by Scanning Maxwell Stress Microscopy. *Japanese Journal of Applied Physics*, **1993**, 32, L1845-L1848	1.4	27
1990	Dynamic mode force microscopy for the detection of lateral and vertical electrostatic forces. *Applied Physics Letters*, **1993**, 63, 2573-2575	3.4	9
1989	Interpretation of force curves in force microscopy. **1993**, 4, 64-80		270
1988	3. Extensions of STM. **1993**, 77-94		
1987	Optical near-field imaging with a semiconductor probe tip. *Applied Physics Letters*, **1994**, 64, 2338-2340	3.4	29
1986	Scanned electrostatic force microscope for noninvasive high frequency potential measurement. *Applied Physics Letters*, **1994**, 64, 1442-1444	3.4	15
1985	Sampled waveform measurement in integrated circuits using heterodyne electrostatic force microscopy. **1994**, 65, 3378-3381		11
1984	Nonresonant detection of electric force gradients by dynamic force microscopy. *Applied Physics Letters*, **1994**, 65, 3143-3145	3.4	43
1983	Surface potential imaging of phase-separated LB monolayers by scanning Maxwell stress microscopy. **1994**, 243, 399-402		24
1982	Scanning maxwell stress microscope for nanometre-scale surface electrostatic imaging of thin films. **1994**, 242, 33-39		101

1981	Scanning surface potential microscope for characterization of Langmuir-Blodgett films. **1994**, 242, 163-169		52
1980	Imaging high frequency dielectric dispersion of surfaces and thin films by heterodyne force-detected scanning Maxwell-stress microscopy. **1994**, 93, 359-373		11
1979	Dipole potential of lipid membranes. **1994**, 73, 57-79		333
1978	. **1994**, 43, 469-474		8
1977	Conducting AFM: Applications to Semiconductor Surfaces. **1995**, 386, 371		
1976	Application of Atomic Force Microscopy to Ultrastructural and Histochemical Studies of Fixed and Embedded Cells. **1995**,		
1975	Comparisons of experimental data to indices of adhesion derived from dielectric models. **1995**, 35, 1811-1817		1
1974	In-situ measurement of electric fields at individual grain boundaries in TiO2. **1995**, 75, 35-42		16
1973	Design and calibration of a scanning force microscope for friction, adhesion, and contact potential studies. **1995**, 66, 4566-4574		46
1972	Atomic-force microscopy on the Si(111)7 x 7 surface. **1995**, 51, 5484-5487		71
1971	Attractive Forces Between Micron-Sized Particles: A Patch Charge Model. **1995**, 51, 71-86		18
1970	Competition between Electrostatic and Capillary Forces Acting on a Single Particle. *Japanese Journal of Applied Physics*, **1995**, 34, 4176-4184	1.4	10
1969	Improvement of Kelvin Probe Force Microscope (KFM) System. *Japanese Journal of Applied Physics*, **1995**, 34, 3403-3405	1.4	16
1968	DRAM failure analysis with the force-based scanning Kelvin probe. **1995**,		2
1967	Kelvin probe force microscopy for potential distribution measurement of semiconductor devices. **1995**, 77, 2358-2362		112
1966	Two-dimensional surface dopant profiling in silicon using scanning Kelvin probe microscopy. **1995**, 77, 1888-1896		162
1965	Potential profile measurement of cleaved surface of GaAs HEMTs by Kelvin probe force microscopy.		6
1964	Surface potential measurements using the Kelvin probe force microscope. **1996**, 273, 279-283		50

1963	Scanning probe microscopies for molecular photodiodes. **1996**, 273, 168-176		22
1962	Scanning probe microscopy for 2-D semiconductor dopant profiling and device failure analysis. **1996**, 42, 88-98		26
1961	Nanoscale characterization of semiconductor materials and devices using scanning probe techniques. **1996**, 17, 147-206		24
1960	Methods for simultaneous measurements of topography and local electrical properties using scanning force microscopy.		5
1959	Vacuum compatible high-sensitive Kelvin probe force microscopy. **1996**, 67, 1463-1467		98
1958	Thermal conductivity and diffusivity measurements in the sub-µm and sub-µs scale on centimeter area samples using a microthermocouple. **1996**, 67, 4246-4255		25
1957	Construction of well organized functional Langmuir-Blodgett films by mimicking structures and functions of biological membranes. **1996**, 4, 181-209		1
1956	Scanning Maxwell stress microscopy for UHV applications. **1997**, 8, A19-A23		4
1955	Local surface potential measurement of Pd/GaAs contact and anodized aluminum films using scanning probe microscopy. **1997**, 8, A24-A31		5
1954	Noninvasive probing of high frequency signal in integrated circuits using electrostatic force microscope. **1997**, 68, 4506-4510		3
1953	A high-resolution scanning Kelvin probe microscope for contact potential measurements on the 100 nm scale. **1997**, 68, 3108-3111		37
1952	Kelvin Probe Force Microscopy for Potential Distribution Measurement of Cleaved Surface of GaAs Devices. *Japanese Journal of Applied Physics*, **1997**, 36, 1826-1829	1.4	33
1951	Two-dimensional potential profile measurement of GaAs HEMT's by Kelvin probe force microscopy. **1997**, 18, 423-425		29
1950	The Formation of Nano-Dot and Nano-Ring Structures in Colloidal Monolayer Lithography□ **1997**, 13, 7080-7084		90
1949	Absolute quantitative time resolved voltage measurements on 1 µm conducting lines of integrated circuits via electric force microscope-(EFM-) testing. **1997**, 37, 1579-1582		4
1948	Atomic Force Microscope Based Kelvin Probe Measurements: Application to an Electrochemical Reaction. **1997**, 101, 10162-10165		27
1947	Surface potential mapping: A qualitative material contrast in SPM. **1997**, 69, 39-49		174
1946	Effect of tip shape in the design of long distance electrostatic force microscopy. **1997**, 37, 1627-1630		9

1945	Industrial Uses of STM and AFM * *Contribution of the National Institute of Standards and Technology. Not subject to copyright except for illustrations taken from other sources.. **1997**, 46, 597-620		48
1944	Progress in Assessing Surface and Subsurface Integrity. **1998**, 47, 669-693		94
1943	Resolution and contrast in Kelvin probe force microscopy. **1998**, 84, 1168-1173		424
1942	Sub-micrometer thermal physics An overview on SThM techniques1Presented at the Twelfth Ulm-Freiberg Conference, Freiberg, Germany, 1921 March 19971. **1998**, 310, 1-17		62
1941	Microscopy with a single electron transistor probe. **1998**, 107, 657-661		9
1940	Scanning single-electron transistor microscopy: Imaging individual charges. **1998**, 3, 8-14		
1939	Scanned potential microscopy of a two-dimensional electron gas. **1998**, 249-251, 79-83		6
1938	Observation of surface potential at nanometer scale by electrostatic force microscopy (EFM) with large signals. **1998**, 51, 197-201		6
1937	Application of scanning near-field optical microscopy to thin organic film devices. **1998**, 71, 269-274		7
1936	High-resolution imaging of contact potential difference with ultrahigh vacuum noncontact atomic force microscope. *Applied Physics Letters*, **1998**, 72, 3154-3156	3.4	271
1935	Low cost PC based scanning Kelvin probe. **1998**, 69, 3902-3907		120
1934	Nonlinear Optical Films from Pairwise-Deposited Semiionomeric Syndioregic Polymers. **1998**, 267-287		1
1933	Optical Near-Field Imaging Using the Kelvin Probe Technique. *Japanese Journal of Applied Physics*, **1998**, 37, L1074-L1077	1.4	7
1932	Imaging p-n Junctions by Scanning Auger Microscopy. *Japanese Journal of Applied Physics*, **1998**, 37, L963-L965	1.4	2
1931	Tunneling Current and Surface Potential Simultaneous Measurement Using a Scanning Probe. *Japanese Journal of Applied Physics*, **1998**, 37, 4557-4560	1.4	15
1930	Detecting electrical forces in noncontact atomic force microscopy. *Measurement Science and Technology*, **1998**, 9, 734-738	2	19
1929	A method for in situ characterization of tip shape in ac-mode atomic force microscopy using electrostatic interaction. **1998**, 84, 4060-4064		49
1928	Potentiometry and repair of electrically stressed nanowires using atomic force microscopy. *Applied Physics Letters*, **1998**, 72, 915-917	3.4	45

1927	Cross-Sectional Potential Imaging of Compound Semiconductor Heterostructure by Kelvin Probe Force Microscopy. *Japanese Journal of Applied Physics*, **1998**, 37, 1522-1526	1.4	29
1926	Measurement of Contact Potential of GaAs pn Junctions by Kelvin Probe Force Microscopy. *Japanese Journal of Applied Physics*, **1999**, 38, 4893-4894	1.4	17
1925	Direct measurement of minority carriers diffusion length using Kelvin probe force microscopy. *Applied Physics Letters*, **1999**, 75, 2435-2437	3.4	46
1924	Detecting work-function differences in scanning tunneling microscopy. *Applied Physics Letters*, **1999**, 74, 2963-2965	3.4	6
1923	Multitip scanning bio-Kelvin probe. **1999**, 70, 1842-1850		70
1922	Practical aspects of Kelvin probe force microscopy. **1999**, 70, 1756-1760		172
1921	Nanoscale conduction modulation in Au/Pb(Zr, Ti)O3/SrRuO3 heterostructure. *Applied Physics Letters*, **1999**, 75, 1449-1451	3.4	35
1920	Van der Waals and capacitive forces in atomic force microscopies. **1999**, 86, 5245-5248		58
1919	Carbon nanotube-modified cantilevers for improved spatial resolution in electrostatic force microscopy. *Applied Physics Letters*, **1999**, 75, 2842-2844	3.4	29
1918	Measurement of induced surface charges, contact potentials, and surface states in GaN by electric force microscopy. *Applied Physics Letters*, **1999**, 74, 3522-3524	3.4	72
1917	Probing domains at the nanometer scale in piezoelectric thin films. **1999**, 60, 16198-16204		72
1916	Scanned potential microscopy of edge and bulk currents in the quantum Hall regime. **1999**, 59, 4654-4657		110
1915	Topographic and electronic studies of wedge-shape surface defects on AlGaAs/GaAs films grown on Ge substrates. *Applied Physics Letters*, **1999**, 75, 2111-2113	3.4	13
1914	Charge storage in CeO2/Si/CeO2/Si(111) structures by electrostatic force microscopy. *Applied Physics Letters*, **1999**, 75, 1326-1328	3.4	45
1913	Atomic force microscopy of work functions on the nanometer scale. *Applied Physics Letters*, **1999**, 74, 2641-2642	3.4	29
1912	Direct Measurement of Surface Defect Level Distribution Associated with GaAs Antiphase Boundaries. **1999**, 82, 612-615		8
1911	Observation of high field regions in GaAs MESFETs by using Kelvin probe force microscopy.		0
1910	High aspect ratio all diamond tips formed by focused ion beam for conducting atomic force microscopy. **1999**, 17, 1570		43

(1999-1999)

1909	Potential profile measurement of GaAs MESFETs passivated with low-temperature grown GaAs layer by Kelvin probe force microscopy. **1999**, 43, 1547-1553		11
1908	Application of a specialized capacitance probe in bearing diagnosis. **1999**, 225-229, 1215-1221		8
1907	High resolution imaging of contact potential difference using a novel ultrahigh vacuum non-contact atomic force microscope technique. **1999**, 140, 265-270		79
1906	True atomic resolution imaging of surface structure and surface charge on the GaAs(110). **1999**, 140, 371-375		66
1905	Near-field optical imaging using force detection with new tip-electrode geometry. **1999**, 140, 383-387		5
1904	Semiconductor acousto-electric potential detection using a force microscope. **1999**, 140, 394-399		
1903	Imaging of various surface properties of fluorescently labelled phospholipid Langmuir-Blodgett films with a combined scanning probe microscope. **1999**, 194, 467-71		8
1902	Nanometer-Scale Variations in Interface Potential by Scanning Probe Microscopy. **1999**, 82, 1941-1944		35
1901	High-sensitivity quantitative Kelvin probe microscopy by noncontact ultra-high-vacuum atomic force microscopy. *Applied Physics Letters*, **1999**, 75, 286-288	3.4	232
1900	Potential imaging of operating light-emitting devices using Kelvin force microscopy. *Applied Physics Letters*, **1999**, 74, 2972-2974	3.4	76
1899	Digital signal measurements with electric force microscope testing. **1999**, 27, 307-311		
1898	In situ observation of electrode surfaces using scanning Maxwell-stress microscopy under water. **1999**, 27, 317-323		10
1897	Measuring and modifying the electric surface potential distribution on a nanometre scale: a powerful tool in science and technology. **1999**, 27, 361-367		63
1896	Surface potential studies of self-assembling monolayers using Kelvin probe force microscopy. **1999**, 27, 368-373		28
1895	Aspects of dynamic force microscopy on NaCl/Cu(111): resolution, tip�sample interactions and cantilever oscillation characteristics. **1999**, 27, 462-466		47
1894	KELVIN PROBE FORCE MICROSCOPY OF MOLECULAR SURFACES. **1999**, 29, 353-380		135
1893	Electrostatic force microscopy studies of surface defects on GaAs/Ge films. **1999**, 85, 2465-2472		42
1892	Observation of domain dynamics and nanoscale control of domains in ferroelectric materials with scanning probe microscope. **1999**, 229, 131-140		1

1891	Kelvin Probe Force Microscopy on Surfaces: Investigation of the Surface Potential of Self-Assembled Monolayers on Gold. **1999**, 15, 8184-8188		157
1890	Two-dimensional surface band structure of operating light emitting devices. **1999**, 86, 107-113		44
1889	Measurement of Contact Potential of GaAs/AlGaAs Heterostructure Using Kelvin Probe Force Microscopy. *Japanese Journal of Applied Physics*, **1999**, 38, L767-L769	1.4	9
1888	Measurement of hardness, surface potential, and charge distribution with dynamic contact mode electrostatic force microscope. **1999**, 70, 1735-1739		98
1887	Chemical and biochemical analysis using scanning force microscopy. **1999**, 99, 2845-90		231
1886	Nanostructural conductivity and surface-potential study of low-field-emission carbon films with conductive scanning probe microscopy. *Applied Physics Letters*, **1999**, 75, 3527-3529	3.4	46
1885	Changes of Contact Potential Difference Induced by Frictional Damage in Ultrahigh Vacuum. **1999**, 558, 161		
1884	Localized Charge Storage in CeO2/Si(111) By Electrostatic Force Microscopy. **1999**, 584, 331		
1883	Characterization of Ferroelectric BaTiO3 (100) Surfaces by Variable Temperature Scanning Surface Potential Microscopy and Piezoresponse Imaging. **1999**, 596, 327		2
1882	Recent Progress in the Study of Surface Observation Using Scanning Probe Microscopy. **1999**, 40, 169-181		2
1881	Surface Potentials of Conjugated Molecules on Metal Surfaces: Measurements Using Electrostatic Force Microscopy and Calculations using a Preliminary Physically-Based Model.. **2000**, 636, 9381		
1880	Surface structure and polarization effects in GaN Thin Films as studied by Electric Force Microscopy. **2000**, 639, 791		
1879	Scanning Kelvin microscopy as a tool for visualization of optically induced molecular switching in azobenzene self assembling films. **2000**, 30, 549-551		11
1878	Progress in scanning probe microscopy. **2000**, 48, 347-358		60
1877	Measurements of electric potential in a laser diode by Kelvin Probe Force Microscopy. **2000**, 157, 251-255		35
1876	A low-temperature scanning force microscope for investigating buried two-dimensional electron systems under quantum Hall conditions. **2000**, 157, 349-354		24
1875	Study of mixed LangmuirBlodgett films of hydrocarbon and fluorocarbon amphiphilic compounds by scanning surface potential microscopy and friction force microscopy. **2000**, 157, 405-411		25
1874	Phase detection of electrostatic force by AFM with a conductive tip. **2000**, 82, 63-8		25

1873	Investigations into local ferroelectric properties by atomic force microscopy. **2000**, 82, 141-8		18
1872	Chemical force microscopy of microcontact-printed self-assembled monolayers by pulsed-force-mode atomic force microscopy. **2000**, 82, 203-12		49
1871	Kelvin probe microscopy measurements of surface potential change under wear at low loads. **2000**, 244, 104-117		63
1870	Kelvin Probe Force Microscopy on InAs Thin Films on (110) GaAs Substrates. *Japanese Journal of Applied Physics*, **2000**, 39, 3721-3723	1.4	8
1869	Evaluating probes for �electrical� atomic force microscopy. **2000**, 18, 418		54
1868	New aspects of nanopotentiometry for complementary metal�oxide�semiconductor transistors. **2000**, 18, 586		18
1867	Electrical testing of gold nanostructures by conducting atomic force microscopy. **2000**, 18, 1160		44
1866	Charging States of Si Quantum Dots as Detected by AFM/Kelvin Probe Technique. *Japanese Journal of Applied Physics*, **2000**, 39, 2318-2320	1.4	23
1865	Nature of the highly conducting interfacial layer in GaN films. *Applied Physics Letters*, **2000**, 77, 2873-2875	3.4	33
1864	Characterization of AlxGa1�xAs/GaAs heterojunction bipolar transistor structures using cross-sectional scanning force microscopy. **2000**, 87, 1937-1942		24
1863	Effect of phase transition on the surface potential of the BaTiO3 (100) surface by variable temperature scanning surface potential microscopy. **2000**, 87, 3950-3957		85
1862	Status and review of two-dimensional carrier and dopant profiling using scanning probe microscopy. **2000**, 18, 361		156
1861	Imaging of a silicon pn junction under applied bias with scanning capacitance microscopy and Kelvin probe force microscopy. *Applied Physics Letters*, **2000**, 77, 106-108	3.4	45
1860	Spatially localized dynamic properties of individual interfaces in semiconducting oxides. *Applied Physics Letters*, **2000**, 76, 1012-1014	3.4	35
1859	Measuring minority-carrier diffusion length using a Kelvin probe force microscope. **2000**, 61, 11041-11046		45
1858	Scanning Probe Microscopy, Industrial Applications of. **2000**,		
1857	Surface potential at surface-interface junctions in SrTiO3 bicrystals. **2000**, 62, 10419-10430		55
1856	Simulation and correction of geometric distortions in scanning Kelvin probe microscopy. **2000**, 18, 1051-1055		40

1855	. **2000**,		
1854	Mapping the Subsurface Composition of Organic Films by Electric Force Microscopy. **2000**, 16, 5231-5233		20
1853	Electrostatic Force Microscopy Characterization of Trioctylphosphine Oxide Self-assembled Monolayers on Graphite. **2000**, 104, 11936-11941		51
1852	Investigation of the cleaved surface of a p[illegible] laser using Kelvin probe force microscopy and two-dimensional physical simulations. *Applied Physics Letters*, **2000**, 76, 2907-2909	3.4	53
1851	Magnetic-field measurements of current-carrying devices by force-sensitive magnetic-force microscopy with potential correction. *Applied Physics Letters*, **2001**, 78, 1005-1007	3.4	13
1850	Electrostatic force microscopy: principles and some applications to semiconductors. **2001**, 12, 485-490		230
1849	Resolution enhancement and improved data interpretation in electrostatic force microscopy. **2001**, 64,		209
1848	A fine needle probe for determining the thermal conductivity of penetrable materials. *Measurement Science and Technology*, **2001**, 12, 58-62	2	20
1847	Dynamic plowing nanolithography on polymethylmethacrylate using an atomic force microscope. **2001**, 72, 136-141		79
1846	Kelvin Probe Force Microscopy Imaging Using Carbon Nanotube Probe. *Japanese Journal of Applied Physics*, **2001**, 40, 4314-4316	1.4	14
1845	Monitoring chemical transformations at buried organic interfaces by electric force microscopy. **2001**, 123, 8412-3		11
1844	Scanning Electric Potential Microscopy Imaging of Polymer Latex Films:´Detection of Supramolecular Domains with Nonuniform Electrical Characteristics. **2001**, 105, 3005-3011		32
1843	Imaging for Uniformity of Lithium Metal Surface Using Tapping Mode-Atomic Force and Surface Potential Microscopy. **2001**, 105, 123-134		30
1842	Supramolecular ionics: electric charge partition within polymers and other non-conducting solids. **2001**, 73, 495-510		12
1841	SURFACE CHARACTERIZATION: COMPOSITION, STRUCTURE AND TOPOGRAPHY. **2001**, 1-53		1
1840	Interface Engineering of Chalcogenide Semiconductors in Thin Film Solar Cells: CdTe as an Example. **2001**, 668, 1		10
1839	Isomerically-Featured Aggregate Images of Phenol-Formaldehyde Monolayers by BAM and SMM. **2001**, 265-283		
1838	1. Surface characterization: Composition, structure and topography. **2001**, 38, 1-109		1

1837	Surface morphology and electronic properties of dislocations in AlGaN/GaN heterostructures. **2001**, 30, 110-114		15
1836	Impurity band in the interfacial region of GaN films grown by hydride vapor phase epitaxy. **2001**, 30, 115-122		8
1835	Highly resolved electric force microscopy of metal-filled anodic alumina. **2001**, 171, 125-129		18
1834	Study of microcontact printed patterns by chemical force microscopy. **2001**, 86, 75-83		27
1833	Near-field fluorescence imaging and simultaneous observation of surface potentials. **2001**, 202, 413-9		5
1832	Scanning electric potential microscopy imaging of polymers: electrical charge distribution in dielectrics. **2001**, 42, 4845-4851		36
1831	Epitaxial layer sheet resistance outside and under ohmic contacts measurements using electrostatic force microscopy. **2001**, 45, 1071-1076		6
1830	Langmuir and Langmuir-Blodgett films of amphiphilic hexa-peri-hexabenzocoronene: new phase transitions and electronic properties controlled by pressure. **2001**, 7, 4894-901		70
1829	Introduction to Scanning Probe Lithography. **2001**, 1-22		1
1828	Surface Potential Measurement of Oligothiophene Ultrathin Films by Kelvin Probe Force Microscopy. *Japanese Journal of Applied Physics*, **2001**, 40, 4381-4383	1.4	13
1827	Kelvin Probe Force Microscopy Images of Microstructured Organosilane Self-Assembled Monolayers. *Japanese Journal of Applied Physics*, **2001**, 40, 4373-4377	1.4	40
1826	Surface Potential Images of Microstructured Organosilane Self-Assembled Monolayers Acquired by Kelvin Probe Force Microscopy. *Japanese Journal of Applied Physics*, **2001**, 40, L174-L176	1.4	15
1825	Measurement of the contact potential difference with an electrostatic force microscope. **2001**, 22, 657-662		4
1824	Spatial variation of electrical properties in lateral epitaxially overgrown GaN. *Applied Physics Letters*, **2001**, 79, 761-763	3.4	16
1823	Electrical characterization of an operating Si pn-junction diode with scanning capacitance microscopy and Kelvin probe force microscopy. **2001**, 90, 443-448		29
1822	Investigation of inversion domains in GaN by electric-force microscopy. *Applied Physics Letters*, **2001**, 78, 2497-2499	3.4	45
1821	Kelvin probe force microscopy on InAs thin films grown on GaAs giant step structures formed on (110) GaAs vicinal substrates. *Applied Physics Letters*, **2001**, 78, 1086-1088	3.4	26
1820	Evidence for voltage drops at misaligned wafer-bonded interfaces of AlGaInP light-emitting diodes by electrostatic force microscopy. **2001**, 90, 4791-4795		6

1819	Electronic properties of self-assembled monolayers on Au(111) studied by electrical force spectroscopy. **2001**, 63,		2
1818	Superhard, conductive coatings for atomic force microscopy cantilevers. *Applied Physics Letters*, **2001**, 79, 3053-3055	3.4	5
1817	Investigation of Li-doped ferroelectric and piezoelectric ZnO films by electric force microscopy and Raman spectroscopy. *Applied Physics Letters*, **2001**, 79, 812-814	3.4	31
1816	Scanning Kelvin probe microscopy of surface electronic structure in GaN grown by hydride vapor phase epitaxy. **2002**, 91, 9924		38
1815	Hysteretic contact potential changes in nanometallic tunnel junctions in air. **2002**, 66,		4
1814	Contact potential imaging of cleaved mirror surface of 1.3 /spl mu/m buried heterostructure laser diodes by Kelvin probe force microscopy.		
1813	Scanning Kelvin force microscopy imaging of surface potential variations near threading dislocations in GaN. *Applied Physics Letters*, **2002**, 81, 3579-3581	3.4	40
1812	Electric force microscopy investigation of the microstructure of thick film resistors. **2002**, 92, 4705-4711		9
1811	CuGaSe2 solar cell cross section studied by Kelvin probe force microscopy in ultrahigh vacuum. *Applied Physics Letters*, **2002**, 81, 2017-2019	3.4	103
1810	Kelvin probe force microscopy of beveled semiconductors. **2002**, 20, 2133		4
1809	Two-dimensional transverse cross-section nanopotentiometry of actively driven buried-heterostructure multiple-quantum-well lasers. **2002**, 20, 2401		18
1808	Quantitative evaluation of local charge trapping in dielectric stacked gate structures using Kelvin probe force microscopy. **2002**, 20, 1914		17
1807	Characterisation of Nanocrystals by Scanning Capacitance Force Microscopy. **2002**, 738, 511		1
1806	AFM-based Electrical Characterization of Nano-structures. **2002**, 738, 921		
1805	Distinguishing negatively-charged and highly conductive dislocations in gallium nitride using scanning Kelvin probe and conductive atomic force microscopy. **2002**, 743, L2.4.1		0
1804	AFM-based Electrical Characterization of Nano-structures. **2002**, 761, 1		
1803	Contact potential measurement of cleaved mirror surface of 1.3 [micro sign]m buried heterostructure laser diode by Kelvin probe force microscopy. **2002**, 38, 1662		1
1802	Potential shielding by the surface water layer in Kelvin probe force microscopy. *Applied Physics Letters*, **2002**, 80, 1459-1461	3.4	149

1801	Kelvin Probe Force Microscopy of Periodic Ferroelectric Domain Structure in KTiOPO4 Crystals. **2002**, 2, 455-458	29
1800	Molecular Electrostatics of Conjugated Self-Assembled Monolayers on Au(111) Using Electrostatic Force Microscopy. **2002**, 18, 5120-5125	61
1799	Probe diameter and probe–specimen distance dependence in the lateral resolution of a scanning Kelvin probe. **2002**, 91, 1673-1679	55
1798	Imaging mechanism of piezoresponse force microscopy of ferroelectric surfaces. **2002**, 65,	409
1797	Characterization of Surface Topography. **2002**, 275-354	7
1796	Noncontact potentiometry of polymer field-effect transistors. *Applied Physics Letters*, **2002**, 80, 2913-2915 3.4	306
1795	Surface Potential Nanopatterning Combining Alkyl and Fluoroalkylsilane Self-Assembled Monolayers Fabricated via Scanning Probe Lithography. **2002**, 14, 524-526	58
1794	Electrostatic investigation into the bonding of poly(phenylene) thiols to gold. **2002**, 31, 239-245	21
1793	Local electrical characterization of SOI wafers by scanning probe microscopy. **2002**, 91-92, 156-159	3
1792	Scanning electric field sensing for semiconductor dopant profiling. **2002**, 195, 146-154	3
1791	Scanning surface potential microscopic studies of photo-voltaic Langmuir-Blodgett assemblies containing an A-S-D triad molecule. **2002**, 91, 215-20	6
1790	Charge writing on the nanometre scale in a fluorocarbon film. **2002**, 33, 159-162	38
1789	Study of the potential distribution in a forward-biased silicon diode using electrostatic force microscopy. **2002**, 36, 1058-1064	5
1788	The elimination of the 'artifact' in the electrostatic force measurement using a novel noncontact atomic force microscope/electrostatic force microscope. **2002**, 188, 381-385	54
1787	Emerging Trends in Surface Metrology. **2002**, 51, 701-723	58
1786	Electrostatic force gradient signal: resolution enhancement in electrostatic force microscopy and improved Kelvin probe microscopy. **2003**, 14, 332-340	77
1785	First Harmonic (2f) Characterisation of Resonant Frequency and Q-Factor of Micromechanical Transducers. **2003**, 37, 17-33	12
1784	Localized functionalization of surfaces with molecules from solution using electrostatic attraction. **2003**, 67-68, 736-741	21

1783	Microscopic aspects of electrochemical delamination: an SKPFM study. **2003**, 48, 1235-1243	69
1782	Cross-sectional Scanning Probe Microscopy of GaN-based p heterostructures. **2003**, 34, 571-573	3
1781	Local work function of a rutile TiO2()-(1ˆ 1) surface observed by Kelvin probe force microscopy. **2003**, 529, L245-L250	22
1780	Effects of an adsorbed water layer and self-assembled organosilane monolayers on scanning probe microscopy of silicon pn structures. **2003**, 532-535, 999-1003	9
1779	Effect of surface topography on the frictional behavior at the micro/nano-scale. **2003**, 254, 1019-1031	41
1778	Resolution of Kelvin probe force microscopy in ultrahigh vacuum: comparison of experiment and simulation. **2003**, 210, 32-36	63
1777	Observation of stretched single DNA molecules by Kelvin probe force microscopy. **2003**, 210, 73-78	24
1776	Phase-separated alkanethiol self-assembled monolayers investigated by non-contact AFM. **2003**, 210, 99-104	29
1775	Kelvin probe force microscopy on IIIV semiconductors: the effect of surface defects on the local work function. **2003**, 102, 138-142	63
1774	KPFM imaging of Si(1 1 1)-Sb surface for atom distinction using NC-AFM. **2003**, 210, 128-133	49
1773	Correlated scanning Kelvin probe and conductive atomic force microscopy studies of dislocations in gallium nitride. **2003**, 94, 1448-1453	170
1772	Quantitative Noncontact Electrostatic Force Imaging of Nanocrystal Polarizability. **2003**, 107, 1525-1531	126
1771	Controlling Energy-Level Alignments at Carbon Nanotube/Au Contacts. **2003**, 3, 783-787	216
1770	Failure analysis of a cascade laser structure by electrostatic force microscopy. **2003**, 21, 2151	6
1769	Local behavior of complex materials: scanning probes and nano structure. **2003**, 7, 161-171	15
1768	Photoionization of Individual CdSe/CdS Core/Shell Nanocrystals on Silicon with 2-nm Oxide Depends on Surface Band Bending. **2003**, 3, 497-501	52
1767	Coverage Dependent Evolution of Two-Dimensional Dendrimer/Mica Domain Patterns. **2003**, 107, 12762-12767	10
1766	Correct height measurement in noncontact atomic force microscopy. **2003**, 91, 266101	88

1765	Local Surface Potential of GaN Nanostructures Probed by Kelvin Force Microscopy. **2003**, 20, 1822-1825		3
1764	Micromachines as Tools for Nanotechnology. **2003**,		14
1763	Oxide-Semiconductor Interface Characterization Using Kelvin Probe-AFM In Combination With Corona-Charge Deposition. **2003**, 786, 321		
1762	Direct observation of microscopic photoinduced charge redistribution on TiO2 film sensitized by chloroaluminum phthalocyanine and perylenediimide. *Applied Physics Letters*, **2003**, 83, 1896-1898	3.4	33
1761	Discrete electron forces in a nanoparticle-tunnel junction system. **2003**, 118, 9769-9772		11
1760	High-resolution potential mapping in semiconductor nanostructures by cross-sectional scanning tunneling microscopy and spectroscopy. *Applied Physics Letters*, **2003**, 82, 1932-1934	3.4	14
1759	Conductivity of macromolecular networks measured by electrostatic force microscopy. *Applied Physics Letters*, **2003**, 83, 482-484	3.4	39
1758	Kelvin probe spectroscopy of a two-dimensional electron gas below 300 mK. *Applied Physics Letters*, **2003**, 83, 2602-2604	3.4	13
1757	Materials in nanotechnology: New structures, new properties, new complexity. **2003**, 21, S194-S206		14
1756	Electronic structures of fullerenes and metallofullerenes studied by surface potential analysis. **2003**, 68,		27
1755	Potential imaging of pentacene organic thin-film transistors. *Applied Physics Letters*, **2003**, 83, 2366-2368	3.4	138
1754	A hybrid scanning tunneling�tomic force microscope operable in air. **2003**, 74, 4373-4377		2
1753	Morphology of MDMO-PPV:PCBM bulk heterojunction organic solar cells studied by AFM, KFM, and TEM. **2003**, 4801, 40		10
1752	???????????????. **2003**, 54, 957-961		1
1751	Influence of uncompensated electrostatic force on height measurements in non-contact atomic force microscopy. **2004**, 15, S14-S18		34
1750	Kelvin probe force microscopy of alkali chloride thin films on Au(111). **2004**, 15, S9-S13		61
1749	Carbon tips as sensitive detectors for nanoscale surface and sub-surface charge. **2004**, 15, 1302-1306		10
1748	Surface potential and morphology issues of annealed (HfO2)x(SiO2)1� gate oxides. **2004**, 22, 2113		7

1747	Nanoscale measurements and manipulation. **2004**, 22, 1609		45
1746	Nanoscopic electric potential probing: Influence of probe□sample interface on spatial resolution. *Applied Physics Letters*, **2004**, 84, 601-603	3.4	7
1745	Vertically aligned conductive carbon nanotube junctions and arrays for device applications. *Applied Physics Letters*, **2004**, 84, 2889-2891	3.4	8
1744	Kelvin probe force microscopy as a tool for characterizing chemical sensors. *Applied Physics Letters*, **2004**, 85, 3926-3928	3.4	10
1743	Local conductivity and surface photovoltage variations due to magnesium segregation in p-type GaN. **2004**, 95, 6225-6231		19
1742	Imaging of all dangling bonds and their potential on the Ge/Si105 surface by noncontact atomic force microscopy. **2004**, 93, 266102		75
1741	Dynamic force microscopy at high cantilever resonance frequencies using heterodyne optical beam deflection method. *Applied Physics Letters*, **2004**, 85, 6287-6289	3.4	12
1740	Probing electron charging in nanocrystalline Si dots using Kelvin probe force microscopy. *Applied Physics Letters*, **2004**, 85, 3262-3264	3.4	34
1739	Measurement of interface potential change and space charge region across metal/organic/metal structures using Kelvin probe force microscopy. *Applied Physics Letters*, **2004**, 85, 4148-4150	3.4	21
1738	Local electronic transport at grain boundaries in Nb-doped SrTiO3. **2004**, 70,		36
1737	Structural and surface potential characterization of annealed HfO2 and (HfO2)x(SiO2)1-x films. **2004**, 96, 2365-2373		18
1736	Characterization of quantum wells by cross-sectional Kelvin probe force microscopy. *Applied Physics Letters*, **2004**, 85, 5245-5247	3.4	14
1735	Low temperature scanning contact potentiometry. **2004**, 75, 694-698		6
1734	Chromate Conversion Coating on Aluminum Alloys. *Journal of the Electrochemical Society*, **2004**, 151, B359	3.9	28
1733	Quantitative and Nanoscale Surface Potential Tracking of Ionic and Organic Adsorbates at sub-Monolayer Coverage. **2004**, 838, 139		1
1732	Lateral Averaging Effects on Surface Potential Measurements on InAs Dots Studied by Kelvin Probe Force Microscopy. *Japanese Journal of Applied Physics*, **2004**, 43, 4639-4642	1.4	18
1731	Individual Na Adatoms on TiO2(110)-(1ˆ □1) Surface Observed Using Kelvin Probe Force Microscope. *Japanese Journal of Applied Physics*, **2004**, 43, 4647-4650	1.4	27
1730	Strong nonlinear current-voltage behaviour in perovskite-derivative calcium copper titanate. **2004**, 3, 774-8		703

1729	Atomic force microscopy modified for studying electric properties of thin films and crystals. Review. **2004**, 49, 476-499		34
1728	Atomic force microscope equipped with confocal laser scanning microscope for the spectroscopic measurement of the contact area in liquid. **2004**, 385, 507-511		13
1727	Formation of a cerium-based conversion coating on AA2024: relationship with the microstructure. **2004**, 176, 365-381		218
1726	A study of TaN film field electron emitter material by a Kelvin probe force microscope. **2004**, 71, 343-347		1
1725	Tip-to-sample distance dependence of an electrostatic force in KFM measurements. **2004**, 100, 287-92		18
1724	Surface structure of Au/InSb(001) system investigated with scanning force microscopy. **2004**, 74, 223-227		15
1723	Dynamic force microscopy and Kelvin probe force microscopy of KBr film on InSb(001) surface at submonolayer coverage. **2004**, 566-568, 63-67		23
1722	Investigation of local work function distribution of field emission cathode from carbon materials doped by Ba with the help of AFM/SEM/X-ray. **2004**, 65, 159-163		2
1721	Scanning Maxwell stress microscopy of photo-induced charge separation in A□D triad monolayers. **2004**, 166, 45-56		4
1720	Micromechanical electrostatic field sensor for the characterization of charges in MEMS devices. **2004**, 115, 280-285		2
1719	Microstructural origin of leakage current in GaN/InGaN light-emitting diodes. **2004**, 264, 172-177		106
1718	Spatial distribution of serum solutes on dry latex sub-monolayers determined by SEPM, SNOM and SC microscopy. **2004**, 243, 79-87		6
1717	Kelvin-Probe Force Microscopy Defect Study of Ion Implanted Thermal Oxide Thin Films on Silicon.		
1716	Ionic and electronic impedance imaging using atomic force microscopy. **2004**, 95, 8382-8392		121
1715	Kelvin probe force microscopy on corona charged oxidized semiconductor surfaces. *Applied Physics Letters*, **2004**, 85, 4801-4803	3.4	12
1714	Static and dynamic charges: changing perspectives and aims in electron microscopy. **2004**, 10, 685-90		12
1713	Electric Fields on Oxidized Silicon Surfaces:´Static Polarization of PbSe Nanocrystals□ **2004**, 108, 7814-7819		29
1712	Interaction of water with self-assembled monolayers of alkylsilanes on mica. **2004**, 20, 1284-90		36

1711	Micromechanical electrostatic field sensor for the characterization of charges in MEMS devices. **2004**, 115, 280-280		
1710	Quantitative electrostatic force microscopy-phase measurements. **2004**, 15, 627-634		73
1709	Electron-beam-induced potentials in semiconductors: calculation and measurement with an SEM/SPM hybrid system. *Journal Physics D: Applied Physics*, **2004**, 37, 2785-2794	3	20
1708	Charge-Based and Probe Characterization. **2005**, 523-562		0
1707	Contact mode potentiometric measurements with an atomic force microscope on high resistive perovskite thin films. **2005**, 25, 2353-2356		4
1706	Micro- and nanoxerography in liquids controlling pattern definition. **2005**, 78-79, 331-337		28
1705	Epitaxial nanostructures assembled on InSb(001) by submonolayer deposition of gold. **2005**, 81, 394-399		13
1704	Microscopy and single molecule detection in photosynthesis. **2005**, 36, 483-502		16
1703	Modification of electrode materials for plasma torches. **2005**, 200, 254-257		3
1702	Characterization of locally modified diamond surface using Kelvin probe force microscope. **2005**, 581, 207-212		47
1701	PALS and SPM/EFM investigation of charged nanoporous electret films. **2005**, 412, 50-54		16
1700	Diffusion of Li in the silicon oxide films and evaluation of Li-induced surface potential. **2005**, 244, 61-64		4
1699	Local Phenomena in Oxides by Advanced Scanning Probe Microscopy. **2005**, 88, 1077-1098		72
1698	Influence of molecular order on the local work function of nanographene architectures: a Kelvin-probe force microscopy study. **2005**, 6, 2371-5		35
1697	The Art of SPM: Scanning Probe Microscopy in Materials Science. **2005**, 17, 1821-1833		84
1696	Focused ion beam-nanomachined probes for improved electric force microscopy. **2005**, 104, 220-5		23
1695	Coating Carbon Nanotubes with Compound Ultrathin Film: A Novel Route to Functional SPM tips. **2005**, 3, 417-420		2
1694	Measurements of potential barrier height of grain boundaries in polycrystalline silicon by Kelvin probe force microscopy. **2005**, 85, 41-49		42

1693	Surface Potential Investigation on Nano Domain Formation in Lithium Tantalate Single Crystal. **2005**, 902, 1		1
1692	Principles of Basic and Advanced Scanning Probe Microscopy. **2005**, 77-101		
1691	Investigation of Spatial Resolution in Current-Induced Magnetic Field Detection by Magnetic Force Microscopy. *Japanese Journal of Applied Physics*, **2005**, 44, 8625-8629	1.4	2
1690	Sample-and-Hold Operation in Kelvin Probe Force Microscopy. *Japanese Journal of Applied Physics*, **2005**, 44, 6213-6217	1.4	7
1689	Quantitative electrostatic force microscopy on heterogeneous nanoscale samples. *Applied Physics Letters*, **2005**, 87, 154106	3.4	27
1688	Increase in carrier mobility of organic ultrathin-film transistor with increasing molecular layers investigated by Kelvin probe force microscopy. **2005**, 97, 124503		14
1687	Stable charge storage in granular thin films. *Applied Physics Letters*, **2005**, 86, 074105	3.4	8
1686	Time evolution studies of the electrostatic surface potential of low-temperature-grown GaAs using electrostatic force microscopy. **2005**, 97, 043703		3
1685	Electronic transport imaging in a multiwire SnO2 chemical field-effect transistor device. **2005**, 98, 044503		58
1684	Study of optical recording bits by scanning surface potential microscopy. **2005**, 23, 663-665		4
1683	Simultaneous resistance and capacitance cartography by conducting probe atomic force microscopy in contact mode. *Applied Physics Letters*, **2005**, 86, 123103	3.4	10
1682	Nanoscale Electronic Measurements of Semiconductors Using Kelvin Probe Force Microscopy. **2005** , 119-151		1
1681	Theory of electric force microscopy in the parametric amplification regime. **2005**, 71,		15
1680	Dispersive charge transport along the surface of an insulating layer observed by electrostatic force microscopy. **2005**, 71,		26
1679	Electrostatic investigation of charged nanoporous electret materials.		
1678	Frequency-modulation atomic force microscopy at high cantilever resonance frequencies using the heterodyne optical beam deflection method. **2005**, 76, 126110		18
1677	Nanoscale Measurements of Electronic Properties in Organic Thin Film Transistors. **2005**, 871, 1		
1676	Accuracy and resolution limits of Kelvin probe force microscopy. **2005**, 71,		340

1675	Exploring supramolecular interactions and architectures by scanning force microscopies. **2005**, 34, 551-61		74
1674	Reconstruction of electrostatic force microscopy images. **2005**, 76, 083705		87
1673	Nanoscale potential distribution across multiquantum well structures: Kelvin probe force microscopy and secondary electron imaging. **2005**, 98, 084310		18
1672	Lattice distortion and polarization switching in calcium copper titanate. *Applied Physics Letters*, **2005**, 87, 052901	3.4	64
1671	Kelvin force microscopy on diamond surfaces and devices. **2005**, 14, 466-469		39
1670	Effective tip radius in electrostatic force microscopy. *Applied Physics Letters*, **2005**, 86, 123101	3.4	60
1669	Detection of injected charges by Kelvin probe and multimode electrostatic force microscopy.		
1668	Local origins of sensor activity in 1D oxide nanostructures: from spectromicroscopy to device.		
1667	Supramolecular chemistry on water--towards self-assembling molecular electronic circuitry. **2005**, 1812-23		59
1666	Nano- and meso-measurement methods in the study of dielectrics. **2005**, 12, 979-992		11
1665	Polarity effects on ZnO films grown along the nonpolar [1120] direction. **2005**, 95, 226105		62
1664	Work-function changes of treated indium-tin-oxide films for organic light-emitting diodes investigated using scanning surface-potential microscopy. **2005**, 97, 073713		38
1663	Electrostatic patterning of a silica surface: a new model for charge build-up on a dielectric solid. **2005**, 109, 4631-7		19
1662	Relations between sample preparation and SKPFM Volta potential maps on an EN AW-6005 aluminium alloy. **2005**, 47, 1506-1519		54
1661	Direct resistance profile for an electrical pulse induced resistance change device. *Applied Physics Letters*, **2005**, 87, 233506	3.4	73
1660	FM demodulated Kelvin probe force microscopy for surface photovoltage tracking. **2005**, 16, S1-S6		49
1659	Observation of nanoindentation rosettes on {0001}ZnO using scanning Kelvin probe microscopy. *Applied Physics Letters*, **2005**, 87, 131906	3.4	10
1658	Correlation between surface photovoltage and blend morphology in polyfluorene-based photodiodes. **2005**, 5, 559-63		160

1657	Single-Electron Devices. **2005**, 87-121		4
1656	Local work function of Pt clusters vacuum-deposited on a TiO2 surface. **2006**, 110, 17584-8		64
1655	Nanoscale ferroelectrics: processing, characterization and future trends. **2006**, 69, 2443-2474		384
1654	Kelvin probe force microscopy on surfaces of UHV cleaved ionic crystals. **2006**, 17, S155-61		58
1653	Threshold voltage as a measure of molecular level shift in organic thin-film transistors. *Applied Physics Letters*, **2006**, 88, 043509	3.4	24
1652	Surface potential measurements on Ni(Al)GaN lateral Schottky junction using scanning Kelvin probe microscopy. *Applied Physics Letters*, **2006**, 88, 022112	3.4	9
1651	Photoinduced surface potential change of bacteriorhodopsin mutant D96N measured by scanning surface potential microscopy. **2006**, 110, 10982-90		21
1650	Development of Experimental Methods for Determining the Electronic Structure of Organic Materials. **2006**, 455, 145-181		23
1649	Electronic properties of plasma hydrogenated diamond surfaces: A microscopic study. **2006**, 15, 1374-1377		30
1648	Depth profiles of the Fermi level at an amorphous-carbon nitride/SiO2/n-type-Si heterojunction interface obtained by Kelvin probe force microscopy. **2006**, 15, 1378-1382		1
1647	Geometric artefact suppressed surface potential measurements. **2006**, 17, 3728-3733		35
1646	Strain-induced self organization of metal-insulator domains in single-crystalline VO2 nanobeams. **2006**, 6, 2313-7		261
1645	Patterning amyloid peptide fibrils by AFM charge writing. **2006**, 22, 9089-91		22
1644	Probe microscope observation of platinum atoms deposited on the TiO2(110)-(1 x 1) surface. **2006**, 110, 13453-7		78
1643	Wettability patterning of hydroxyapatite nanobioceramics induced by surface potential modification. *Applied Physics Letters*, **2006**, 88, 163902	3.4	39
1642	Higher Harmonics in Dynamic Atomic Force Microscopy. **2006**, 1-36		1
1641	?????????????????????????????????????. **2006**, 45, 734-737		
1640	Guiding self-assembly with the tip of an atomic force microscope. **2002**, 24, 117-20		4

1639	Surface potential of chalcopyrite films measured by KPFM. **2006**, 203, 2571-2580	30
1638	Charge density alterations in human hair fibers: an investigation using electrostatic force microscopy. **2006**, 28, 95-101	10
1637	Kelvin probe force microscopy An appropriate tool for the electrical characterisation of LED heterostructures. **2006**, 46, 1736-1740	10
1636	Electrical properties of laser-ablation-initiated self-organized nanostructures on silicon surface. **2006**, 134, 114-117	12
1635	Properties of dislocation networks formed by Si wafer direct bonding. **2006**, 9, 96-101	14
1634	Characterization of post-copper CMP surface with scanning probe microscopy: Part II: Surface potential measurements with scanning Kelvin probe force microscopy. **2006**, 83, 2355-2358	6
1633	Apparent height in tapping mode of electrostatic force microscopy. **2006**, 106, 582-586	18
1632	Kelvin probe force microscopy of hole leakage from the active region of a working injection-type semiconductor laser diode. **2006**, 40, 982-989	5
1631	Tunable hydroxyapatite wettability: Effect on adhesion of biological molecules. **2006**, 41, 2367-2372	83
1630	Charge storage in silicon-implanted silicondioxide layers examined by scanning probe microscopy. **2006**, 513, 159-165	1
1629	Nanoscale structural and electronic properties of ultrathin blends of two polyaromatic molecules: a Kelvin probe force microscopy investigation. **2006**, 7, 847-53	10
1628	Nanoscale Characterization of the Morphology and Electrostatic Properties of Poly(3-octylthiophene)/Graphite-Nanoparticle Blends. **2006**, 16, 1975-1984	24
1627	Structural and Electrostatic Complexity at a Pentacene/Insulator Interface. **2006**, 16, 879-884	127
1626	Quantitative Measurement of the Local Surface Potential of Conjugated Nanostructures: A Kelvin Probe Force Microscopy Study. **2006**, 16, 1407-1416	50
1625	High-Resolution Characterization of Pentacene/Polyaniline Interfaces in Thin-Film Transistors. **2006**, 16, 2409-2414	80
1624	Electronic Characterization of Organic Thin Films by Kelvin Probe Force Microscopy. **2006**, 18, 145-164	345
1623	Ordered growth and local workfunction measurements of tris(8-hydroxyquinoline) aluminium on ultrathin KBr films. **2006**, 17, S107-11	21
1622	Adsorption of PTCDA on a partially KBr covered Ag(111) substrate. **2006**, 17, 1568-73	38

1621	Investigation of micro-electro-mechanical processing characteristics of layered boron nitride and carbon films. **2006**, 17, 1607-14		4
1620	Application of spectromicroscopy tools to explore local origins of sensor activity in quasi-1D oxide nanostructures. **2006**, 17, 4014-8		9
1619	Three-dimensional observation of nanoscale ferroelectric domains using scanning nonlinear dielectric microscopy with electric field correction by Kelvin probe force microscopy. **2006**, 17, S162-6		8
1618	Nanoscale capacitance imaging with attofarad resolution using ac current sensing atomic force microscopy. **2006**, 17, 4581-7		63
1617	Quantitative analysis of tip-sample interaction in non-contact scanning force spectroscopy. **2006**, 17, 5491-5500		18
1616	A study of the topographic and electrical properties of self-assembled islands of alkylsilanes on mica using a combination of non-contact force microscopy techniques. **2006**, 17, S178-84		12
1615	Formation and process optimization of scanning resistive probe. **2006**, 24, 2417		6
1614	Direct observation of photoinduced charge redistribution of WO3-TiO2 double layer nanocomposite films by photoassisted Kelvin force microscopy. *Applied Physics Letters*, **2006**, 88, 212108	3.4	23
1613	ac driving amplitude dependent systematic error in scanning Kelvin probe microscope measurements: Detection and correction. **2006**, 77, 043711		22
1612	Some Recent Advances in Contactless Silicon Characterization. **2006**, 3, 321-337		1
1611	Light induced electrostatic force spectroscopy: Application to local electronic transitions in InN epifilms. **2006**, 99, 053518		2
1610	Submicron sensors of local electric field with single-electron resolution at room temperature. *Applied Physics Letters*, **2006**, 88, 013901	3.4	69
1609	Signal amplitude and sensitivity of the Kelvin probe force microscopy. *Applied Physics Letters*, **2006**, 88, 043102	3.4	11
1608	Scalable dope-coded biosensing particles for protein detection. *Applied Physics Letters*, **2006**, 88, 043901	3.4	3
1607	Contrast in scanning probe microscopy images of ultrathin insulator films. *Applied Physics Letters*, **2006**, 88, 063107	3.4	5
1606	Control of microcantilevers in dynamic force microscopy using time delayed feedback. **2006**, 77, 053703		38
1605	Method to assess the grain crystallographic orientation with a submicronic spatial resolution using Kelvin probe force microscope. *Applied Physics Letters*, **2006**, 89, 154101	3.4	37
1604	Evaluation of Kelvin probe force microscopy for imaging grain boundaries in chalcopyrite thin films. *Applied Physics Letters*, **2006**, 89, 113120	3.4	38

1603	Comparison of scanning capacitance microscopy and scanning Kelvin probe microscopy in determining two-dimensional doping profiles of Si homostructures. **2006**, 24, 404		12
1602	Compensating electrostatic forces by single-scan Kelvin probe force microscopy. **2007**, 18, 225505		46
1601	Electrical Scanning Probe Microscopy of Biomolecules on Surfaces and at Interfaces. **2007**, 601-614		2
1600	Kelvin Probe Force Microscopy without Bias-Voltage Feedback. *Japanese Journal of Applied Physics*, **2007**, 46, 5626-5630	1.4	34
1599	Local characterization of vapor-deposited electrode edges in thin film organic electronic devices. **2007**, 25, 421		2
1598	Protocol Optimisation For Work-Function Measurements Of Metal Gates Using Kelvin Force Microscopy. **2007**,		2
1597	Scanning Kelvin Force Microscopy For Characterizing Nanostructures in Atmosphere. **2007**,		5
1596	Characterization of Al-doped ZnTe layer using scanning capacitance microscopy and Kelvin probe force microscopy. **2007**, 61, 1162-1166		1
1595	Photovoltage Mapping on Polycrystalline Silicon Solar Cells by Kelvin Probe Force Microscopy with Piezoresistive Cantilever. *Japanese Journal of Applied Physics*, **2007**, 46, 5548-5551	1.4	30
1594	Electrical Properties of Single Carbon Nanofibers Grown on Tips of Scanning Probe Microscope Cantilevers by Ion Irradiation. *Japanese Journal of Applied Physics*, **2007**, 46, 5607-5610	1.4	8
1593	Multi-Probe Atomic Force Microscopy Using Piezoelectric Cantilevers. *Japanese Journal of Applied Physics*, **2007**, 46, 5543-5547	1.4	20
1592	Work-function measurement by high-resolution scanning Kelvin nanoprobe. *Measurement Science and Technology*, **2007**, 18, 567-578	2	19
1591	Improving sensitivity in electrostatic force detection utilizing cantilever with tailored resonance modes. *Applied Physics Letters*, **2007**, 90, 053113	3.4	6
1590	Triboelectricity evaluation of single toner particle by electron holography. **2007**, 102, 054908		14
1589	An intercepted feedback mode for light sensitive spectroscopic measurements in atomic force microscopy. **2007**, 78, 106104		13
1588	Contact potential measurement using a heated atomic force microscope tip. *Applied Physics Letters*, **2007**, 91, 143111	3.4	14
1587	Tunneling spectroscopy of Stark-shifted image potential states on Cu and Au surfaces. **2007**, 76,		53
1586	Dissipative force modulation Kelvin probe force microscopy applying doubled frequency ac bias voltage. *Applied Physics Letters*, **2007**, 90, 033118	3.4	6

1585	High speed atomic force microscope lithography driven by electrostatic interaction. *Applied Physics Letters*, **2007**, 91, 023121	3.4	6
1584	Spin-current-induced charge accumulation and electric current in semiconductor nanostructures with Rashba spin-orbit coupling. **2007**, 76,		25
1583	A low temperature scanning tunneling microscope for electronic and force spectroscopy. **2007**, 78, 113705		23
1582	Noncontact-mode scanning capacitance force microscopy towards quantitative two-dimensional carrier profiling on semiconductor devices. *Applied Physics Letters*, **2007**, 90, 083101	3.4	12
1581	Ultra-fast High Resolution Microscopy: Options for Pump-probe Methods. **2007**, 1026, 1		
1580	Plasticity Mechanism of Indium Antimony (InSb) in the Brittle Regime: Combined Study with Conventional TEM and LACBED. **2007**, 1026, 1		
1579	Scanning Kelvin probe force microscopy (SKPFM) applied to various conversion coated aluminium surfaces. **2007**, 99-110		1
1578	Local work function analysis of Pt/TiO2photocatalyst by a Kelvin probe force microscope. **2007**, 18, 084007		47
1577	Multifrequency electrostatic force microscopy in the repulsive regime. **2007**, 18, 065502		70
1576	LangmuirBlodgett (LB) Films on Electrodes. **2007**,		
1575	Unconventional nanotubes self-assembled in alumina channels: morphology and surface potential of isolated nanostructures at surfaces. **2007**, 365, 1577-88		2
1574	Electrical, Physical, and Chemical Characterization. **2007**, 28-1-28-79		
1573	Microcharacterization of Semiconductor Device Materials using Kelvin Probe Microscopy. **2007**, 13,		
1572	Optical second harmonic generation imaging for visualizing in-plane electric field distribution. **2007**, 15, 15964-71		24
1571	Use of tip-enhanced vibrational spectroscopy for analytical applications in chemistry, biology, and materials science. **2007**, 115-155		7
1570	Nanoscale Mapping of Strain and Composition in Quantum Dots Using Kelvin Probe Force Microscopy. **2007**, 7, 2089-2093		25
1569	Establishing Efficient Electrical Contact to the Weak Crystals of Triethylsilylethynyl Anthradithiophene. **2007**, 19, 5210-5215		35
1568	Preparation and characterization of dense films of poly(amidoamine) dendrimers on indium tin oxide. **2007**, 23, 8916-24		44

1567	Principles of Kelvin Probe Force Microscopy. **2007**, 113-131		19
1566	Scanning Probe Microscopy in Materials Science. **2007**, 929-968		2
1565	Surface-potential heterogeneity of reacted calcite and rhodochrosite. **2007**, 41, 6491-7		16
1564	Local potential distribution of macrophase separated polymer blend domains. *Journal Physics D: Applied Physics*, **2007**, 40, 4855-4865	3	4
1563	Nanoscale quantitative stress mapping with atomic force microscopy. *Applied Physics Letters*, **2007**, 90, 113111	3.4	9
1562	An alternative method to measure charge distributions: The scanning Kelvin probe. **2007**,		
1561	Ionic electrets: electrostatic charging of surfaces by transferring mobile ions upon contact. **2007**, 129, 4075-88		128
1560	Scanning Kelvin probe imaging of the potential profiles in fixed and dynamic planar LECs. **2007**, 129, 15903-10		88
1559	Effect of formation temperature and roughness on surface potential of octadecyltrichlorosilane self-assembled monolayer on silicon surfaces. **2007**, 111, 12339-43		24
1558	Direct Probing of Electrical Double Layers by Scanning Electrochemical Potential Microscopy. *Journal of Physical Chemistry C*, **2007**, 111, 4620-4627	3.8	23
1557	Metal nanostructures assembled at semiconductor surfaces studied with high resolution scanning probes. **2007**, 18, 044016		8
1556	An elevated level of cholesterol impairs self-assembly of pulmonary surfactant into a functional film. **2007**, 93, 674-83		81
1555	Kelvin probe force and surface photovoltage microscopy observation of minority holes leaked from active region of working InGaAsAlGaAsGaAs laser diode. **2007**, 101, 024504		12
1554	Exploring nanoscale electrical and electronic properties of organic and polymeric functional materials by atomic force microscopy based approaches. **2007**, 3326-37		38
1553	Observation of cross-sectional electric field for GaN-based field effect transistor with field-modulating plate. *Applied Physics Letters*, **2007**, 90, 213504	3.4	7
1552	Local surface charges direct the deposition of carbon nanotubes and fullerenes into nanoscale patterns. **2007**, 7, 3007-12		39
1551	Dual-frequency resonance-tracking atomic force microscopy. **2007**, 18, 475504		365
1550	Theoretical Analyses of Local Tunneling Barrier Height Based on Ab Initio Calculation. **2007**, 28, 593-600		

1549	Dynamic electrochemical-etching technique for tungsten tips suitable for multi-tip scanning tunneling microscopes. **2007**, 5, 94-98	33
1548	A Kelvin Probe Force Microscopy Study of the Photogeneration of Surface Charges in All-Thiophene Photovoltaic Blends. **2007**, 17, 472-478	66
1547	A Multiprotein Microarray on Silicon Dioxide Fabricated by Using Electric-Droplet Lithography. **2007**, 19, 2469-2473	8
1546	Probing Local Electronic Transport at the Organic Single-Crystal/Dielectric Interface. **2007**, 19, 2267-2273	37
1545	New method for electrostatic force gradient microscopy observations and Kelvin measurements under vacuum. **2007**, 107, 1027-32	12
1544	Microscopic characterization of individual grain boundaries in Cu-III▯VI2 chalcopyrites. **2007**, 515, 6136-6141	15
1543	High-resolution Kelvin probe microscopy in corrosion science: Scanning Kelvin probe force microscopy (SKPFM) versus classical scanning Kelvin probe (SKP). **2007**, 53, 290-299	230
1542	On the reliability of scanning probe based electrostatic force measurements. **2007**, 84, 512-516	5
1541	Interfacial state and potential barrier height associated with grain boundaries in polycrystalline silicon. **2007**, 462, 61-67	26
1540	High resolution electrical characterisation of organic photovoltaic blends. **2007**, 84, 431-436	21
1539	Selective deposition of functionalized nano-objects by nanoxerography. **2007**, 84, 1423-1426	15
1538	Magnetic resonance force microscopy combined with surface topography. **2007**, 188, 380-6	3
1537	Scanning probe studies of the electrical activity at interfaces formed by silicon wafer direct bonding. **2007**, 4, 2893-2897	
1536	Electrostatic force microscopy study of electrical conductivity of hydrogen-terminated CVD diamond films. **2007**, 204, 2915-2919	
1535	High-resolution morphological and electrical characterisation of organic bulk heterojunction solar cells by scanning probe microscopy. **2007**, 15, 713-726	32
1534	Label-free and high-resolution protein/DNA nanoarray analysis using Kelvin probe force microscopy. **2007**, 2, 653-9	153
1533	Biosensing: Taking charge of biomolecules. **2007**, 2, 596-7	39
1532	Atomic force microscopy study of the degradation mechanism of ultrathin HfO2 layers on silicon during vacuum annealing. **2007**, 1, 84-89	1

1531	Single quantum dot nanowire LEDs. **2007**, 7, 367-71	310
1530	Noncontact atomic force microscopy studies of vacancies and hydroxyls of TiO2(110): Experiments and atomistic simulations. **2007**, 76,	86
1529	Characterization of electronic materials and devices by scanning near-field microscopy. **2007**, 87, 443-449	8
1528	Nanoscale determination of surface orientation and electrostatic properties of ZnO thin films. **2007**, 88, 77-82	7
1527	Strategies for controlled placement of nanoscale building blocks. **2007**, 2, 519-45	83
1526	Modeling electrostatic force microscopy for conductive and dielectric samples using the boundary element method. **2008**, 32, 682-691	11
1525	Shape dependence of the capacitance of scanning capacitance microscope probes. **2008**, 108, 712-7	2
1524	Atomic force microscopy, a tool for characterization, synthesis and chemical processes. **2008**, 286, 85-95	10
1523	Scanning probe microscopy at video-rate. **2008**, 11, 40-48	107
1522	Magnetic sensitive force microscopy. **2008**, 3, 28-39	82
1521	Nanoscopic distribution of potential and topography on Si (111) surface having 1 ˆ 1 and 7 ˆ 7 structures with and without scratching. **2008**, 40, 885-888	4
1520	Electric field measurement for quantum-dot cellular automata clocking circuits. **2008**, 40, 1503-1506	
1519	Fixed charge density distribution on pulsed laser deposited high-k oxide layers. **2008**, 5, 3304-3308	1
1518	Probing Local Surface Potential of Quasi-One-Dimensional Systems: A KPFM Study of P3HT Nanofibers. **2008**, 18, 907-914	50
1517	Charge Trapping in Intergrain Regions of Pentacene Thin Film Transistors. **2008**, 18, 3907-3913	135
1516	Manipulating the Local Light Emission in Organic Light-Emitting Diodes by using Patterned Self-Assembled Monolayers. **2008**, 20, 2703-6	25
1515	Characterisation of trapped electric charge carriers behaviour at nanometer scale by electrostatic force microscopy. **2008**, 66, 538-547	31
1514	Local chemical state change in CoO resistance random access memory. **2008**, 2, 99-101	25

1513	Kelvin Probe Force Microscopy: Recent Advances and Applications. **2008**, 351-376		1
1512	Microscopic investigation of InGaN/GaN heterostructure laser diode degradation using Kelvin probe force microscopy. *Journal Physics D: Applied Physics*, **2008**, 41, 135115	3	5
1511	Space Charge Measurements with the Scanning Kelvin Probe. **2008**, 15, 560-567		10
1510	Two-dimensional junction identification in multicrystalline silicon solar cells by scanning Kelvin probe force microscopy. **2008**, 104, 104501		19
1509	Ultrasharp and high aspect ratio carbon nanotube atomic force microscopy probes for enhanced surface potential imaging. **2008**, 19, 235704		31
1508	Applied Scanning Probe Methods VIII. **2008**,		8
1507	Local work function measurements of epitaxial graphene. *Applied Physics Letters*, **2008**, 93, 133117	3.4	186
1506	Electrochemically assisted scanning probe microscopy. **2008**, 237-286		1
1505	Kelvin probe study of laterally inhomogeneous dielectric charging and charge diffusion in RF MEMS capacitive switches. **2008**,		23
1504	A resolution study for electrostatic force microscopy on bimetallic samples using the boundary element method. **2008**, 19, 035710		13
1503	Simulating and interpreting Kelvin probe force microscopy images on dielectrics with boundary integral equations. **2008**, 79, 023711		19
1502	Nanometrology. **2008**, 49, 351-374		8
1501	Water Vapor Adsorption Effect on Silica Surface Electrostatic Patterning. *Journal of Physical Chemistry C*, **2008**, 112, 17193-17199	3.8	35
1500	Tip-modulation scanned gate microscopy. **2008**, 8, 2161-5		19
1499	Kelvin Probe Force Microscope Observation of Chlorine-Adsorbed TiO2(110) Surfaces. *Japanese Journal of Applied Physics*, **2008**, 47, 6149-6152	1.4	8
1498	Work Function on Dye-Adsorbed TiO2 Surfaces Measured by Using a Kelvin Probe Force Microscope. *Journal of Physical Chemistry C*, **2008**, 112, 6961-6967	3.8	21
1497	Characterization Method of Polycrystalline Materials Using Conductive Atomic Force Microscopy. **2008**, 25, 3597-3600		6
1496	Simultaneous investigation of the influence of topography and charge on protein adsorption using artificial nanopatterns. **2008**, 24, 2284-7		32

1495	Minimum voltage for threshold switching in nanoscale phase-change memory. **2008**, 8, 3429-33		69
1494	Tip□Sample Interactions in Kelvin Probe Force Microscopy: Quantitative Measurement of the Local Surface Potential. *Journal of Physical Chemistry C*, **2008**, 112, 17368-17377	3.8	52
1493	Local detection of X-ray spectroscopies with an in-situ Atomic Force Microscope. **2008**, 3, P12004-P12004		22
1492	Thin water films grown at ambient conditions on BaF(2)(111) studied by scanning polarization force microscopy. **2008**, 129, 174705		29
1491	Nanoscale surface electrical properties of aluminum zinc oxide thin films investigated by scanning probe microscopy. **2008**, 104, 114314		37
1490	Electrically driven light emission from individual CdSe nanowires. **2008**, 8, 4552-6		58
1489	Noble metal-coated probes sliding at up to 100 mm s□against PZT films for AFM probe-based ferroelectric recording technology. **2008**, 20, 225013		8
1488	Controlled positive and negative surface charge injection and erasure in a GaAs/AlGaAs based microdevice by scanning probe microscopy. **2008**, 19, 045304		9
1487	Imparting chemical specificity to nanometer-spaced electrodes. **2008**, 19, 355303		6
1486	Surface potential domains on lamellar P3OT structures. **2008**, 19, 065709		13
1485	Control of Chemical States on Locally Anode-Oxidized Si Surfaces. *Japanese Journal of Applied Physics*, **2008**, 47, 6105-6108	1.4	8
1484	Direct Measurement of Transfer Functions in Kelvin Probe Force Microscopy Using Artificially Patterned Surface Potentials. *Japanese Journal of Applied Physics*, **2008**, 47, 5630-5635	1.4	5
1483	Development of Surface Hall Potentiometry to Reveal the Variation of Drift Velocity of Carriers in Semiconductor Materials. *Japanese Journal of Applied Physics*, **2008**, 47, 3041-3045	1.4	
1482	Compositional Changes in Co□Ferritin Nanoparticles Induced by Ion Bombardment as Determined by Kelvin Probe Force Microscopy in High Vacuum. *Japanese Journal of Applied Physics*, **2008**, 47, 6160-6165	1.4	4
1481	Nanotribology and nanomechanics of AFM probe-based data recording technology. **2008**, 20, 365207		27
1480	Two-Dimensional Carrier Profiling by Kelvin-Probe Force Microscopy. *Japanese Journal of Applied Physics*, **2008**, 47, 4448-4453	1.4	13
1479	Lateral resolution and potential sensitivity in Kelvin probe force microscopy: Towards understanding of the sub-nanometer resolution. **2008**, 77,		64
1478	Minority carrier lifetime in polycrystalline silicon solar cells studied by photoassisted Kelvin probe force microscopy. *Applied Physics Letters*, **2008**, 93, 021902	3.4	53

1477	Feed-forward compensation of surface potential in atomic force microscopy. **2008**, 79, 063704		22
1476	Two-dimensional electrostatic force field measurements with simultaneous topography measurement on embedded interdigitated nanoelectrodes using a force distance curve based method. *Applied Physics Letters*, **2008**, 92, 063113	3.4	8
1475	Minority carrier dynamics in polycrystalline silicon solar cells studied by photo-assisted Kelvin probe force microscopy. **2008**,		
1474	Platinum-coated probes sliding at up to 100 mm/s against lead zirconate titanate films for atomic force microscopy probe-based ferroelectric recording technology. **2008**, 26, 783-793		13
1473	Observation of individual dopants in a thin silicon layer by low temperature Kelvin Probe Force Microscope. *Applied Physics Letters*, **2008**, 93, 142101	3.4	56
1472	Atomic structure and friction of ultrathin films of KBr on Cu(100). **2008**, 77,		43
1471	Atomic scale Kelvin probe force microscopy studies of the surface potential variations on the TiO2(110) surface. **2008**, 100, 236104		107
1470	Characterization of Phases in Duplex Stainless Steel by Magnetic Force Microscopy/Scanning Kelvin Probe Force Microscopy. **2008**, 11, C41		48
1469	Analytical approach to the local contact potential difference on (001) ionic surfaces: Implications for Kelvin probe force microscopy. **2008**, 78,		91
1468	Si Single-Electron SOI-MOSFETs: Interplay with Individual Dopants and Photons. **2008**, 1145, 1		
1467	Electric charges and forces in atomic force microscopy and nano-xerography. **2008**, 142, 012048		2
1466	Electrical characterisitics of ferritin cores investegated by Kelvin Probe force microscopy. **2008**, 100, 052004		2
1465	Development of Ultra-High Vacuum Non-Contact Atomic Force Microscope and Its Applications. **2008**, 57, 157-169		
1464	Investigation of cross-sectional potential distribution in GaN-based field effect transistors by Kelvin probe force microscopy. **2008**,		3
1463	Scanning gate study of organic thin-film field-effect transistor. **2008**, 109, 012007		2
1462	????????????????????. **2008**, 59, 812-817		2
1461	Surface features on Sahara soil dust particles made visible by atomic force microscope (AFM) phase images. **2008**, 1, 1-8		7
1460	The electrical surface potential of pulmonary surfactant. **2009**, 14, 4337-47		

1459	Photovoltaic characterization of Cu(InGa)Se2 and Cu(InAl)Se2 solar cells by photoassisted Kelvin probe force microscopy. **2009**,		2
1458	Evaluation of the catalytic metal for the hydrogen sensor using terahertz chemical microscope. **2009**,		
1457	Measurement of charge distribution in actin bundles by surface potential microscopy. *Applied Physics Letters*, **2009**, 95, 033701	3.4	9
1456	. **2009**,		4
1455	Quantitative dopant profiling in semiconductors: A Kelvin probe force microscopy model. **2009**, 80,		38
1454	Topography and surface potential in Kelvin force microscopy of perfluoroalkyl alkanes self-assemblies. **2009**, 27, 903		18
1453	Preamplifying cantilevers for dynamic atomic force microscopy. *Applied Physics Letters*, **2009**, 94, 103507	3.4	12
1452	Tailoring the electronic properties of GaxIn1P beyond simply varying alloy composition. *Applied Physics Letters*, **2009**, 94, 091113	3.4	3
1451	Study of minority carrier diffusion length in multicrystalline silicon solar cells using photoassisted Kelvin probe force microscopy. *Applied Physics Letters*, **2009**, 95, 191908	3.4	16
1450	Electrical mapping of microtubular structures by surface potential microscopy. *Applied Physics Letters*, **2009**, 95, 113703	3.4	12
1449	Electrostatic force spectroscopy on insulating surfaces: the effect of capacitive interaction. **2009**, 20, 365501		6
1448	Nanostructuring of epitaxial graphene layers on SiC by means of field-induced atomic force microscopy modification. **2009**, 27, 3149		15
1447	Focused ion beam induced local modifications of the contact potential difference of n- and p-doped silicon. *Journal Physics D: Applied Physics*, **2009**, 42, 145117	3	4
1446	Electrochemical Deposition of Metallic Nanowires as a Scanning Probe Tip. *Journal of the Electrochemical Society*, **2009**, 156, D431	3.9	5
1445	Influence of sputtering a ZnMgO window layer on the interface and bulk properties of Cu(In,Ga)Se2 solar cells. **2009**, 27, 2384		10
1444	Frequency dependent Kelvin probe force microscopy on silicon surfaces. **2009**, 27, 969		3
1443	Improving lateral resolution of electrostatic force microscopy by multifrequency method under ambient conditions. *Applied Physics Letters*, **2009**, 94, 223109	3.4	20
1442	Enhanced Spatial Resolution Scanning Kelvin Force Microscopy Using Conductive Carbon Nanotube Tips. **2009**,		

1441	Material and doping transitions in single GaAs-based nanowires probed by Kelvin probe force microscopy. **2009**, 20, 385702		34
1440	Reduction and oxidation of oxide ion conductors with conductive atomic force microscopy. **2009**, 20, 445706		18
1439	Electrostatic force microscopy and potentiometry of realistic nanostructured systems. **2009**, 105, 054301		11
1438	Scanning Kelvin Probe Microscopy of CdTe Solar Cells Measured Under Different Bias Conditions. **2009**, 1165, 1		1
1437	Quantitative Kelvin probe force microscopy. **2009**, 1232, 70201		
1436	Observation of Unusual Homoepitaxy in Ultrathin Pentacene Films and Correlation with Surface Electrostatic Potential. **2009**, 21, 3092-3098		39
1435	Electrical modes in scanning probe microscopy. **2009**, 30, 1167-78		67
1434	Controlling chaos in dynamic-mode atomic force microscope. **2009**, 373, 3140-3144		33
1433	Improvement of KFM performance by intermittent bias application method and by sampling detection of cantilever deflection. **2009**, 109, 963-7		2
1432	Surface potential images of polycrystalline organic semiconductors obtained by Kelvin probe force microscopy. **2009**, 95, 125-130		25
1431	Up close & personal with atoms & molecules. **2009**, 12, 18-25		5
1430	Identification of changes in the inorganic matrix of dye sensitized solar cells during preparation. **2009**, 206, 2709-2714		2
1429	Electromechanical Imaging and Spectroscopy of Ferroelectric and Piezoelectric Materials: State of the Art and Prospects for the Future. **2009**, 92, 1629-1647		268
1428	Bimolecular recombination in ambipolar organic field effect transistors. **2009**, 10, 994-997		19
1427	A review of advanced scanning probe microscope analysis of functional films and semiconductor devices. **2009**, 517, 5100-5105		35
1426	Optical properties and scanning probe microscopy study of some AgAsSSe amorphous films. **2009**, 517, 5943-5947		10
1425	Microelectrical characterizations of junctions in solar cell devices by scanning Kelvin probe force microscopy. **2009**, 109, 952-7		14
1424	Band profiles of ZnMgO/ZnO heterostructures confirmed by Kelvin probe force microscopy. *Applied Physics Letters*, **2009**, 94, 242107	3.4	29

1423	Direct observation of minority carrier leakage in operating laser diodes by Kelvin probe force microscopy. **2009**, 35, 573-576		2
1422	Atomic force microscopy study of the potential distribution over a locally metallized n-GaAs surface. **2009**, 3, 888-896		11
1421	Measurements of work function of pristine and CuI doped carbon nanotubes. **2009**, 109, 307-313		8
1420	Imaging surface charges of individual biomolecules. **2009**, 9, 2769-73		71
1419	Atomic force microscope nanolithography: dip-pen, nanoshaving, nanografting, tapping mode, electrochemical and thermal nanolithography. **2009**, 21, 483001		62
1418	Quantifying electric field gradient fluctuations over polymers using ultrasensitive cantilevers. **2009**, 9, 2273-9		24
1417	Detection of charge distributions in insulator surfaces. **2009**, 21, 263002		67
1416	Kelvin Probe Force Microscopy Characterization of Self-Assembled Monolayers on Metals Deposited with Dip-Pen Nanolithography. *Journal of Physical Chemistry C*, **2009**, 113, 8329-8335	3.8	9
1415	Structural Changes of Electrodeposited ZnO Matrices for Dye-Sensitized Solar Cells During Preparation. *Journal of Physical Chemistry C*, **2009**, 113, 6910-6912	3.8	18
1414	Quantitative nanoscale dielectric microscopy of single-layer supported biomembranes. **2009**, 9, 1604-8		96
1413	In situ measurement of corrosion on the nanoscale. **2009**, 51, 1569-1572		24
1412	Depletion effects at phase boundaries in 2205 duplex stainless steel characterized with SKPFM and TEM/EDS. **2009**, 51, 1850-1860		134
1411	No anomalous scaling in electrostatic calibrations for Casimir force measurements. **2009**, 79,		59
1410	Determination of effective tip geometries in Kelvin probe force microscopy on thin insulating films on metals. **2009**, 20, 264016		34
1409	The influence of surface topography on Kelvin probe force microscopy. **2009**, 20, 505503		44
1408	Measuring the charge state of an adatom with noncontact atomic force microscopy. **2009**, 324, 1428-31		281
1407	Quantitative dielectric constant measurement of thin films by DC electrostatic force microscopy. **2009**, 20, 395702		59
1406	Influence of the macroscopic shape of the tip on the contrast in scanning polarization force microscopy images. **2009**, 20, 285704		12

1405	The new future of scanning probe microscopy: Combining atomic force microscopy with other surface-sensitive techniques, optical microscopy and fluorescence techniques. *Nanoscale*, **2009**, 1, 40-9	7.7	64
1404	Quantitative study of domain structure of BaTiO3 single crystal by UHV-sanning probe microscopy. **2009**,		
1403	Surface photovoltage spectroscopy in a Kelvin probe force microscope under ultrahigh vacuum. **2009**, 80, 013907		29
1402	Electrostatic charging of hydrophilic particles due to water adsorption. **2009**, 131, 11381-6		93
1401	A kelvin probe force microscopy of charged indentation-induced dislocation structures in KBr. **2009** , 20, 264005		19
1400	Evaporation and sliding of water droplets on fluoroalkylsilane coatings with nanoscale roughness. **2009**, 25, 5417-20		26
1399	Nanostructure formation driven by local protonation of polymer thin films. **2009**,		3
1398	Scanning probe measurements of CuI doped single-walled carbon nanotubes. **2009**,		
1397	Local charge storage and decay mechanism in silica. **2009**,		1
1396	AFM + Raman Microscopy + SNOM + Tip-Enhanced Raman: Instrumentation and Applications. **2010**, 18, 28-32		8
1395	Influence of ex-situ AFM treatment on epitaxial growth of self-organized InAs quantum dots. **2010**,		
1394	Potential contributions of noncontact atomic force microscopy for the future Casimir force measurements. **2010**, 28, C4A1-C4A7		14
1393	Object size effect on the contact potential difference measured by scanning Kelvin probe method. **2010**, 51, 21201		3
1392	References. **2010**, 139-173		
1391	On the accuracy of quantitative measurements of the local surface potential. **2010**, 36, 228-231		8
1390	Local work function differences at line defects in aluminium oxide on NiAl(110). **2010**, 11, 2085-7		12
1389	Ultraviolet luminescent, high-effective-work-function LaTiO3-doped indium oxide and its effects in organic optoelectronics. **2010**, 22, 2211-5		14
1388	Reconnaissance of the specific surface of vapour grown carbon micro and nanofibres as a main controller of the sorption of hydrogen. **2010**, 256, 5797-5802		5

1387	Optical and physical characteristics of In-doped ZnO nanorods. **2010**, 10, 1076-1086		25
1386	Observation of discrete dopant potential and its application to Si single-electron devices. **2010**, 518, S38-S43		22
1385	Study of phenylpyridyldiketopyrrolopyrrole interaction with hydrogen in gas and in acids. **2010**, 207, 2327-2333		3
1384	Atomic force microscopy of biological samples. **2010**, 2, 618-34		126
1383	Laser photoelectron projection microscopy of an organic conducting polymer. **2010**, 92, 779-782		5
1382	Principles and Topics of Scanning Probe Microscopy for Nanoscale Evaluation. **2010**, 83, 233-239		
1381	Dielectric charging. 140-187		6
1380	Bias Potential for Tip□Plane Systems in Kelvin Probe Force Microscopy Imaging of Non-uniform Surface Potential Distributions. *Japanese Journal of Applied Physics*, **2010**, 49, 025201	1.4	4
1379	(Invited) Tip Cleaning and Sample Design for High Resolution MOSCAP x-KPFM. **2010**, 33, 97-103		
1378	EFM Study on Ge Island: Carrier Charge and Storage Effect. **2010**, 1260, 1		
1377	Surface Science Approach to Photochemistry of TiO2. **2010**, 162, 115-133		4
1376	Electrostatic Force Microscopy and Kelvin Force Microscopy as a Probe of the Electrostatic and Electronic Properties of Carbon Nanotubes. **2010**, 89-128		19
1375	Kelvin probe force microscopy for conducting nanobits of NiO thin films. **2010**, 21, 215704		10
1374	Current anisotropy of carbon nanotube diodes: Voltage and work function dependence. *Applied Physics Letters*, **2010**, 96, 263107	3.4	8
1373	Image force microscopy of molecular resonance: A microscope principle. *Applied Physics Letters*, **2010**, 97,	3.4	102
1372	Nanoscale space charge generation in local oxidation nanolithography. *Applied Physics Letters*, **2010** , 96, 263112	3.4	14
1371	. **2010**, 19, 1490-1502		6
1370	Structure and electronic properties of step edges in the aluminum oxide film on NiAl(110). **2010**, 82,		14

1369	Diffused junctions in multicrystalline silicon solar cells studied by complementary scanning probe microscopy and scanning electron microscopy techniques. **2010**,		4
1368	Halving the Casimir force with conductive oxides: Experimental details. **2010**, 82,		38
1367	Ionization of Rydberg atoms at metallic surfaces: Influence of stray fields. **2010**, 81,		23
1366	Surface contact potential patches and Casimir force measurements. **2010**, 81,		74
1365	Kelvin probe force microscope with near-field photoexcitation. **2010**, 107, 103501		5
1364	Improved Kelvin probe force microscopy for imaging individual DNA molecules on insulating surfaces. *Applied Physics Letters*, **2010**, 97, 203703	3.4	31
1363	Contact potentials in Casimir force setups: An experimental analysis. **2010**, 28, C4A25-C4A29		17
1362	Nanoscale potential measurements in liquid by frequency modulation atomic force microscopy. **2010**, 81, 123705		51
1361	A surface work function measurement technique utilizing constant deflected grazing electron trajectories: oxygen uptake on Cu(001). **2010**, 81, 105109		4
1360	Microwave atomic force microscopy imaging for nanometer-scale electrical property characterization. **2010**, 81, 123708		26
1359	Scanning probe microscopy study of height-selected Ag/Ge(111) nanomesas driven by quantum size effects. **2010**, 81,		6
1358	Kelvin probe force microscopy study on nanotriboelectrification. *Applied Physics Letters*, **2010**, 96, 083112	3.4	35
1357	Integration of a Fabrication Process for an Aluminum Single-Electron Transistor and a Scanning Force Probe for Tuning-Fork-Based Probe Microscopy. **2010**, 19, 1088-1097		6
1356	Observation of Ferroelectric Domains Having Atomically Ordered Surface in Air by Atomic Force Microscopy and Piezoresponse Force Microscopy. **2010**, 401, 192-195		2
1355	Calculating Kelvin force microscopy signals from static force fields. *Applied Physics Letters*, **2010**, 96, 103119	3.4	24
1354	Dynamic measurement and modeling of the Casimir force at the nanometer scale. *Applied Physics Letters*, **2010**, 96, 063106	3.4	1
1353	Single-electron transport through single dopants in a dopant-rich environment. **2010**, 105, 016803		66
1352	Band profile around grain boundary of Cu(InGa)Se2 solar cell material characterized by scanning probe microscopy. **2010**,		2

1351	CASIMIR FORCE EXPERIMENTS IN AIR: TWO BIRDS WITH ONE STONE. **2010**, 25, 2231-2239		6
1350	Electrical properties of CdTe/CdS AND CdTe/SnO2 solar cells studied with scanning kelvin probe microscopy. **2010**,		
1349	Surface Potential Investigation of Carbon Nanotube Field-Effect Transistor by Point-by-Point Atomic Force Microscope Potentiometry. *Japanese Journal of Applied Physics*, **2010**, 49, 02BD03	1.4	3
1348	Disordered electrical potential observed on the surface of SiO2 by electric field microscopy. **2010**, 22, 045002		2
1347	Cantilever contribution to the total electrostatic force measured with the atomic force microscope. *Measurement Science and Technology*, **2010**, 21, 025502	2	22
1346	Termination of diamond surfaces with hydrogen, oxygen and fluorine using a small, simple plasma gun. **2010**, 19, 324-328		24
1345	Electrical Measurement Techniques in Atomic Force Microscopy. **2010**, 35, 38-51		39
1344	Long range interactions in nanoscale science. **2010**, 82, 1887-1944		304
1343	Photoassisted Kelvin probe force microscopy at GaN surfaces: The role of polarity. *Applied Physics Letters*, **2010**, 97, 172111	3.4	30
1342	AFM tip characterization by Kelvin probe force microscopy. **2010**, 12, 093024		39
1341	Atomic resolution non-contact atomic force microscopy of clean metal oxide surfaces. **2010**, 22, 263001		52
1340	Aging dynamics of solution-processed amorphous oxide semiconductor field effect transistors. *ACS Applied Materials & Interfaces*, **2010**, 2, 626-32	9.5	32
1339	DNA Immobilization on GaP(100) Investigated by Kelvin Probe Force Microscopy. *Journal of Physical Chemistry C*, **2010**, 114, 15486-15490	3.8	8
1338	Morphology and self-arraying of SDS and DTAB dried on mica surface. **2010**, 26, 7824-32		22
1337	Scanning tunneling spectroscopy and Kelvin probe force microscopy investigation of Fermi energy level pinning mechanism on InAs and InGaAs clean surfaces. **2010**, 108, 023711		60
1336	Simulation method of Kelvin probe force microscopy at nanometer range and its application. **2010**, 82,		14
1335	AFM force mapping for characterizing patterns of electrostatic charges on SiO2 electrets. **2010**, 26, 11958-62		11
1334	Nanoscale quantitative measurement of the potential of charged nanostructures by electrostatic and Kelvin probe force microscopy: unraveling electronic processes in complex materials. **2010**, 43, 541-50		147

1333	Reversible resistive switching and multilevel recording in La0.7Sr0.3MnO3 thin films for low cost nonvolatile memories. **2010**, 10, 3828-35		108
1332	Advancing Characterization of Materials with Atomic Force Microscopy-Based Electric Techniques. **2010**, 233-300		3
1331	Study of nobility of chromium nitrides in isothermally aged duplex stainless steels by using SKPFM and SEM/EDS. **2010**, 52, 179-186		101
1330	The influence of carbon nanotubes on the corrosion behaviour of AZ31B magnesium alloy. **2010**, 52, 3917-3923		60
1329	Note: On the deconvolution of Kelvin probe force microscopy data. **2010**, 81, 056107		7
1328	Microstructure, Property and Processing of Functional Ceramics. **2010**,		13
1327	Nonlinear Dynamics in Atomic Force Microscopy and Its Control for Nanoparticle Manipulation. **2010**, 267-286		3
1326	Molecular heterojunction morphology on rough substrate surfaces: component separation by Fourier subtraction. **2010**, 21, 285705		2
1325	Investigation of potential and electric field profiles in cross sections of CdTe/CdS solar cells using scanning Kelvin probe microscopy. **2010**, 108, 074503		32
1324	Absence of Correlation Between Atomic Lattice Steps and 180° Domain Boundaries in BaTiO3 Single Crystals. **2010**, 400, 113-116		1
1323	Probing the selectivity of a nanostructured surface by xenon adsorption. *Nanoscale*, **2010**, 2, 502-8	7.7	21
1322	Triboelectrification studies of skin and skin cream using Kelvin probe microscopy. **2010**, 28, 1018-1028		12
1321	Scanning Kelvin Probe Force Microscopy for investigation of charge transport in carbon-nanotube enhanced organic photovoltaics. **2010**,		
1320	Effect of electron injection into phosphorus donors in silicon-on-insulator channel observed by Kelvin probe force microscopy. *Applied Physics Letters*, **2011**, 99, 213101	3.4	17
1319	Atomic Force Microscopy□AFM. **2011**, 1		1
1318	High-resolution field effect sensing of ferroelectric charges. **2011**, 11, 1428-33		37
1317	Interference Phenomena Observed on an Atomic Force Microscope Cantilever by Laser Confocal Microscopy. *Japanese Journal of Applied Physics*, **2011**, 50, 08LB17	1.4	3
1316	Determination of quasi-Fermi levels across illuminated organic donor/acceptor heterojunctions by Kelvin probe force microscopy. **2011**, 133, 13802-5		35

1315	Dielectric fluctuations over polymer films detected using an atomic force microscope. **2011**, 115, 14493-500		15
1314	Probing the gate--voltage-dependent surface potential of individual InAs nanowires using random telegraph signals. **2011**, 5, 2191-9		18
1313	Ionization energy and energy gap structure of MoSI molecular wires: Kelvin probe, ultraviolet photoelectron spectroscopy, and cyclic voltammetry measurements. **2011**, 27, 4296-9		8
1312	Single-molecule chemistry and physics explored by low-temperature scanning probe microscopy. **2011**, 47, 9011-23		42
1311	Nanoscale Investigation of Polycrystalline Ferroelectric Materials via Piezoresponse Force Microscopy. **2011**, 409-468		6
1310	The method of minimizing the impact of local residual electrostatic charge on dimensional measurement accuracy in atomic force microscopy measurements. *Measurement Science and Technology*, **2011**, 22, 094022	2	2
1309	Band excitation in scanning probe microscopy: sines of change. *Journal Physics D: Applied Physics*, **2011**, 44, 464006	3	141
1308	Nanoscale surface photovoltage of organic semiconductors with two pass Kelvin probe microscopy. **2011**, 22, 375704		10
1307	Variations in the work function of doped single- and few-layer graphene assessed by Kelvin probe force microscopy and density functional theory. **2011**, 83,		152
1306	Resistive switching memory: observations with scanning probe microscopy. *Nanoscale*, **2011**, 3, 490-502	7.7	96
1305	Ultrathin spin-coated dioleoylphosphatidylcholine lipid layers in dry conditions: a combined atomic force microscopy and nanomechanical study. **2011**, 27, 13165-72		17
1304	Scanning noise microscopy on graphene devices. **2011**, 5, 8620-8		19
1303	Electrostatic contributions in the increased compatibility of polymer blends. **2011**, 27, 15199-205		7
1302	Work function of vanadium dioxide thin films across the metal-insulator transition and the role of surface nonstoichiometry. *ACS Applied Materials & Interfaces*, **2011**, 3, 3396-401	9.5	105
1301	Procedure for Calibrating Kelvin Probe Force Microscope. **2011**, 227-235		
1300	Analysis of untreated cross sections of Cu(In,Ga)Se2 thin-film solar cells with varying Ga content using Kelvin probe force microscopy. *Applied Physics Letters*, **2011**, 99, 042111	3.4	11
1299	Nanotribology and Nanomechanics I. **2011**,		17
1298	Scanning Probe Microscopy of Functional Materials. **2011**,		14

1297	Single-molecule recognition of biomolecular interaction via Kelvin probe force microscopy. **2011**, 5, 6981-90	46
1296	Local voltage drop in a single functionalized graphene sheet characterized by Kelvin probe force microscopy. **2011**, 11, 3543-9	75
1295	Defects in oxide surfaces studied by atomic force and scanning tunneling microscopy. **2011**, 2, 1-14	20
1294	Oberservation of thermal discharge in nanopatterned electrets by Kelvin-Probe-Microscopy. **2011**,	0
1293	Tailoring the electrical properties of Ge/GaAs by film deposition rate and preparation of fully compensated Ge films. **2011**, 84,	5
1292	Proton-fountain Electric-field-assisted Nanolithography (PEN). **2011**, 299-324	
1291	Oxidation Dynamics of Epitaxial Rubrene Ultrathin Films. **2011**, 23, 3246-3253	23
1290	Distinguishing magnetic and electrostatic interactions by a Kelvin probe force microscopy-magnetic force microscopy combination. **2011**, 2, 552-60	51
1289	Polarized Tips or Surfaces: Consequences in Kelvin Probe Force Microscopy. **2011**, 9, 6-14	20
1288	Highly Sensitive Electrostatic Force Detection Using Small Amplitude Frequency-Modulation Atomic Force Microscopy in the Second Flexural Mode. **2011**, 9, 146-152	5
1287	Effect of Trapped Charges on Local Potential Measurement of Carbon Nanotubes Using Frequency-Modulation Kelvin-Probe Force Microscopy. **2011**, 9, 210-214	6
1286	Theoretical simulation of scanning probe microscopy. **2011**, 27, 121-7	1
1285	Mapping Membrane Proteins on Living Cells Using the Atomic Force Microscope. **2011**, 263-284	
1284	Switching surface polarization of atomic force microscopy probe utilizing photoisomerization of photochromic molecules. **2011**, 109, 064308	4
1283	Quantitative potential measurements of nanoparticles with different surface charges in liquid by open-loop electric potential microscopy. **2011**, 110, 044315	40
1282	A study of bulky nanotube composites based on albumin by high-resolution microscopy. **2011**, 56, 194-199	2
1281	Investigation of organic films by atomic force microscopy: Structural, nanotribological and electrical properties. **2011**, 66, 379-393	19
1280	Modifying organic/metal interface via solvent treatment to improve electron injection in organic light emitting diodes. **2011**, 12, 1858-1863	68

1279	Nucleotides, RNA and DNA selective adsorption on atomic-flat MgAl-hydroxysilicate substrates. **2011**, 6, 922		15
1278	Atom devices based on single dopants in silicon nanostructures. **2011**, 6, 479		57
1277	Scanning Kelvin probe force microscopy for the in situ observation of the direct interaction between active head and intermetallic particles in filiform corrosion on aluminium alloy. **2011**, 56, 9588-9595		35
1276	Experimental and Theoretical Study of the New Image Force Microscopy Principle (Invited Paper). **2011**, 1318, 1		1
1275	Peculiarities of three-passage measurements in magnetic force microscopy. **2011**, 40, 529-532		1
1274	Force gradient sensitive detection in lift-mode Kelvin probe force microscopy. **2011**, 22, 075501		59
1273	Surface redox induced bipolar switching of transition metal oxide films examined by scanning probe microscopy. **2011**, 102, 827-834		20
1272	Scanning Kelvin probe force microscopy study of chromium nitrides in 2507 super duplex stainless steel Implications and limitations. **2011**, 56, 1792-1798		65
1271	Wavelength dependence of nanoscale photodegradation in poly(3-octylthiophene) thin films. **2011**, 96, 1279-1285		14
1270	Kelvin force microscopy studies of work function of transparent conducting ZnO:Al electrodes synthesized under varying oxygen pressures. *Solar Energy Materials and Solar Cells*, **2011**, 95, 602-605	6.4	25
1269	Spatially resolved photoelectric performance of axial GaAs nanowire pn-diodes. **2011**, 4, 987-995		27
1268	AFM-assisted fabrication of thiol SAM pattern with alternating quantified surface potential. **2011**, 6, 185		12
1267	Single-photon detection by Si single-electron FETs. **2011**, 208, 646-651		9
1266	Kelvin probe force microscopy in the presence of intrinsic local electric fields. **2011**, 208, 777-789		13
1265	Electronic and morphological properties of the electrochemically prepared step bunched silicon (111) surface. **2011**, 248, 361-369		9
1264	Local surface potential of conjugated nanostructures by Kelvin probe force microscopy: effect of the sampling depth. **2011**, 7, 634-9		20
1263	Evaluation of corrosion behaviour in a 317L stainless steel strip welding using scanning Kelvin probe force microscopy. **2011**, 62, 1092-1099		1
1262	Recent trends in surface characterization and chemistry with high-resolution scanning force methods. **2011**, 23, 477-501		199

1261	Surface potential mapping of SAM-functionalized organic semiconductors by Kelvin probe force microscopy. **2011**, 23, 502-7		70
1260	Scanning Probe Microscopy on Inorganic Thin Films for Solar Cells. **2011**, 275-298		2
1259	Influence of UV radiation and ozone exposure on the electro-optical properties and nanoscale structure of P3OT films. **2011**, 12, 1389-1398		14
1258	The thermal stability of Pt/Ir coated AFM tips for resistive switching measurements. **2011**, 257, 7627-7632		11
1257	Kelvin probe force microscopy and its application. **2011**, 66, 1-27		945
1256	Surface Potential Measurement of Tris(8-hydroxyquinolinato)aluminum and Bis[N-(1-naphthyl)-N-phenyl]benzidine Thin Films Fabricated on Indium□in Oxide by Kelvin Probe Force Microscopy. *Japanese Journal of Applied Physics*, **2011**, 50, 071601	1.4	2
1255	Photoassisted Kelvin Probe Force Microscopy on Multicrystalline Si Solar Cell Materials. *Japanese Journal of Applied Physics*, **2011**, 50, 08LA05	1.4	6
1254	Single-Electron Charging in Phosphorus Donors in Silicon Observed by Low-Temperature Kelvin Probe Force Microscope. *Japanese Journal of Applied Physics*, **2011**, 50, 08LB10	1.4	7
1253	Measurements of Electrostatic Potential Across p□ Junctions on Oxidized Si Surfaces by Scanning Multimode Tunneling Spectroscopy. *Japanese Journal of Applied Physics*, **2011**, 50, 04DA04	1.4	6
1252	Cathodoluminescence microcharacterization of the radiation-sensitive defect microstructure ofin situburied oxide in silicon. *Journal Physics D: Applied Physics*, **2011**, 44, 255402	3	4
1251	The Protocol Of KFM Characterization On Cross-section Of CdS/CdTe Thin Film Solar Cell. **2011**,		1
1250	Development of dual-probe atomic force microscopy system using optical beam deflection sensors with obliquely incident laser beams. **2011**, 82, 033708		15
1249	Electric field concentration in the vicinity of the interface between anode and degraded BaTiO3-based ceramics in multilayer ceramic capacitor. *Applied Physics Letters*, **2011**, 98, 072905	3.4	33
1248	Determination of long time discharge current in microelectromechanical system capacitive switches. *Applied Physics Letters*, **2011**, 99, 103503	3.4	23
1247	Barrier height of Pt□hxGa1□N (0□□0.5) nanowire Schottky diodes. *Applied Physics Letters*, **2011**, 98, 183116	3.4	12
1246	Controlling the function of carbon nanotube devices with re-writable charge patterns. *Applied Physics Letters*, **2011**, 99, 053125	3.4	4
1245	Polarization effects in noncontact atomic force microscopy: A key to model the tip-sample interaction above charged adatoms. **2011**, 83,		33
1244	Note: Quantitative (artifact-free) surface potential measurements using Kelvin force microscopy. **2011**, 82, 036101		27

1243	Three-dimensional electrostatic interactions in dynamic force microscopy: Experiment and theory. **2011**, 83,		2
1242	Low temperature ultrahigh vacuum noncontact atomic force microscope in the pendulum geometry. **2011**, 82, 023705		16
1241	Kelvin Probe Force Microscope Measurement Uncertainty. **2011**, 222, 114-117		
1240	KFM Observation of Electron Charging and Discharging in Phosphorus-Doped SOI Channel. **2011**, 470, 33-38		
1239	Topographic patterning by voltage-assisted tribocharging of a polymer. **2011**, 109, 124312		
1238	Surface potential measurement of organic thin film on metal electrodes by dynamic force microscopy using a piezoelectric cantilever. **2011**, 109, 114306		2
1237	Electrothermal Atomic-Force Microscope Cantilever With Integrated Heater and n-p-n Back-to-Back Diodes. **2011**, 20, 644-653		4
1236	Two-dimensional measurement of n+-p asymmetrical junctions in multicrystalline silicon solar cells using AFM-based electrical techniques with nanometer resolution. **2011**,		
1235	Two-step controllable electrochemical etching of tungsten scanning probe microscopy tips. **2012**, 83, 063708		31
1234	Dual frequency open-loop electric potential microscopy for local potential measurements in electrolyte solution with high ionic strength. **2012**, 83, 033709		26
1233	Force and conductance during contact formation to a C60molecule. **2012**, 14, 073032		44
1232	Thin NaCl films on silver (001): island growth and work function. **2012**, 14, 103037		27
1231	Mapping the surface charge distribution of amyloid fibril. *Applied Physics Letters*, **2012**, 101, 043703	3.4	46
1230	Spectroscopic imaging in piezoresponse force microscopy: New opportunities for studying polarization dynamics in ferroelectrics and multiferroics. **2012**, 2, 61-73		34
1229	Microscopic Measurements of Electrical Potential in Hydrogenated Nanocrystalline Silicon Solar Cells. **2012**, 1426, 371-376		2
1228	Lateral Resolution and Signal to Noise Ratio in Electrostatic Force Detection Based on Scanning Probe Microscopy. **2012**, 29, 070703		3
1227	Microwave Atomic Force Microscopy: Quantitative Measurement and Characterization of Electrical Properties on the Nanometer Scale. **2012**, 5, 016602		9
1226	Development of Scanning Tunneling Potentiometry for Semiconducting Samples. *Japanese Journal of Applied Physics*, **2012**, 51, 125202	1.4	3

1225	Potential Characterization of Interconnect Corrosion by Kelvin Probe and Electrostatic Force Microscopies. *Japanese Journal of Applied Physics*, **2012**, 51, 04DB05	1.4	
1224	Probing the properties of metal-oxide interfaces: silica films on Mo and Ru supports. **2012**, 24, 354010		15
1223	Detection and stability of nanoscale space charges in local oxidation nanolithography. **2012**, 23, 095707		11
1222	Quasi-analytical model for scattering infrared near-field microscopy on layered systems. **2012**, 20, 13173-88		62
1221	Work function shifts of catalytic metals under hydrogen gas visualized by terahertz chemical microscopy. **2012**, 20, 11637-42		15
1220	Half-harmonic Kelvin probe force microscopy with transfer function correction. *Applied Physics Letters*, **2012**, 100, 063118	3.4	18
1219	Scanning probes for new energy materials: Probing local structure and function. **2012**, 37, 633-637		20
1218	Reevaluation of the beneficial effect of Cu(In,Ga)Se2 grain boundaries using Kelvin probe force microscopy. *Applied Physics Letters*, **2012**, 100, 203903	3.4	16
1217	High potential sensitivity in heterodyne amplitude-modulation Kelvin probe force microscopy. *Applied Physics Letters*, **2012**, 100, 223104	3.4	38
1216	Environment and baking influence on charge retention on silicon nitride charge trap layers. **2012**, 111, 023710		4
1215	The importance of cantilever dynamics in the interpretation of Kelvin probe force microscopy. **2012** , 112, 64510		5
1214	Localization of the phantom force induced by the tunneling current. **2012**, 85,		10
1213	Toward quantitative Kelvin probe force microscopy of nanoscale potential distributions. **2012**, 85,		34
1212	Real-space microscopic electrical imaging of n+-p junction beneath front-side Ag contact of multicrystalline Si solar cells. **2012**, 111, 083704		8
1211	Large negative electronic compressibility of LaAlO3-SrTiO3 interfaces with ultrathin LaAlO3 layers. **2012**, 86,		14
1210	Note: A scanning electron microscope sample holder for bidirectional characterization of atomic force microscope probe tips. **2012**, 83, 036108		
1209	. **2012**,		
1208	Water assisted gate induced temporal surface charge distribution probed by electrostatic force microscopy. **2012**, 112, 084329		10

1207	Improvement of scanning tunneling microscopy resolution with H-sensitized tips. **2012**, 108, 246102		34
1206	Electromechanical switching behavior of individual molecular complexes of Cu and Ni on NaCl-covered Cu(111) and Ag(111). **2012**, 86,		7
1205	Interfacial Dipole Effects on High-k Gate Stacks. **2012**, 319-353		
1204	. **2012**,		4
1203	AFM tip-induced modification of semiconductor surface properties. **2012**,		
1202	Intrinsic Free Electrons/Holes at Polarization Discontinuities and their Implications for Basics of Ferroelectricity and its Origin. **2012**, 189, 57-93		3
1201	Temperature and Time-Dependent Ion Diffusion Across Stainless Steel-Zirconium Film Interface Studied by Scanning Surface Potential.. **2012**, 1383, 133		
1200	Towards fast AFM-based nanometrology and nanomanufacturing. **2012**, 8, 392		4
1199	Photothermal Signal and Surface Potential around Grain Boundaries in Multicrystalline Silicon Solar Cells Investigated by Scanning Probe Microscopy. **2012**, 5, 022301		12
1198	Nm-scale measurements of fast surface potential transients in an AlGaN/GaN high electron mobility transistor. *Applied Physics Letters*, **2012**, 100, 193507	3.4	27
1197	Modulation effect of hydrogen and fluorine decoration on the surface work function of BN sheets. *AIP Advances*, **2012**, 2, 022125	1.5	14
1196	AFM-utilizing approach to search for new oxide materials for perspective applications in memristive devices. **2012**, 58, 20102		4
1195	Laser cleaning of exfoliated graphene. **2012**, 1455, 25		3
1194	UV-induced modulation of the conductivity of polyaniline: towards a photo-patternable charge injection layer for structured organic light emitting diodes. **2012**, 22, 2922-2928		26
1193	Advanced Dynamic Force Methods. **2012**, 400-436		
1192	Multiscale approach for simulations of Kelvin probe force microscopy with atomic resolution. **2012**, 86,		54
1191	Bimetallic Nanoparticles, Grown Under UHV on Insulators, Studied by Scanning Probe Microscopy. **2012**, 25-68		1
1190	Measurement of electrical properties of materials under the oxide layer by microwave-AFM probe. **2012**, 18, 1917-1922		4

1189	Corrosion behavior of a duplex stainless steel under cyclic loading: a scanning Kelvin probe force microscopy (SKPFM) based microscopic study. **2012**, 42, 1049-1056		11
1188	In situ detection of differences in the electrochemical activity of Al2Cu IMPs and investigation of their effect on FFC by scanning Kelvin probe force microscopy. **2012**, 58, 307-314		34
1187	Graphene on Si(111)7ˆ ▯7. **2012**, 23, 405708		27
1186	Local polarization in strontium barium niobate (SBN) epitaxial thin films investigated using Kelvin Force Microscopy (KFM). **2012**,		
1185	Dual harmonic Kelvin probe force microscopy for surface potential measurements of ferroelectrics. **2012**,		9
1184	Influence of the Ga content on the optical and electrical properties of CuIn1⌧GaxSe2 thin-film solar cells. **2012**,		
1183	Influence of Surface Adsorption on Work Function Measurements on Gold-Platinum Interface Using Scanning Kelvin Probe Microscopy. **2012**, 371, 012030		6
1182	Influence of Coumarin 343 Monomer Codeposition on the Structure and Electronic Properties of Electrodeposited ZnO. *Journal of Physical Chemistry C*, **2012**, 116, 5610-5613	3.8	4
1181	Nanoscale Electro-Optical Properties of Organic Semiconducting Thin Films: From Individual Materials to the Blend. *Journal of Physical Chemistry C*, **2012**, 116, 17919-17927	3.8	7
1180	Investigation of charge transfer in Au nanoparticle-ZnO nanosheet composite photocatalysts. **2012**, 14, 14492-4		23
1179	Acid-base site detection and mapping on solid surfaces by Kelvin force microscopy (KFM). **2012**, 84, 10191-8		31
1178	Nanoscale Laterally Modulated Properties of Oxide Ultrathin Films by Substrate Termination Replica through Layer-by-Layer Growth. **2012**, 24, 4177-4184		13
1177	KPFM and PFM of Biological Systems. **2012**, 243-287		7
1176	Experimental Technique and Working Modes. **2012**, 7-24		12
1175	Electrostatic Force Microscopy Characterization of Low Dimensional Systems. **2012**, 175-199		1
1174	A near-field scanning microwave microscope for characterization of inhomogeneous photovoltaics. **2012**, 83, 083702		22
1173	Morphology characterization in organic and hybrid solar cells. **2012**, 5, 8045		359
1172	Imaging extended non-homogeneities in HVPE grown GaN with Kelvin Probe Microscopy and photo-etching. **2012**, 353, 68-71		5

1171	New opportunities in crystal engineering--the role of atomic force microscopy in studies of molecular crystals. **2012**, 48, 9210-26		49
1170	The effect of sample resistivity on Kelvin probe force microscopy. *Applied Physics Letters*, **2012**, 101, 213105	3.4	6
1169	Self-assembled electrical biodetector based on reduced graphene oxide. **2012**, 6, 5514-20		35
1168	Step like surface potential on few layered graphene oxide. *Applied Physics Letters*, **2012**, 101, 263109	3.4	17
1167	Seeing the charge within. **2012**, 7, 210-1		4
1166	Electrical Characterization of Solar Cell Materials Using Scanning Probe Microscopy. **2012**, 551-573		3
1165	Determination of grain boundary charging in Cu(In,Ga)Se2 thin films. **2012**,		0
1164	Practical aspects of single-pass scan Kelvin probe force microscopy. **2012**, 83, 113701		39
1163	Evidence of intrinsic ambipolar charge transport in a high band gap organic semiconductor. **2012**, 22, 345-348		8
1162	Quantitative multichannel NC-AFM data analysis of graphene growth on SiC(0001). **2012**, 3, 179-85		17
1161	Quantitative analysis of the resolution and sensitivity of Kelvin probe force microscopy using carbon nanotube functionalized probes. *Measurement Science and Technology*, **2012**, 23, 105404	2	6
1160	Resonant multi-frequency method for Kelvin probe force microscopy in air. *Measurement Science and Technology*, **2012**, 23, 105402	2	3
1159	Scanning probe microscopy of solar cells: From inorganic thin films to organic photovoltaics. **2012**, 37, 642-650		27
1158	Electrostatic Force Microscopy And Kelvin Probe Force Microscopy. **2012**, 1		2
1157	The Effect of the Measuring Tip and Image Reconstruction. **2012**, 45-67		
1156	3 Probing and Modelling of Galvanic Coupling Phenomena in Localized Corrosion. **2012**, 243-296		1
1155	Electronic Properties of Metal/Organic Interfaces. **2012**, 221-241		
1154	Scanning Probe Microscopy Forces and Currents in the Nanoscale World. **2012**, 539-614		2

(2012-2012)

1153	Introduction. **2012**, 1-3		1
1152	Hydrogenated graphene: Structures and surface work function. **2012**,		1
1151	Recombination dynamics of excitons and exciton complexes in single quantum dots. **2012**, 100, 67006		8
1150	Mechatronics. **2012**,		
1149	Light-soaking issue in polymer solar cells: Photoinduced energy level alignment at the sol-gel processed metal oxide and indium tin oxide interface. **2012**, 111, 114511		106
1148	Kelvin probe force microscopy in nonpolar liquids. **2012**, 28, 13892-9		32
1147	Instrumentation for dual-probe scanning near-field optical microscopy. **2012**, 83, 083709		16
1146	Switching spectroscopic measurement of surface potentials on ferroelectric surfaces via an open-loop Kelvin probe force microscopy method. *Applied Physics Letters*, **2012**, 101, 242906	3.4	12
1145	Measuring Atomic-Scale Variations of the Electrostatic Force. **2012**, 289-327		2
1144	Nano- and Macrotribological Properties of Nanoperiod Multilayer Films Deposited by Bias Sputtering. **2012**, 2012, 1-16		
1143	Interface properties of OFETs based on an air-stable n-channel perylene tetracarboxylic diimide semiconductor. **2012**, 209, 585-593		13
1142	Theoretical simulation of Kelvin probe force microscopy for Si surfaces by taking account of chemical forces. **2012**, 24, 084002		6
1141	Measurements of tunneling conduction to carbon nanotubes and its sensitivity to oxygen gas. **2012** , 86,		5
1140	Reading and writing charge on graphene devices. *Applied Physics Letters*, **2012**, 101, 023505	3.4	5
1139	Imaging the charge distribution within a single molecule. **2012**, 7, 227-31		250
1138	Open-loop band excitation Kelvin probe force microscopy. **2012**, 23, 125704		28
1137	Advanced dielectric charging characterization in capacitive MEMS. **2012**,		2
1136	Invited review article: combining scanning probe microscopy with optical spectroscopy for applications in biology and materials science. **2012**, 83, 061101		54

1135	Quantitative nanoscale surface voltage measurement on organic semiconductor blends. **2012**, 23, 045703		7
1134	Local Organization of Graphene Network Inside Graphene/Polymer Composites. **2012**, 22, 1311-1318		42
1133	Microscopic conduction pathways of poly(3-hexylthiophene) nanofibers embedded in polymer film. **2012**, 44, 371-374		8
1132	Potential distribution in channel of thin-film transistors. *Applied Physics Letters*, **2012**, 101, 013504	3.4	2
1131	Casimir force and in situ surface potential measurements on nanomembranes. **2012**, 109, 027202		68
1130	AFM diagnostics of graphene-based quantum Hall devices. **2012**, 43, 479-86		16
1129	The Kelvin probe technique for assessing efficiency of stearic acid removal from gold surfaces using atmospheric-pressure plasma. **2012**, 206, 3715-3720		
1128	Doping transition of doped ZnO nanorods measured by Kelvin probe force microscopy. **2012**, 520, 4622-4625		9
1127	. **2012**, 59, 1709-1715		5
1126	Surface electrostatic potential of inn epitaxial layers and its changes during anodic oxidization. **2012**, 6, 420-423		1
1125	Paradox of low field enhancement factor for field emission nanodiodes in relation to quantum screening effects. **2012**, 7, 125		11
1124	SECM and SKPFM Studies of the Local Corrosion Mechanism of Al Alloys A Pathway to an Integrated SKP-SECM System. **2012**, 24, 239-245		13
1123	Environmental effects in Kelvin force microscopy of modified diamond surfaces. **2012**, 75, 977-81		2
1122	Oxygen Surface Exchange at Grain Boundaries of Oxide Ion Conductors. **2012**, 22, 965-971		109
1121	Operational stability of organic field-effect transistors. **2012**, 24, 1146-58		182
1120	Kelvin probe microscopy and current images of the degradation process of layered poly-3-octyl-thiophene structures. **2013**, 49, 2092-2100		1
1119	Reconstruction of surface potential from Kelvin probe force microscopy images. **2013**, 24, 295702		50
1118	Electrical characterization of organic solar cell materials based on scanning force microscopy. **2013**, 49, 1907-1915		39

1117	Electrostatic interactions with dielectric samples in scanning probe microscopies. **2013**, 88,		17
1116	Study on Multi-Frequency Method for Electrostatic Force Microscopy in Air. **2013**, 145, 59-67		1
1115	Influence of the Ga Content on the Optical and Electrical Properties of CuIn $_{{bm 1}hbox{--}{bm x}}$Ga $_{bm x}$Se$_{bm 2}$ Thin-Film Solar Cells. **2013**, 3, 823-827		5
1114	Thermal Wave-Based Scanning Probe Microscopy and Its Applications. **2013**, 34, 1353-1366		4
1113	Characterization of the morphology of solution-processed bulk heterojunction organic photovoltaics. **2013**, 38, 1990-2052		237
1112	A new method to invert top-gate organic field-effect transistors for Kelvin probe investigations. **2013**, 112, 431-436		3
1111	Visualizing physical, electronic, and optical properties of organic photovoltaic cells. **2013**, 6, 2871		50
1110	Light-induced charge separation in a donor�hromophore�cceptor nanocomposite poly[TPA-Ru(tpy)2]@ZnO. **2013**, 1, 1223-1230		26
1109	Photoinduced Charge Separation of Self-Organized Semiconducting Superstructures Composed of a Functional Polymer�iO2 Hybrid. **2013**, 214, 975-984		12
1108	Role of Oxygen in the Work Function Modification at Various Stages of Chemically Synthesized Graphene. *Journal of Physical Chemistry C*, **2013**, 130911121623000	3.8	9
1107	Room temperature H2S sensor based on Au modified ZnO nanowires. **2013**, 186, 718-726		147
1106	Mechanical control of electroresistive switching. **2013**, 13, 4068-74		48
1105	Nanoscale quantification of charge injection and transportation process in Si-nanocrystal based sandwiched structure. *Nanoscale*, **2013**, 5, 9971-7	7.7	13
1104	Solvent treatment as an efficient anode modification method to improve device performance of polymer light-emitting diodes. **2013**, 14, 548-553		14
1103	. **2013**, 3, 1383-1388		18
1102	Electrical conduction channel along the grain boundaries of Cu(In,Ga)Se2 thin films. *Applied Physics Letters*, **2013**, 102, 253905	3.4	15
1101	Corrosion behavior of each phase in low carbon microalloyed ferrite�bainite dual-phase steel: Experiments and modeling. **2013**, 75, 67-77		29
1100	Photovoltaic Characteristics of Film Composites Based on Glycidylcarbazole Cooligomer with Symmetrical Cationic Polymethine Dyes. **2013**, 49, 219-223		2

1099	Artificial intelligence in nanotechnology. **2013**, 24, 452002		43
1098	Open loop Kelvin probe force microscopy with single and multi-frequency excitation. **2013**, 24, 475702		53
1097	A Dual Probe STM Imaging System and a Low Noise Switched-Capacitor Transimpedance Amplifier. *IEEE Sensors Journal*, **2013**, 13, 2984-2992	4	5
1096	Epitaxial Graphene and GrapheneBased Devices Studied by Electrical Scanning Probe Microscopy. **2013**, 3, 191-233		60
1095	Work function engineering of single layer graphene by irradiation-induced defects. *Applied Physics Letters*, **2013**, 103, 171604	3.4	92
1094	Hydrogen detection in metals: a review and introduction of a Kelvin probe approach. **2013**, 14, 014201		78
1093	Work function modulation of bilayer MoS2 nanoflake by backgate electric field effect. *Applied Physics Letters*, **2013**, 103, 033122	3.4	30
1092	Atomic Force Microscopy. **2013**, 121-193		2
1091	Toward Quantum FinFET. **2013**,		6
1090	Sample preparation for scanning Kelvin probe microscopy studies on cross sections of organic solar cells. *AIP Advances*, **2013**, 3, 092134	1.5	15
1089	The effect of degree of reduction on the electrical properties of functionalized graphene sheets. *Applied Physics Letters*, **2013**, 102, 023114	3.4	98
1088	Local triboelectrification of an n-GaAs surface using the tip of an atomic-force microscope. **2013**, 47, 1170-1173		6
1087	Potential sensitivities in frequency modulation and heterodyne amplitude modulation Kelvin probe force microscopes. **2013**, 8, 532		6
1086	Direct measurement of electrostatic fields using single Teflon nanoparticle attached to AFM tip. **2013**, 8, 519		3
1085	Imaging at the Nanoscale. **2013**, 467-507		1
1084	The resistive switching in TiO2 films studied by conductive atomic force microscopy and Kelvin probe force microscopy. *AIP Advances*, **2013**, 3, 082107	1.5	34
1083	Electroluminescent, polycrystalline cadmium selenide nanowire arrays. **2013**, 7, 9469-79		9
1082	Construction and characterization of molecular nonwoven fabrics consisting of cross-linked poly(□methyl-L-glutamate). **2013**, 29, 7478-87		7

1081	RETRACTED ARTICLE: Investigation of coating delamination on steels by surface topography and Volta potential difference. **2013**, 17, 1109-1115		2
1080	Micro-Galvanic Corrosion Effects on Patterned Copper-Zinc Samples during Exposure in Humidified Air Containing Formic Acid. *Journal of the Electrochemical Society*, **2013**, 160, C423-C431	3.9	21
1079	Orthogonal self-assembly and selective solvent vapour annealing: simplified processing of a photovoltaic blend. **2013**, 49, 4322-4		7
1078	Organic synthesis on graphene. **2013**, 46, 2297-306		58
1077	Atmospheric contaminants on graphitic surfaces. **2013**, 61, 33-39		61
1076	Investigation of Kelvin probe force microscopy efficiency for the detection of hydrogen ingress by cathodic charging in an aluminium alloy. **2013**, 68, 479-482		32
1075	Doping of TIPS-pentacene via Focused Ion Beam (FIB) exposure. **2013**, 14, 1570-1576		12
1074	Electronic structure and carrier transport at laminated polymer homojunctions. **2013**, 14, 149-155		13
1073	Subsurface measurement of nanostructures on GaAs by electrostatic force microscopy. **2013**, 271, 131-135		1
1072	Quantitative evaluation of initial galvanic corrosion behavior of CNTs reinforced MgAl alloy. **2013**, 24, 833-837		21
1071	Scanning probe study on the photovoltaic characteristics of a Si solar cell by using Kelvin force microscopy and photoconductive atomic force microscopy. **2013**, 546, 353-357		4
1070	Different tips for high-resolution atomic force microscopy and scanning tunneling microscopy of single molecules. *Applied Physics Letters*, **2013**, 102, 073109	3.4	121
1069	High-efficiency polymer solar cells enhanced by solvent treatment. **2013**, 25, 1646-52		421
1068	Morphology of water transport channels and hydrophobic clusters in Nafion from high spatial resolution AFM-IR spectroscopy and imaging. **2013**, 30, 5-8		30
1067	Sub-surface imaging of carbon nanotube-polymer composites using dynamic AFM methods. **2013**, 24, 135706		43
1066	Surface potential and interlayer screening effects of few-layer MoS2 nanoflakes. *Applied Physics Letters*, **2013**, 102, 143110	3.4	112
1065	Intrinsically Conducting Polymer-Based Heavy-Duty and Environmentally Friendly Coating System for Corrosion Protection of Structural Steels. **2013**, 46, 268-276		2
1064	Built-in potential and charge distribution within single heterostructured nanorods measured by scanning Kelvin probe microscopy. **2013**, 13, 1278-84		37

1063	Microscopy of Graphene Growth, Processing, and Properties. **2013**, 23, 2617-2634		32
1062	In situ quantitative study of nanoscale triboelectrification and patterning. **2013**, 13, 2771-6		163
1061	Electrostatic Fields. **2013**, 191-205		
1060	Unravelling the secrets of Cs controlled secondary ion formation: Evidence of the dominance of site specific surface chemistry, alloying and ionic bonding. **2013**, 68, 108-230		44
1059	Cross sections of operating Cu(In,Ga)Se2 thin-film solar cells under defined white light illumination analyzed by Kelvin probe force microscopy. *Applied Physics Letters*, **2013**, 102, 023903	3.4	10
1058	Surface work function of chemically derived graphene: A first-principles study. **2013**, 377, 1760-1765		5
1057	Investigation of charge loss mechanism of thickness-scalable trapping layer by variable temperature Kelvin probe force microscopy. **2013**, 34, 870-872		19
1056	Effect of using stencil masks made by focused ion beam milling on permalloy (Ni81Fe19) nanostructures. **2013**, 24, 115301		4
1055	Non-contact AFM imaging in water using electrically driven cantilever vibration. **2013**, 29, 6762-9		12
1054	Atomic force microscopy based manipulation of graphene using dynamic plowing lithography. **2013**, 24, 015303		39
1053	Influence of gallium-doped zinc-oxide thickness on polymer light-emitting diode luminescence efficiency. **2013**, 76, 783-7		2
1052	Spatially-resolved spectroscopic measurements of Ec 0.57 eV traps in AlGaN/GaN high electron mobility transistors. *Applied Physics Letters*, **2013**, 102, 193509	3.4	72
1051	Controlling electrostatic charging of nanocrystalline diamond at nanoscale. **2013**, 29, 7111-7		5
1050	The stray capacitance effect in Kelvin probe force microscopy using FM, AM and heterodyne AM modes. **2013**, 24, 225701		32
1049	Imaging the Electric Potential within Organic Solar Cells. **2013**, 23, 5854-5860		31
1048	Tuning the work-function via strong coupling. **2013**, 25, 2481-5		144
1047	Photobleaching of MEH-PPV thin films: Correlation between optical properties and the nanoscale surface photovoltage. *Solar Energy Materials and Solar Cells*, **2013**, 117, 15-21	6.4	6
1046	Kelvin probe force microscopic imaging of the energy barrier and energetically favorable offset of interfaces in double-junction organic solar cells. *ACS Applied Materials & Interfaces*, **2013**, 5, 1279-86	9.5	24

1045	Microstructure influence on corrosion behavior of a FeCrVN tool alloy studied by SEM/EDS, scanning Kelvin force microscopy and electrochemical measurement. **2013**, 66, 153-159		17
1044	EFM data mapped into 2D images of tip-sample contact potential difference and capacitance second derivative. **2013**, 3, 3352		13
1043	AFM investigations on the influence of CO2 exposure on Ba0.5Sr0.5Co0.8Fe0.2O3 **2013**, 17, 2897-2907		9
1042	Characterization of the Corrosion Behavior of a Mg Alloy in Chloride Solution. **2013**, 69, 497-508		10
1041	Effects of deep-level dopants on the electronic potential of thin Si pn junctions observed by Kelvin probe force microscope. *Applied Physics Letters*, **2013**, 102, 083109	3.4	18
1040	Improved accuracy and speed in scanning probe microscopy by image reconstruction from non-gridded position sensor data. **2013**, 24, 335703		22
1039	C-AFM and KPFM approach to investigate the electrical properties of single grain boundaries in ZnO varistor devices. **2013**,		5
1038	Epitaxial graphene on SiC(0001): functional electrical microscopy studies and effect of atmosphere. **2013**, 24, 215702		20
1037	Visualization of Charge Injection Processes in Polydiacetylene Thin Film Grains by Dual-Probe Atomic Force Microscopy. *Japanese Journal of Applied Physics*, **2013**, 52, 085201	1.4	2
1036	Atomic Force Microscopy Based Electric Modes in Characterization of Organic Photovoltaics. **2013**, 1500, 1		
1035	Gold nanoparticle coated silicon tips for Kelvin probe force microscopy in air. **2013**, 24, 395701		8
1034	Scanning Kelvin probe measurements on As-doped CdTe solar cells. **2013**, 28, 105024		9
1033	Acridine orange as a biosensitive photovoltaic material. **2013**, 114, 144504		4
1032	A polyaniline based intrinsically conducting coating for corrosion protection of structural steels. **2013**, 76, 1186-95		4
1031	Analysis of capacitive force acting on a cantilever tip at solid/liquid interfaces. **2013**, 113, 154311		15
1030	Manipulation of the graphene surface potential by ion irradiation. *Applied Physics Letters*, **2013**, 102, 153103	3.4	41
1029	Local potential profiling of operating carbon nanotube transistor using frequency-modulation high-frequency electrostatic force microscopy. *Applied Physics Letters*, **2013**, 102, 013115	3.4	13
1028	Casimir probe based upon metallized high Q SiN nanomembrane resonator. **2013**, 84, 015115		1

1027	Fixing the energy scale in scanning tunneling microscopy on semiconductor surfaces. **2013**, 111, 216802		10
1026	Local properties of the surface layer(s) of BiFeO3 single crystals. **2013**, 113, 187220		14
1025	Temperature and damping effects on the frequency dependence of electrostatic force microscopy force gradients. **2013**, 114, 214315		1
1024	Radial Spreading of Localized Corrosion-Induced Selective Leaching on Brass in Dilute NaCl Solution. **2013**, 69, 468-476		5
1023	Potential barrier at grain boundaries in polycrystalline silicon: influence of grain-boundary character and copper/iron contamination. **2013**, 93, 1413-1424		7
1022	Localized Electroless Ag Plating at a Tip Apex for Scanning Kelvin Probe Microscopy. *Japanese Journal of Applied Physics*, **2013**, 52, 06GF03	1.4	3
1021	Kelvin probe force microscopy and electrostatic force microscopy responses to the polarization in a ferroelectric thin film: Theoretical and experimental investigations. **2013**, 114, 014302		9
1020	Scanning Probe Techniques. **2013**, 427-488		1
1019	Experimental Basics. **2013**, 73-72		
1018	Scanning probe microscopy beyond imaging: a general tool for quantitative analysis. **2013**, 14, 1283-92		17
1017	Delamination of organic coating on carbon steel studied by scanning Kelvin probe force microscopy. **2013**, 45, 978-984		1
1016	Influence of the Ga content on the optical and electrical properties of CuIn1GaxSe2 thin-film solar cells. **2013**,		
1015	Routes to rupture and folding of graphene on rough 6H-SiC(0001) and their identification. **2013**, 4, 625-31		3
1014	Kelvin probe force microscopy of nanocrystalline TiO2 photoelectrodes. **2013**, 4, 418-28		39
1013	Study of Carbon Nanotube Based Devices Using Scanning Probe Microscope. **2013**,		
1012	Effect of contaminations and surface preparation on the work function of single layer MoS2. **2014**, 5, 291-7		61
1011	. **2014**,		25
1010	Trapped charge mapping in crystalline organic transistors by using scanning Kelvin probe force microscopy. *Applied Physics Letters*, **2014**, 105, 193303	3.4	12

1009	Electronic characterization of supramolecular materials at the nanoscale by Conductive Atomic Force and Kelvin Probe Force microscopies. **2014**, 17, 504-517		42
1008	Kelvin probe force microscopy of metallic surfaces used in Casimir force measurements. **2014**, 90,		38
1007	Nanoscale dielectric measurements from electrostatic force microscopy. **2014**, 28, 1430011		3
1006	Structure and electronic properties of poly(3,4-ethylenedioxythiophene) poly(styrene sulfonate) prepared under ultrasonic irradiation. **2014**, 195, 335-339		7
1005	Effect of Annealing Temperature on the Mechanical and Corrosion Behavior of a Newly Developed Novel Lean Duplex Stainless Steel. **2014**, 7, 6604-6619		35
1004	Hydration layers trapped between graphene and a hydrophilic substrate. **2014**, 16, 053039		40
1003	8. Analysis of Mineral Surfaces by Atomic Force Microscopy. **2014**, 331-370		1
1002	Cross-talk artefacts in Kelvin probe force microscopy imaging: A comprehensive study. **2014**, 115, 144313		35
1001	Measurement of the electrostatic edge effect in wurtzite GaN nanowires. *Applied Physics Letters*, **2014**, 105, 213107	3.4	11
1000	Microwave-induced nucleation of conducting graphitic domains on silicon carbide surfaces. **2014**, 32, 011215		3
999	Quantitative non-contact voltage profiling of quasi one-dimensional nanoelectronic devices. *Applied Physics Letters*, **2014**, 104, 213102	3.4	7
998	High-resolution characterization of the diffusion of light chemical elements in metallic components by scanning microwave microscopy. *Nanoscale*, **2014**, 6, 14932-8	7.7	4
997	Understanding the bond-energy, hardness, and adhesive force from the phase diagram via the electron work function. **2014**, 116, 173506		9
996	Quantifying electrostatic force contributions in electrically biased nanoscale interactions. **2014**, 115, 124311		5
995	System analysis of force feedback microscopy. **2014**, 115, 054309		9
994	Single atom impurity in a single molecular transistor. **2014**, 116, 154302		14
993	Atomic Force Microscopy as a Tool to Explore Triboelectrostatic Phenomena in Mineral Processing. **2014**, 86, 857-864		13
992	Atomic-dipole-moment induced local surface potential on Si(111)-(7 ˆ 7) surface studied by non-contact scanning nonlinear dielectric microscopy. *Applied Physics Letters*, **2014**, 105, 121601	3.4	5

991	Identifying the absolute orientation of a low-symmetry surface in real space. **2014**, 90,		10
990	Nanophotonics. Plasmoelectric potentials in metal nanostructures. **2014**, 346, 828-31		173
989	Nanoscale electrical properties of wide-bandgap Cu(In,Ga)Se2 and Cu2ZnSn(SSe)4 thin films. **2014**,		
988	nm-scaled workfunction mapping of the interfaces of silicon heterojunction (SHJ) solar cell using Kelvin probe force microscopy. **2014**,		0
987	Artifacts in KPFM in FM, AM and Heterodyne AM Modes. **2014**, 609-610, 1362-1368		0
986	Surface potential measurement of fullerene/copper phthalocyanine films on indium tin oxide electrode by Kelvin probe force microscopy. *Japanese Journal of Applied Physics*, **2014**, 53, 05FY03	1.4	2
985	Modeling. **2014**, 215-275		1
984	Charge Loss Characteristics of Different Al Contents in a HfAlO Trapping Layer Investigated by Variable Temperature Kelvin Probe Force Microscopy. **2014**, 31, 067701		1
983	Current-Sensing Atomic Force Microscopic Study of Doping Level Distribution in Doped Poly[2,2Bithiophene]. **2014**, 122, 72-78		1
982	Electrostatic potential variation across the surface of a diamond/SiC nanocomposite thin film. **2014**, 101, 333-336		5
981	Possible superconductivity in multi-layer-graphene by application of a gate voltage. **2014**, 72, 312-320		12
980	Investigation of multi-junction solar cells using electrostatic force microscopy methods. **2014**, 141, 1-8		11
979	Multibit data storage states formed in plasma-treated MoSransistors. **2014**, 8, 4023-32		111
978	Analysis of Mineral Surfaces by Atomic Force Microscopy. **2014**, 78, 331-369		12
977	Probing charge screening dynamics and electrochemical processes at the solid-liquid interface with electrochemical force microscopy. **2014**, 5, 3871		73
976	Contrast formation in Kelvin probe force microscopy of single conjugated molecules. **2014**, 14, 3342-6		71
975	Light-induced mass transport in amorphous chalcogenides: Toward surface plasmon-assisted nanolithography and near-field nanoimaging. **2014**, 251, 1354-1362		20
974	Multichannel scanning probe microscopy and spectroscopy of graphene moirˆ 'structures. **2014**, 16, 3894-908		23

973	Practical aspects of Kelvin-probe force microscopy at solid/liquid interfaces in various liquid media. **2014**, 116, 134307		24
972	Localized two-step galvanic replacement of a tip apex modification for field sensitive scanning probe microscopy. **2014**,		0
971	Intermodulation electrostatic force microscopy for imaging surface photo-voltage. *Applied Physics Letters*, **2014**, 105, 143113	3.4	34
970	Photovoltaic properties of film composites based on poly(vinyl butyral) with Cu/Mn heterometallic complex and a cationic organic dye. **2014**, 48, 266-268		
969	Microscopic and macroscopic characterization of the charging effects in SiC/Si nanocrystals/SiC sandwiched structures. **2014**, 25, 055703		7
968	Local charge writing in epitaxial SmNiO3 thin films. **2014**, 2, 3805-3811		4
967	Assessing local voltage in CIGS solar cells by nanoscale resolved Kelvin Probe Force Microscopy and sub-micron photoluminescence. **2014**,		1
966	Parallelization of thermochemical nanolithography. *Nanoscale*, **2014**, 6, 1299-304	7.7	32
965	Dual harmonic Kelvin probe force microscopy at the graphene▯liquid interface. *Applied Physics Letters*, **2014**, 104, 133103	3.4	42
964	Electronic Polarization at Pentacene/Polymer Dielectric Interfaces: Imaging Surface Potentials and Contact Potential Differences as a Function of Substrate Type, Growth Temperature, and Pentacene Microstructure. *Journal of Physical Chemistry C*, **2014**, 118, 2487-2497	3.8	14
963	High-resolution scanning tunneling microscopy imaging of Si(1 1 1)-7 ˆ ▯7 structure and intrinsic molecular states. **2014**, 26, 394001		4
962	Exploring the possibility of protective surface oxides upon Mg alloy AZ31 via lutetium additions. **2014**, 89, 101-110		23
961	Metal-conducting polymer interface studied by Kelvin probe microscopy: Au and Al on poly(3-octyl-thiophene). **2014**, 52, 1083-1093		2
960	Design and fabrication of an electrode array sensor for probing the electric potential distribution at the mesoscopic scale in antistatic felts. *Measurement Science and Technology*, **2014**, 25, 075903	2	2
959	Optically induced forces in scanning probe microscopy. **2014**, 3, 105-116		6
958	Morphology-dependent electronic properties in cross-linked (P3HT-b-P3MT) block copolymer nanostructures. **2014**, 8, 8344-9		21
957	Li distribution in graphite anodes: A Kelvin Probe Force Microscopy approach. **2014**, 268, 887-894		26
956	Changes of Work Function in Different Deformation Stage for 2205 Duplex Stainless Steel by SKPFM. **2014**, 3, 1736-1741		17

955	Scratch testing for micro- and nanoscale evaluation of tribocharging in DLC films containing silver nanoparticles using AFM and KPFM techniques. **2014**, 260, 205-213		50
954	Scanning Probe Microscopy Insights into Supramolecular □Conjugated Nanostructures for Optoelectronic Devices. **2014**, 491-526		
953	Hole extraction layer utilizing well defined graphene oxide with multiple functionalities for high-performance bulk heterojunction solar cells. **2014**, 15, 2868-2875		19
952	Localized charge transfer reactions near the Pt-YSZ interfaces using Kelvin probe microscopy. **2014**, 1, 201-205		7
951	Macroscopic evidence of nanoscale resistive switching in La2/3Sr1/3MnO3 micro-fabricated bridges. **2014**, 26, 395010		7
950	Layer-number-dependent work function of MoS2 nanoflakes. **2014**, 64, 1550-1555		126
949	Performance enhancement of inverted polymer solar cells with fullerene ester derivant-modified ZnO film as cathode buffer layer. *Solar Energy Materials and Solar Cells*, **2014**, 126, 36-41	6.4	27
948	Epitaxial growth of pentacene on alkali halide surfaces studied by Kelvin probe force microscopy. **2014**, 8, 3294-301		20
947	Organic bulk heterojunction photovoltaic structures: design, morphology and properties. **2014**, 83, 575-599		32
946	Potential profile and photovoltaic effect in nanoscale lateral pn junction observed by Kelvin probe force microscopy. **2014**, 557, 249-253		3
945	Inverted bulk-heterojunction solar cell with cross-linked hole-blocking layer. **2014**, 15, 997-1001		36
944	First-Principles Studies of Paramagnetic Vivianite Fe3(PO4)2□8H2O Surfaces. *Journal of Physical Chemistry C*, **2014**, 118, 6110-6121	3.8	6
943	Graphitic nanostripes in silicon carbide surfaces created by swift heavy ion irradiation. **2014**, 5, 3913		46
942	Kelvin Probe Force Microscopy in Surface Chemistry: Reactivity of Pd Nanoparticles on Highly Oriented Pirolytic Graphite. **2014**, 4, 1838-1844		21
941	Discriminating short-range from van der Waals forces using total force data in noncontact atomic force microscopy. **2014**, 89,		13
940	Volta potential of clad AA2024 aluminium after exposure to CeCl3 solution. **2014**, 86, 189-201		19
939	Ultra-sensitive direct detection of silver ions via Kelvin probe force microscopy. **2014**, 60, 299-304		29
938	Zr-based conversion layer on Zn-Al-Mg alloy coated steel sheets: insights into the formation mechanism. **2014**, 137, 65-74		53

937	Imaging and Characterization of The BioNano Interface. **2014**, 242-272		
936	Measurement of contact potential difference and material distribution by using an SEFM. **2014**, 8, JAMDSM0050-JAMDS		
935	Quantitative Electrical Measurements with Atomic Force Microscopy. **2015**, 23, 32-37		2
934	Direct nm-scale spatial mapping of traps in CIGS. **2015**,		
933	Effect of selective doping on the spatial dispersion of donor-induced quantum dots in Si nanoscale transistors. **2015**, 8, 094202		5
932	Kelvin Probe Force Microscopy by Dissipative Electrostatic Force Modulation. **2015**, 4,		18
931	Insights into Kelvin probe force microscopy data of insulator-supported molecules. **2015**, 91,		31
930	Local tunneling decay length and Kelvin probe force spectroscopy. **2015**, 92,		7
929	Interfacial Charge States in Graphene on SiC Studied by Noncontact Scanning Nonlinear Dielectric Potentiometry. **2015**, 114, 226103		25
928	Probing Charges on the Atomic Scale by Means of Atomic Force Microscopy. **2015**, 115, 076101		45
927	Imaging Nanoscale Electromagnetic Near-Field Distributions Using Optical Forces. **2015**, 5, 10610		50
926	Photovoltaic properties of films of polyvinyl alcohol-xanthene dye composites. **2015**, 49, 255-258		2
925	References. 572-624		
924	Work function contrast and energy band modulation between amorphous and crystalline Ge2Sb2Te5 films. *Applied Physics Letters*, **2015**, 107, 082101	3.4	15
923	Scanning nonlinear dielectric potentiometry. **2015**, 86, 093704		14
922	Modular apparatus for electrostatic actuation of common atomic force microscope cantilevers. **2015**, 86, 073703		9
921	Comparative study of donor-induced quantum dots in Si nano-channels by single-electron transport characterization and Kelvin probe force microscopy. **2015**, 117, 244307		10
920	Experimental study of electric dipoles on an oxygen-adsorbed Si(100)-2 ˆ 1 surface by non-contact scanning nonlinear dielectric microscopy. *Applied Physics Letters*, **2015**, 107, 031604	3.4	2

919	Nanoscale characterization of an electron emitting tip by field emission microscopy and scanning probe microscopy. **2015**, 33, 051809		1
918	Silver nanoparticles with tunable work functions. *Applied Physics Letters*, **2015**, 107, 151601	3.4	15
917	Pump-probe Kelvin-probe force microscopy: Principle of operation and resolution limits. **2015**, 118, 154302		34
916	Local impedance measurement of an electrode/single-pentacene-grain interface by frequency-modulation scanning impedance microscopy. **2015**, 118, 055501		2
915	Facile Preparation of a Platinum Silicide Nanoparticle-Modified Tip Apex for Scanning Kelvin Probe Microscopy. **2015**, 10, 401		3
914	Tunneling in Systems of Coupled Dopant-Atoms in Silicon Nano-devices. **2015**, 10, 372		8
913	Characterization of an Electron Emitting Tip by Field Emission Microscope and Scanning Probe Microscope. **2015**, 58, 131-133		
912	Imaging chemical concentration pattern and early stages of spinodal decomposition in the AgxNa1�Br system by scanning force microscopy. **2015**, 2, 105013		
911	Direct observation of the potential distribution within organic light emitting diodes under operation. **2015**, 9, 475-479		9
910	Electrostatic Limit of Detection of Nanowire-Based Sensors. **2015**, 11, 4931-7		18
909	Periodic potential distribution in linear photonic-plasmonic crystals. **2015**, 613, 012004		1
908	Scanning Kelvin force microscopy study at the cut-edge of aluminum rich metal coated steel. **2015**, 66, 16-22		5
907	Kelvin probe force microscopy in liquid using electrochemical force microscopy. **2015**, 6, 201-14		28
906	Large area scanning probe microscope in ultra-high vacuum demonstrated for electrostatic force measurements on high-voltage devices. **2015**, 6, 2485-97		3
905	Kelvin probe force microscopy for local characterisation of active nanoelectronic devices. **2015**, 6, 2193-206		25
904	Surface potential measurement of fullerene derivative/copper phthalocyanine on indium tin oxide electrode by Kelvin probe force microscopy. *Japanese Journal of Applied Physics*, **2015**, 54, 08KF06	1.4	2
903	Surface Potential Measurement of Organic Multi-layered Films on Electrodes by Kelvin Probe Force Microscopy. **2015**, E98.C, 91-97		3
902	. **2015**,		221

901	The electronic structure of metal oxide/organo metal halide perovskite junctions in perovskite based solar cells. **2015**, 5, 8704		81
900	Effect of Schottky gate type and channel defects on the stability of transparent ZnO MESFETs. **2015**, 30, 024008		11
899	The effect of patch potentials in Casimir force measurements determined by heterodyne Kelvin probe force microscopy. **2015**, 27, 214012		31
898	Scanning Thermal Microscopy (SThM). **2015**, 177-221		16
897	Graphene on SiC(0001) inspected by dynamic atomic force microscopy at room temperature. **2015**, 6, 901-6		9
896	A force sensor based on three weakly coupled resonators with ultrahigh sensitivity. **2015**, 232, 151-162		66
895	Improving the Design of the Shield for the Electric Field in SiC-Based Schottky-Rectifiers and Ion-Implantation Cascades by SPM Dopant-Imaging. **2015**, 148, 1-4		4
894	Investigation of surface charge density on solid-liquid interfaces by modulating the electrical double layer. **2015**, 27, 194102		5
893	Enhanced electrical properties at boundaries including twin boundaries of polycrystalline CdTe thin-film solar cells. **2015**, 17, 11150-5		29
892	Patterning of PMMA by gold-nanoparticle initiated localized decomposition. **2015**,		
891	Effect of the interaction conditions of the probe of an atomic-force microscope with the n-GaAs surface on the triboelectrization phenomenon. **2015**, 49, 1057-1061		2
890	Scanning-probe-microscopy of polyethylene terephthalate surface treatment by argon ion beam. **2015**, 362, 49-56		5
889	Varying Surface Chemistries for p-Doped and n-Doped Silicon Nanocrystals and Impact on Photovoltaic Devices. *ACS Applied Materials & Interfaces*, **2015**, 7, 28207-14	9.5	14
888	Emerging interface dipole versus screening effect in copolymer/metal nano-layered systems. **2015**, 359, 637-642		1
887	Kelvin Probe Force Microscope Observation of Donors▯Arrangement in Si Transistor Channel. **2015**, 1117, 82-85		
886	Electrical detection of ortho-para conversion in fullerene-encapsulated water. **2015**, 6, 8112		42
885	Visualizing monolayers with a water-soluble fluorophore to quantify adsorption, desorption, and the double layer. **2015**, 112, E826-35		16
884	Liquid phase deposition of a space-durable, antistatic SnO▯coating on Kapton. *ACS Applied Materials & Interfaces*, **2015**, 7, 3539-46	9.5	33

883	Depth-sensitive subsurface imaging of polymer nanocomposites using second harmonic Kelvin probe force microscopy. **2015**, 9, 2938-47		36
882	Scanning probe microscopy and spectroscopy of graphene on metals. **2015**, 252, 451-468		23
881	Nanometer-scale surface potential and resistance mapping of wide-bandgap Cu(In,Ga)Se2 thin films. *Applied Physics Letters*, **2015**, 106, 043901	3.4	7
880	Surface electrical properties of stainless steel fibres: An AFM-based study. **2015**, 330, 65-73		18
879	Growing perovskite into polymers for easy-processable optoelectronic devices. **2015**, 5, 7725		65
878	Cross-sectional potential profile across a BaSi2pn junction by Kelvin probe force microscopy. *Japanese Journal of Applied Physics*, **2015**, 54, 030306	1.4	3
877	Complete information acquisition in dynamic force microscopy. **2015**, 6, 6550		44
876	The influence of the local oxygen vacancy concentration on the piezoresponse of strontium titanate thin films. *Nanoscale*, **2015**, 7, 14351-7	7.7	21
875	Understanding the role of organic polar solvent induced nanoscale morphology and electrical evolutions of P3HT:PCBM composite film. **2015**, 25, 50-56		8
874	Non-Contact Local Conductance Mapping of Individual Graphene Oxide Sheets during the Reduction Process. **2015**, 6, 2629-35		7
873	Scanning Quantum Dot Microscopy. **2015**, 115, 026101		63
872	MoS2 Heterojunctions by Thickness Modulation. **2015**, 5, 10990		71
871	Microscopic Investigations into the Effect of Surface Treatment of Cathode and Electron Transport Layer on the Performance of Inverted Organic Solar Cells. *ACS Applied Materials & Interfaces*, **2015**, 7, 16418-27	9.5	17
870	Effect of surface contact potential in atomic-size contacts. **2015**, 379, 2239-2244		2
869	A highly sensitive, direct and label-free technique for Hg(2+) detection using Kelvin probe force microscopy. **2015**, 26, 305501		16
868	Tunable diameter electrostatically formed nanowire for high sensitivity gas sensing. **2015**, 8, 2206-2215		30
867	Strong electric fields at a prototypical oxide/water interface probed by ab initio molecular dynamics: MgO(001). **2015**, 17, 20382-90		30
866	SKPFM measured Volta potential correlated with strain localisation in microstructure to understand corrosion susceptibility of cold-rolled grade 2205 duplex stainless steel. **2015**, 99, 164-171		108

865	Investigating inhomogeneous electronic properties of radial junction solar cells using correlative microscopy. *Japanese Journal of Applied Physics*, **2015**, 54, 08KA08	1.4	7
864	Kelvin Probe Force Microscopy in Nanoscience and Nanotechnology. **2015**, 117-158		3
863	Effect of Oligomer Structure on the Diffraction Efficiency of Holographic Recording Media. **2015**, 51, 104-108		3
862	Effect of the Structure and Content of Carbazolyl-Containing Co-oligomers on the Diffraction Efficiency of Holographic Recording Media. **2015**, 51, 67-71		4
861	An in vivo study of electrical charge distribution on the bacterial cell wall by atomic force microscopy in vibrating force mode. *Nanoscale*, **2015**, 7, 8843-57	7.7	20
860	Electrochemical investigation of ITO□metal correlation accordance to metal thickness. **2015**, 12, 1447-1455		
859	Size dependence and UV irradiation tuning of the surface potential in single conical ZnO nanowires. **2015**, 5, 42075-42080		24
858	Effect of the Structure of Polymethine Dyes on Their Photovoltaic Properties in Polymer Films. **2015**, 51, 37-44		4
857	Surface potential imaging with atomic resolution by frequency-modulation Kelvin probe force microscopy without bias voltage feedback. **2015**, 26, 195701		14
856	Peculiarities of the photovoltaic properties of films based on photoconducting polymer and organic dye in samples with free surfaces and between electric contacts. **2015**, 41, 191-194		3
855	Hole-doping of mechanically exfoliated graphene by confined hydration layers. **2015**, 8, 3020-3026		13
854	Observing optical plasmons on a single nanometer scale. **2014**, 4, 4096		18
853	Processing of New Materials by Additive Manufacturing: Iron-Based Alloys Containing Silver for Biomedical Applications. **2015**, 46, 2829-2833		39
852	Tuning the graphene work function by uniaxial strain. *Applied Physics Letters*, **2015**, 106, 043106	3.4	19
851	Fundamentals of Organic Semiconductor Devices. **2015**, 307-388		5
850	Quantitative 3D-KPFM imaging with simultaneous electrostatic force and force gradient detection. **2015**, 26, 175707		23
849	Large-Area Epitaxial Monolayer MoS2. **2015**, 9, 4611-20		583
848	Morphological and electrical properties of self-assembled iron silicide nanoparticles on Si(0 0 1) and Si(1 1 1) substrates. **2015**, 357, 573-582		0

847	Carrier separation and transport in perovskite solar cells studied by nanometre-scale profiling of electrical potential. **2015**, 6, 8397		172
846	Nanoscale Electrostructural Characterization of Compositionally Graded Al(x)Ga(1-x)N Heterostructures on GaN/Sapphire (0001) Substrate. *ACS Applied Materials & Interfaces*, **2015**, 7, 23320-7	9.5	17
845	Assessment of Polarity in GaN Self-Assembled Nanowires by Electrical Force Microscopy. **2015**, 15, 6770-6		38
844	Work function measurements of olivine: Implication to photoemission charging properties in planetary environments. **2015**, 56, 2432-2438		
843	Determination of High-Frequency Dielectric Constant and Surface Potential of Graphene Oxide and Influence of Humidity by Kelvin Probe Force Microscopy. **2015**, 31, 11339-43		27
842	Two-Dimensional Carrier Profiling on Lightly Doped n-Type 4H-SiC Epitaxially Grown Layers. **2015**, 821-823, 269-272		1
841	Band excitation Kelvin probe force microscopy utilizing photothermal excitation. *Applied Physics Letters*, **2015**, 106, 104102	3.4	14
840	The generation of artificial microscopic defects in organic coatings by AFM scratching. **2015**, 100, 517-523		11
839	SYNTHESIZING AND CHARACTERIZING A WATERBORNE POLYANILINE FOR CORROSION PROTECTION OF STEELS. **2015**, 22, 1550021		2
838	Swift Heavy Ion Induced Optical and Electronic Modifications of Graphene□TiO2 Nanocomposites. *Journal of Physical Chemistry C*, **2015**, 119, 21270-21277	3.8	19
837	Spectroscopic ellipsometry, photoluminescence and Kelvin probe force microscopy studies of CdSe nanoparticles dispersed on ZnS thin film. **2015**, 117, 245310		11
836	Direct nm-Scale Spatial Mapping of Traps in CIGS. **2015**, 5, 1482-1486		21
835	Development of power semiconductors by quantitative nanoscale dopant imaging. **2015**,		
834	Quantitative Analysis of the Local Phase Transitions Induced by Laser Heating. **2015**, 9, 12442-50		18
833	Room temperature observation of quantum confinement in single InAs nanowires. **2015**, 15, 481-5		17
832	Effective AFM cantilever tip size: methods for in-situ determination. *Measurement Science and Technology*, **2015**, 26, 015002	2	19
831	Photodiode-like behavior and excellent photoresponse of vertical Si/monolayer MoS2 heterostructures. **2014**, 4, 7186		120
830	Quantifying charge carrier concentration in ZnO thin films by Scanning Kelvin Probe Microscopy. **2014**, 4, 4203		72

829	Tunnel conductivity switching in a single nanoparticle-based nano floating gate memory. **2014**, 4, 4196		18
828	Controlling ZnO nanowire surface density during its growth by altering morphological properties of a ZnO buffer layer by UV laser irradiation. **2015**, 118, 1239-1246		8
827	Investigation of micro-electrical properties of Cu2ZnSnSe4 thin films using scanning probe microscopy. *Solar Energy Materials and Solar Cells*, **2015**, 132, 342-347	6.4	20
826	Graphene on mica - intercalated water trapped for life. **2014**, 4, 6003		51
825	Nanoscale Characterization of Mock Explosive Materials Using Advanced Atomic Force Microscopy Methods. **2015**, 33, 51-65		7
824	Nanoplasmonic Metal□Insulator□Metal Waveguides. **2015**, 45-66		2
823	Local surface potential on hydrogenated microcrystalline silicon films. *Japanese Journal of Applied Physics*, **2016**, 55, 01AH10	1.4	1
822	Simultaneous observation of two dimensional electron gas and polarization in AlGaN/GaN heterostructure using scanning nonlinear dielectric microscopy. *Japanese Journal of Applied Physics*, **2016**, 55, 08NB13	1.4	6
821	Atomic-scale electric capacitive change detected with a charge amplifier installed in a non-contact atomic force microscope. **2016**, 9, 046601		1
820	Advances in AFM Imaging Applications for Characterizing the Biophysical Properties of Amyloid Fibrils. **2016**,		1
819	Imaging Water Thin Films in Ambient Conditions Using Atomic Force Microscopy. **2016**, 9,		20
818	Nanometer-Scale Electric Potential and Charge Density Measurements in Electrolyte Solution Using Frequency Modulation Atomic Force Microscopy. **2016**, 37, 475-481		
817	Surface Potential Analysis of Nanoscale Biomaterials and Devices Using Kelvin Probe Force Microscopy. **2016**, 2016, 1-21		18
816	Visualized Multiprobe Electrical Impedance Measurements with STM Tips Using Shear Force Feedback Control. **2016**, 16,		
815	The Wide-Open Door: Atomic Force Microscopy 30 Years On. **2016**, 24, 12-17		2
814	Characteristic Work Function Variations of Graphene Line Defects. *ACS Applied Materials & Interfaces*, **2016**, 8, 18360-6	9.5	29
813	A Roadmap for Controlled and Efficient n-Type Doping of Self-Assisted GaAs Nanowires Grown by Molecular Beam Epitaxy. **2016**, 26, 2836-2845		17
812	Oxidation of neodymium precipitates in a Ti6Al4V2Nd alloy in sodium chloride solution. **2016**, 67, 277-285		1

811	Adsorption of oriented carborane dipoles on a silver surface. **2016**, 253, 591-600		8
810	Mode-synthesizing atomic force microscopy for volume characterization of mixed metal nanoparticles. **2016**, 263, 307-11		2
809	Impact of Monovalent Cation Halide Additives on the Structural and Optoelectronic Properties of CH3NH3PbI3 Perovskite. **2016**, 6, 1502472		171
808	Optical second-harmonic generation measurement for probing organic device operation. **2016**, 5, e16040		27
807	Localized electrochemical characterization of organic coatings: A brief review. **2016**, 99, 365-377		55
806	Nanoscale surface charge detection in epoxy resin materials using electrostatic force spectroscopy. *AIP Advances*, **2016**, 6, 035318	1.5	17
805	Mapping the electrostatic force field of single molecules from high-resolution scanning probe images. **2016**, 7, 11560		76
804	Broadband local dielectric spectroscopy. *Applied Physics Letters*, **2016**, 108, 182906	3.4	8
803	Critical role of wettability in assembly of zirconia nanoparticles on a self-assembled monolayer-patterned substrate. **2016**, 120, 085304		4
802	High voltage surface potential measurements in ambient conditions: Application to organic thin-film transistor injection and transport characterization. **2016**, 119, 125501		16
801	Study of the Polarization Behavior of Ce0.9Gd0.1O2-Single Crystals below 350°C to Room Temperature. *Journal of the Electrochemical Society*, **2016**, 163, H1179-H1185	3.9	5
800	A new setup for the investigation of swift heavy ion induced particle emission and surface modifications. **2016**, 87, 013903		17
799	Milligram mass metrology using an electrostatic force balance. **2016**, 53, A86-A94		42
798	Forensic potential of atomic force microscopy. **2016**, 2, 93-104		18
797	Low work function of crystalline GeTe/Sb2Te3superlattice-like films induced by Te dangling bonds. *Journal Physics D: Applied Physics*, **2016**, 49, 495302	3	10
796	Investigation of the surface potential of TiO (110) by frequency-modulation Kelvin probe force microscopy. **2016**, 27, 505704		8
795	Developments in SPM technologies for semiconductor failure analysis. **2016**,		
794	Polarity in GaN and ZnO: Theory, measurement, growth, and devices. **2016**, 3, 041303		85

793	Investigation of the depletion layer by scanning capacitance force microscopy with Kelvin probe force microscopy. *Japanese Journal of Applied Physics*, **2016**, 55, 08NB10	1.4	9
792	Photodetection in p□ junctions formed by electrolyte-gated transistors of two-dimensional crystals. *Applied Physics Letters*, **2016**, 109, 201107	3.4	12
791	The weight function for charges□A rigorous theoretical concept for Kelvin probe force microscopy. **2016**, 119, 025304		8
790	Recent progress in nanoelectrical characterizations of CdTe and Cu(In, Ga)Se2. **2016**,		5
789	G-mode magnetic force microscopy: Separating magnetic and electrostatic interactions using big data analytics. *Applied Physics Letters*, **2016**, 108, 193103	3.4	21
788	Photoconducting Characteristics of Films of Poly(Vinyl Butyral)/Hetero-Polyoxometalate Composite. **2016**, 52, 10-15		
787	A symmetrical stretching stage for electrical atomic force microscopy. **2016**, 87, 185-188		2
786	Communication□The Effect of Hydrocarbon Contamination on the Volta Potential of Second Phase Particles in Beryllium. *Journal of the Electrochemical Society*, **2016**, 163, C420-C422	3.9	8
785	Memristive Behavior of Nb/NbOx/Nb Structures Prepared by Local Anodic Oxidation1. **2016**, 3, 803-809		0
784	Solid-state electrochemistry on the nanometer and atomic scales: the scanning probe microscopy approach. *Nanoscale*, **2016**, 8, 13838-58	7.7	22
783	Heterogeneity of surface potential in contact electrification under ambient conditions: A comparison of pre- and post-contact states. **2016**, 81, 76-81		11
782	Kelvin probe force microscopy of DNA-capped nanoparticles for single-nucleotide polymorphism detection. *Nanoscale*, **2016**, 8, 13537-44	7.7	14
781	The Effects of Substrates on 2D Crystals. **2016**, 67-113		5
780	Robust Hierarchically Structured Biphasic Ambipolar Oxide Photoelectrodes for Light-Driven Chemical Regulation and Switchable Logic Applications. **2016**, 28, 9308-9312		23
779	Imaging via complete cantilever dynamic detection: general dynamic mode imaging and spectroscopy in scanning probe microscopy. **2016**, 27, 414003		12
778	An attempt to correlate surface physics with chemical properties: molecular beam and Kelvin probe investigations of CeZrO thin films. **2016**, 18, 27594-27602		8
777	The nobility of second phase particles in S-65 beryllium studied by scanning kelvin probe force microscopy. **2016**, 112, 669-678		7
776	Hydrophilic Nanoparticles: Hydrophilic Polymer/Silica Hybrid Nanoparticles□An Overview of a Novel Synthesis Strategy and Its Application in the Proton Exchange Membrane. **2016**, 374-382		

775	Photo-generated charge behaviors in all-polymer solar cells studied by Kelvin probe force microscopy. **2016**, 39, 38-42		6
774	Reprint of: GaN nanowires on diamond. **2016**, 55, 32-45		7
773	Elucidating the charge carrier transport and extraction in planar heterojunction perovskite solar cells by Kelvin probe force microscopy. **2016**, 4, 17464-17472		38
772	Experimental Characterization of Interfaces of Relevance to Organic Electronics. **2016**, 159-191		2
771	Estimation of local built-in potential of amorphous silicon thin-film solar cells by Kelvin force microscopy. *Japanese Journal of Applied Physics*, **2016**, 55, 04ES13	1.4	1
770	Principal Factors of Contact Charging of Minerals for a Successful Triboelectrostatic Separation Process □ Review. **2016**, 161, 359-382		7
769	Role of irradiation-induced defects on SiC dissolution in hot water. **2016**, 112, 402-407		31
768	Electrodeposition of nanocrystalline zinc on steel for enhanced resistance to corrosive wear. **2016**, 304, 567-573		34
767	Local charge trapping in Ge nanoclustersdetected by Kelvin probe force microscopy. **2016**, 389, 783-789		8
766	Intrinsic Charge Trapping Observed as Surface Potential Variations in diF-TES-ADT Films. *ACS Applied Materials & Interfaces*, **2016**, 8, 21490-6	9.5	2
765	Heuristic Description of Magnetoelectricity of Cu2OSeO3. **2016**, 16, 5612-8		18
764	Imaging of electrical response of NiO x under controlled environment with sub-25-nm resolution. **2016**, 6, 038001		2
763	Precipitantless Crystallization of Protein Molecules Induced by High Surface Potential. **2016**, 16, 5323-5329		3
762	In-situ probing of thermal desorption of vapor molecules on a nanowire via work function variance. **2016**, 9, 3334-3345		6
761	Direct investigations of the interface impedance of organic field-effect transistors with self-assembled-monolayer-modified electrodes. **2016**, 38, 74-78		8
760	Scanning Probe Microscopy of Functional Materials Surfaces and Interfaces. **2016**, 63-125		6
759	Electrostatic and Kelvin Probe Force Microscopy for Domain Imaging of Ferroic Systems. **2016**, 435-460		1
758	Seeing Down to the Bottom: Nondestructive Inspection of All-Polymer Solar Cells by Kelvin Probe Force Microscopy. **2016**, 3, 1600446		11

757	Fast, high-resolution surface potential measurements in air with heterodyne Kelvin probe force microscopy. **2016**, 27, 245705		47
756	Scanning quantum dot microscopy: A quantitative method to measure local electrostatic potential near surfaces. *Japanese Journal of Applied Physics*, **2016**, 55, 08NA04	1.4	5
755	Scanning Probe Microscopy on Inorganic Thin Films for Solar Cells. **2016**, 343-369		
754	Growth models of coexisting p(2ˆ 1) and c(6ˆ 2) phases on an oxygen-terminated Cu(110) surface studied by noncontact atomic force microscopy at 78 K. **2016**, 27, 205702		2
753	Potentiometric measurement with a Kelvin probe: Contactless measurement of chloride ions in aqueous electrolyte. **2016**, 236, 1126-1132		6
752	Two competing interpretations of Kelvin probe force microscopy on semiconductors put to test. **2016**, 93,		13
751	Photoconducting Properties of Film Composites Based on Polyvinyl Butyral and Heterometallic Cu/Mo Complexes. **2016**, 83, 854-859		1
750	Full data acquisition in Kelvin Probe Force Microscopy: Mapping dynamic electric phenomena in real space. **2016**, 6, 30557		39
749	In Situ Observation of Enhanced Photoinduced Charge Separation in a Gold Nanoparticle Assembly Immobilized on TiO2. **2016**, 1, 5666-5670		1
748	Mapping surface charge density of lipid bilayers by quantitative surface conductivity microscopy. **2016**, 7, 12447		77
747	Measurement of surface potential and adhesion with Kelvin Probe Force Microscopy. **2016**,		
746	Mid-infrared time-resolved photoconduction in black phosphorus. **2016**, 3, 041006		42
745	Charge-state dynamics in electrostatic force spectroscopy. **2016**, 27, 274005		8
744	SPM for MEMS/NEMS Measurements. **2016**, 191-226		
743	Measurements of the work function of single-walled carbon nanotubes encapsulated by AgI, AgCl, and CuBr using kelvin probe technique with different kinds of probes. **2016**, 123, 143-148		4
742	Graphene on C-terminated face of 4H-SiC observed by noncontact scanning nonlinear dielectric potentiometry. *Japanese Journal of Applied Physics*, **2016**, 55, 08NB02	1.4	2
741	p+-doping analysis of laser fired contacts for silicon solar cells by Kelvin probe force microscopy. **2016**, 119, 105707		1
740	Kelvin-probe force microscopy of the pH-dependent charge of functional groups. *Applied Physics Letters*, **2016**, 108, 233702	3.4	10

739	Enhanced electrostatic force microscopy reveals higher-order DNA looping mediated by the telomeric protein TRF2. **2016**, 6, 20513		21
738	Using Kelvin probe force microscopy for controlling the phase composition of austenite□martensite chromium□nickel steel. **2016**, 52, 664-672		1
737	Quantitative analysis of sideband coupling in photoinduced force microscopy. **2016**, 94,		27
736	The Orientation Dependence of the Photochemical Activity of □Fe2O3. **2016**, 99, 2428-2435		9
735	Surface potential analysis on initial galvanic corrosion of Ti/Mg-Al dissimilar material. *Materials Chemistry and Physics*, **2016**, 179, 5-9	4.4	9
734	Improving lateral resolution of ambient electrostatic force microscopy by intermittent contact method. **2016**, 169, 96-106		1
733	Air-Stable n-Doping of WSe2 by Anion Vacancy Formation with Mild Plasma Treatment. **2016**, 10, 6853-60		147
732	Correlative EBSD and SKPFM characterisation of microstructure development to assist determination of corrosion propensity in grade 2205 duplex stainless steel. **2016**, 51, 1931-1948		41
731	Prominent local transport in silicon carbide composites containing in-situ synthesized three-dimensional graphene networks. **2016**, 36, 3073-3081		8
730	Effect of vacuum annealing on the photoconductivity of CuO thin films grown using sequential ionic layer adsorption reaction. *Materials Chemistry and Physics*, **2016**, 180, 149-155	4.4	9
729	Dopant imaging of power semiconductor device cross sections. **2016**, 160, 18-21		7
728	Surface electric potential of linear periodic charge density. **2016**, 714, 012012		
727	Influence of Au doping on electrical properties of CVD graphene. **2016**, 100, 625-631		20
726	Functionalized Carboxylate Deposition for rapid sensitization of dye-sensitized solar cells. **2016**, 126, 128-136		1
725	Raman Spectroscopy and Kelvin Probe Force Microscopy characteristics of the CVD suspended graphene. **2016**, 64, 27-33		18
724	Visualizing the Path of DNA through Proteins Using DREEM Imaging. **2016**, 61, 315-23		15
723	Nanoscale heterogeniety and workfunction variations in ZnO thin films. **2016**, 363, 516-521		18
722	Scanning probe microscopy polarization experiments with polycrystalline Ce0.8Gd0.2□PrxO2□ and Ce0.8Y0.2O2□single crystals at room temperature. **2016**, 288, 325-330		7

721	Synaptic compartmentalization by micropatterned masking of a surface adhesive cue in cultured neurons. **2016**, 92, 46-56		10
720	GaN nanowires on diamond. **2016**, 48, 65-78		18
719	Multifrequency spectrum analysis using fully digital G Mode-Kelvin probe force microscopy. **2016**, 27, 105706		33
718	Visualizing Nanoscale Distribution of Corrosion Cells by Open-Loop Electric Potential Microscopy. **2016**, 10, 2575-83		26
717	Consecutive Charging of a Molecule-on-Insulator Ensemble Using Single Electron Tunnelling Methods. **2016**, 16, 911-6		19
716	Electronic structure investigation of Al0.7Ga0.3As/GaAs nanometric heterostructures by Kelvin force microscopy. **2016**, 6, 6782-6787		1
715	Excluding Contact Electrification in Surface Potential Measurement Using Kelvin Probe Force Microscopy. **2016**, 10, 2528-35		44
714	Growth of single gold nanofilaments at the apex of conductive atomic force microscope tips. *Nanoscale*, **2016**, 8, 7496-500	7.7	7
713	Nanoscale characteristics of antibacterial cationic polymeric brushes and single bacterium interactions probed by force microscopy. **2016**, 6, 17092-17099		12
712	Redox-mediated flux control in functional paper. **2016**, 98, 429-436		29
711	Spatially resolved resistance of NiO nanostructures under humid environment. **2016**,		1
710	Applications of piezoresponse force microscopy in materials research: from inorganic ferroelectrics to biopiezoelectrics and beyond. **2016**, 61, 46-70		74
709	Spatial variation of wear and electrical properties across wrinkles in chemical vapour deposition graphene. **2016**, 102, 304-310		65
708	Kelvin Probe Force Microscopy investigations of High Strength Metallurgical Graphene transferred on low-density polyethylene. **2016**, 157, 71-77		2
707	Tailoring LaAlO3/SrTiO3 Interface Metallicity by Oxygen Surface Adsorbates. **2016**, 16, 2739-43		28
706	Critical invisible defect detection system of thin film transistor panels using Kelvin probe force microscopy. **2016**, 375, 19-25		1
705	Nanostructured Ir-supported on Ti4O7 as a cost-effective anode for proton exchange membrane (PEM) electrolyzers. **2016**, 18, 4487-95		35
704	Diamond nanoparticles as a way to improve electron transfer in sol-gel L-lactate biosensing platforms. **2016**, 908, 141-9		22

703	Layer-dependent surface potential of phosphorene and anisotropic/layer-dependent charge transfer in phosphorene-gold hybrid systems. *Nanoscale*, **2016**, 8, 129-35	7.7	54
702	Effect of nanoscale size and medium on metal work function in oleylamine-capped gold nanocrystals. **2016**, 89, 7-14		18
701	Ideal Scan Path for High-Speed Atomic Force Microscopy. **2017**, 22, 381-391		26
700	Generation, manipulation and characterization of molecules by atomic force microscopy. **2017**, 1,		116
699	Structure and local charging of electromigrated Au nanocontacts. **2017**, 28, 055206		4
698	Coupled Slow and Fast Charge Dynamics in Cesium Lead Bromide Perovskite. **2017**, 2, 488-496		11
697	Direct Imaging of Dopant Distribution in Polycrystalline ZnO Films. *ACS Applied Materials & Interfaces*, **2017**, 9, 7241-7248	9.5	7
696	The trapping, detrapping, and transport of the ambipolar charges in the electret of Polystyrene/C 60 blend films. **2017**, 44, 247-252		13
695	Buried Charge at the TiO/SrTiO (111) Interface and Its Effect on Photochemical Reactivity. *ACS Applied Materials & Interfaces*, **2017**, 9, 7843-7851	9.5	9
694	Induced inhomogeneity in graphene work function due to graphene - TiO2/Ag/glass substrate interaction. **2017**, 628, 43-49		6
693	Effective Contact Potential of Thin Film Metal-Insulator Nanostructures and Its Role in Self-Powered Nanofilm X-ray Sensors. *ACS Applied Materials & Interfaces*, **2017**, 9, 11258-11265	9.5	6
692	Anisotropic MoS Nanosheets Grown on Self-Organized Nanopatterned Substrates. **2017**, 29, 1605785		38
691	Growth of HfO2/TiO2 nanolaminates by atomic layer deposition and HfO2-TiO2 by atomic partial layer deposition. **2017**, 121, 064302		31
690	Quantitative AC - Kelvin Probe Force Microscopy. **2017**, 176, 28-32		8
689	Development of an improved Kelvin probe force microscope for accurate local potential measurements on biased electronic devices. **2017**, 267, 272-279		9
688	The structure and electrical properties of PbPdO2 thin films with preferred orientation prepared by PLD. **2017**, 43, 10428-10433		9
687	Hydrogen mapping in an aluminum alloy using an alternating current scanning electrochemical microscope (AC-SECM). **2017**, 80, 29-32		11
686	Force-gradient sensitive Kelvin probe force microscopy by dissipative electrostatic force modulation. *Applied Physics Letters*, **2017**, 110, 163103	3.4	13

685	Insight into interfaces and junction of polycrystalline silicon solar cells by kelvin probe force microscopy. **2017**, 36, 303-312		16
684	Reversible electrochemical modification of the surface of a semiconductor by an atomic-force microscope probe. **2017**, 51, 420-422		2
683	Internal potential mapping of charged solid-state-lithium ion batteries using in situ Kelvin probe force microscopy. *Nanoscale*, **2017**, 9, 893-898	7.7	56
682	A Kelvin probe force microscopy study of hydrogen insertion and desorption into 2024 aluminum alloy. **2017**, 722, 760-766		11
681	Near-equilibrium measurement of quantum size effects using Kelvin probe force microscopy. *Nanoscale*, **2017**, 9, 7868-7874	7.7	6
680	Photophysical Properties of Film Composites of Organic Polymers with Heterometallic Complexes of Transition Metals: a Review. **2017**, 53, 69-92		2
679	Transient surface photovoltage measurement over 12 orders of magnitude in time. **2017**, 88, 053904		7
678	Quantitative measurements of dielectrophoresis in a nanoscale electrode array with an atomic force microscopy. *Applied Physics Letters*, **2017**, 110, 203701	3.4	2
677	Reconstruction of electrostatic force microscopy image for nanoscale potential distributions with potential steps. *Measurement Science and Technology*, **2017**, 28, 055005	2	
676	Influence of metal choice on (010) □Ga2O3 Schottky diode properties. *Applied Physics Letters*, **2017** , 110, 202102	3.4	100
675	Surface potential of nanodiamonds investigated by KPFM. **2017**, 273-300		2
674	Non-contact scanning probe technique for electric field measurements based on nanowire field-effect transistor. **2017**, 179, 33-40		10
673	Forces from periodic charging of adsorbed molecules. **2017**, 146, 092327		13
672	Functional two/three-dimensional assembly of monolayer WS2 and nickel oxide. **2017**, 7, 014001		1
671	Multiparametric Kelvin Probe Force Microscopy for the Simultaneous Mapping of Surface Potential and Nanomechanical Properties. **2017**, 33, 2725-2733		15
670	Transformation of graphene flakes into carbon nanostructures by□rradiation. **2017**, 4, 045602		1
669	Nanoscale subsurface imaging. **2017**, 29, 173001		18
668	The work function of few-layer graphene. **2017**, 29, 035003		39

667	Influence of laser irradiation on local electronic properties of graphene in the presence of water adsorbate. **2017**, 90, 216-221		7
666	Atomic species recognition on oxide surfaces using low temperature scanning probe microscopy. **2017**, 394, 472-478		1
665	Imaging Energy Harvesting and Storage Systems at the Nanoscale. **2017**, 2, 2761-2777		33
664	Eigenmodes of a quartz tuning fork and their application to photoinduced force microscopy. **2017**, 95,		14
663	Recent advances in hybrid measurement methods based on atomic force microscopy and surface sensitive measurement techniques. **2017**, 7, 47464-47499		11
662	A simplified model to estimate thermal resistance between carbon nanotube and sample in scanning thermal microscopy. *Journal Physics D: Applied Physics*, **2017**, 50, 494004	3	8
661	Bipolar charge transfer induced by water: experimental and first-principles studies. **2017**, 19, 29418-29423		27
660	Photo-assisted Kelvin probe force microscopy investigation of three dimensional GaN structures with various crystal facets, doping types, and wavelengths of illumination. **2017**, 122, 085307		7
659	Edge-On MoS2 Thin Films by Atomic Layer Deposition for Understanding the Interplay between the Active Area and Hydrogen Evolution Reaction. **2017**, 29, 7604-7614		64
658	KPFM and its Use to Characterize the CPD in Different Materials. **2017**, 297-317		3
657	Hot Electron Nanoscopy and Spectroscopy (HENs). **2017**, 319-354		1
656	Efficient utilization of multilayer graphene towards thermionic convertors. **2017**, 121, 358-368		7
655	Hydrogen diffusion and trapping in a low copper 7xxx aluminium alloy investigated by Scanning Kelvin Probe Force Microscopy. **2017**, 706, 126-135		23
654	Temperature controlled interlayer disorder in ultrathin films of □-sexithiophene. **2017**, 642, 182-187		2
653	Photovoltaic Properties of Polymeric Film Composites with Ni(II), Co(II), and Cu(II) Complexes. **2017**, 53, 187-193		1
652	Adjustment of diffraction efficiency of polarization holograms in azobenzene polymers films using electric field. **2017**, 122, 013101		13
651	Charge erasure analysis on the nanoscale using Kelvin probe force microscopy. *AIP Advances*, **2017**, 7, 075104	1.5	1
650	Full Information Acquisition in Scanning Probe Microscopy. **2017**, 25, 34-45		3

649	Tuning of surface properties of poly vinyl alcohol by using graphene oxide nanosheets. **2017**,		
648	Observation of silicon carbide Schottky barrier diode under applied reverse bias using atomic force microscopy/Kelvin probe force microscopy/scanning capacitance force microscopy. *Japanese Journal of Applied Physics*, **2017**, 56, 08LB05	1.4	5
647	Effect of lateral tip motion on multifrequency atomic force microscopy. *Applied Physics Letters*, **2017**, 111, 043105	3.4	7
646	UV-activated ZnO films on a flexible substrate for room temperature O and HO sensing. **2017**, 7, 6053		44
645	Influences of water molecules on the electronic properties of atomically thin molybdenum disulfide. *Applied Physics Letters*, **2017**, 111, 043106	3.4	5
644	Nanoscale observation of organic thin film by atomic force microscopy. *Japanese Journal of Applied Physics*, **2017**, 56, 08LB08	1.4	1
643	Apparent Reversal of Molecular Orbitals Reveals Entanglement. **2017**, 119, 056801		12
642	Plasma enhanced hot filament CVD growth of thick carbon nanowall layers. **2017**,		
641	Breaking the Time Barrier in Kelvin Probe Force Microscopy: Fast Free Force Reconstruction Using the G-Mode Platform. **2017**, 11, 8717-8729		50
640	Dopant Profiling in Semiconductor Nanoelectronics. 203-221		
639	Scanning Probe Microscopy Principle of Operation, Instrumentation and Probes. **2017**, 725-768		1
638	Low-Temperature Scanning Probe Microscopy. **2017**, 769-808		
637	Numerical studies on sub-10 nanometer resolution imaging in electrostatic force microscopy. **2017**, 182, 148-160		1
636	Vector electric field measurement via position-modulated Kelvin probe force microscopy. *Applied Physics Letters*, **2017**, 111, 173106	3.4	2
635	Inkjet printing of NiO films and integration as hole transporting layers in polymer solar cells. **2017**, 7, 1775		30
634	The structural and electronic properties of metal atoms adsorbed on graphene. **2017**, 93, 265-270		6
633	Rewritable ghost floating gates by tunnelling triboelectrification for two-dimensional electronics. **2017**, 8, 15891		27
632	Stress-induced phase transition in lead-free relaxor ferroelectric composites. **2017**, 136, 271-280		75

631	Surface potential modeling and reconstruction in Kelvin probe force microscopy. **2017**, 28, 365705		11
630	Spatially-resolved nanoscale measurements of grain boundary enhanced photocurrent in inorganic CsPbBr3 perovskite films. *Solar Energy Materials and Solar Cells*, **2017**, 171, 205-212	6.4	32
629	A pulsed, mono-energetic and angular-selective UV photo-electron source for the commissioning of the KATRIN experiment. **2017**, 77, 1		15
628	Electrical domain writing and nanoscale potential modulation on LaVO3/SrTiO3. *Applied Physics Letters*, **2017**, 110, 261604	3.4	5
627	The composition, structure and surface properties of the titanium-carbon coatings prepared by PVD technique. **2017**, 309, 680-686		26
626	Unravelling charge separation via surface built-in electric fields within single particulate photocatalysts. **2017**, 198, 473-479		24
625	Comparing the photocatalytic activity of TiO at macro- and microscopic scales. **2017**, 24, 12683-12690		8
624	Vectorial scanning force microscopy using a nanowire sensor. **2017**, 12, 150-155		64
623	Flexible NO gas sensor based on conducting polymer poly[N -9?-heptadecanyl-2,7-carbazole-alt-5,5-(4?,7?-di-2-thienyl-2?,1?,3?-benzothiadiazole)] (PCDTBT). **2017**, 239, 734-745		72
622	Label-free and high-sensitive detection of Kirsten rat sarcoma viral oncogene homolog and epidermal growth factor receptor mutation using Kelvin probe force microscopy. **2017**, 87, 222-228		14
621	As cast microstructures on the mechanical and corrosion behaviour of ZK40 modified with Gd and Nd additions. **2017**, 682, 238-247		20
620	Dopant-Based Charge Sensing Utilizing P-I-N Nanojunction. **2017**, 24, 391-399		
619	Amplitude quantification in contact-resonance-based voltage-modulated force spectroscopy. **2017**, 122, 065106		9
618	Using dynamic force microscopy with piezoelectric cantilever for indentation and high-speed observation. **2017**, 8, 98-106		1
617	Atomic Force Microscopy: A Powerful Tool for Electrical Characterization. **2017**, 37-64		3
616	Identifying a doping type of semiconductor nanowires by photoassisted kelvin probe force microscopy as exemplified for GaN nanowires. **2017**, 7, 904		17
615	Contrast and imaging performance in photo induced force microscopy. **2017**, 25, 26923-26938		18
614	Analysis of Historic Copper Patinas. Influence of Inclusions on Patina Uniformity. **2017**, 10,		10

613	The Electrostatically Formed Nanowire: A Novel Platform for Gas-Sensing Applications. **2017**, 17,		10
612	Advanced Scanning Probe Microscopy of Graphene and Other 2D Materials. **2017**, 7, 216		21
611	Vickers Hardness of Diamond and cBN Single Crystals: AFM Approach. **2017**, 7, 369		26
610	Electrical Study of Trapped Charges in Copper-Doped Zinc Oxide Films by Scanning Probe Microscopy for Nonvolatile Memory Applications. **2017**, 12, e0171050		11
609	Scanning Probe Microscopy Techniques for Modern Nanomaterials. **2017**, 77-114		0
608	Fermi Level Tuning of ZnO Films Through Supercycled Atomic Layer Deposition. **2017**, 12, 541		14
607	Evaluation of carrier concentration reduction in GaN-on-GaN wafers by Raman spectroscopy and Kelvin force microscopy. *Japanese Journal of Applied Physics*, **2017**, 56, 08LB07	1.4	2
606	Creation of Optimal Frequency for Electrostatic Force Microscopy Using Direct Digital Synthesizer. **2017**, 7, 704		4
605	Scanning Probe Microscopy. **2017**, 183-243		1
604	Work Function of Metals. **2018**, 319-326		4
603	Kelvin Probe Force Microscope. **2018**, 313-317		
602	Significant photoluminescence enhancement in WS monolayers through NaS treatment. *Nanoscale*, **2018**, 10, 6105-6112	7.7	21
601	Rasterkraftmikroskopie fˆ □die molekulare Strukturaufklˆ ⁄ung. **2018**, 130, 3950-3972		9
600	Atomic Force Microscopy for Molecular Structure Elucidation. **2018**, 57, 3888-3908		85
599	Nanoscale Transport Imaging of Active Lateral Devices: Static and Frequency Dependent Modes. **2018**, 251-329		3
598	Room temperature ferroelectricity of hybrid organic□inorganic perovskites with mixed iodine and bromine. **2018**, 6, 9665-9676		21
597	Identification of nanoparticles and nanosystems in biological matrices with scanning probe microscopy. **2018**, 10, e1521		7
596	Manifold Coupling Mechanisms of Transition Metal Dichalcogenides to Plasmonic Gold Nanoparticle Arrays. *Journal of Physical Chemistry C*, **2018**, 122, 9663-9670	3.8	6

595	Dissipation Modulated Kelvin Probe Force Microscopy Method. **2018**, 23-47		1
594	Imaging Static Charge Distributions: A Comprehensive KPFM Theory. **2018**, 147-170		1
593	Interpretation of KPFM Data with the Weight Function for Charges. **2018**, 171-200		1
592	Quantitative Analysis of Kelvin Probe Force Microscopy on Semiconductors. **2018**, 227-247		
591	Infrared nanoscopy down to liquid helium temperatures. **2018**, 89, 033702		13
590	Proton beam flux dependent work function of mono-layer MoS2. **2018**, 660, 766-770		6
589	Calibrated work function mapping by Kelvin probe force microscopy. **2018**, 89, 043702		13
588	Comparisons of the topographic characteristics and electrical charge distributions among Babesia-infected erythrocytes and extraerythrocytic merozoites using AFM. **2018**, 271, 84-97		6
587	Functional material properties of oxide thin films probed by atomic force microscopy on the nanoscale. **2018**, 181-201		
586	On the Origin of Extended Resolution in Kelvin Probe Force Microscopy with a Worn Tip Apex. **2018**, 24, 126-131		2
585	Direct Imaging of Space-Charge Accumulation and Work Function Characteristics of Functional Organic Interfaces. **2018**, 14, e1703647		7
584	Homogenization of Al CoCrFeNi high-entropy alloys with improved corrosion resistance. **2018**, 133, 120-131		143
583	Local characterization of mobile charge carriers by two electrical AFM modes: multi-harmonic EFM versus sMIM. **2018**, 2, 025013		7
582	Nanoscale Mapping of the Surface Potential: Multifrequency Modulation Open-Loop Kelvin Probe Force Microscopy. **2018**, 17, 670-674		0
581	Study of charge transport properties in a ZnO/CdS/Cu(In,Ga)Se2 solar cell via admittance spectroscopy. **2018**, 36, 022904		9
580	Polarization Effects in Graded AlGaN Nanolayers Revealed by Current-Sensing and Kelvin Probe Microscopy. *ACS Applied Materials & Interfaces*, **2018**, 10, 6755-6763	9.5	11
579	Chemical Phenomena of Atomic Force Microscopy Scanning. **2018**, 90, 3475-3481		16
578	Imaging, microscopic analysis, and modeling of a CdTe module degraded by heat and light. *Solar Energy Materials and Solar Cells*, **2018**, 178, 46-51	6.4	7

577	Recording media for polarization holography with diffraction efficiency adjusted using electric field. **2018**, 158, 1308-1312		6
576	Surface-screening mechanisms in ferroelectric thin films and their effect on polarization dynamics and domain structures. **2018**, 81, 036502		93
575	Scanning Probe Microscopy Applied to Organic□norganic Halide Perovskite Materials and Solar Cells. **2018**, 2, 1700295		46
574	Kelvin probe force microscopy studies of the charge effects upon adsorption of carbon nanotubes and C60 fullerenes on hydrogen-terminated diamond. **2018**, 123, 015103		2
573	Simultaneous measurement of triboelectrification and triboluminescence of crystalline materials. **2018**, 89, 013901		10
572	In situ analytical techniques for battery interface analysis. **2018**, 47, 736-851		248
571	Illustration of charge transfer in graphene-coated hexagonal ZnO photocatalysts using Kelvin probe force microscopy.. **2018**, 8, 885-894		10
570	Photoluminescence in Spray Pyrolysis Deposited □n2S3 Thin Films. **2018**, 47, 2249-2256		3
569	Recording medium based on the films of azobenzene copolymer with free surface and in sandwich-structures for polarization holography. **2018**, 76, 169-173		6
568	Improved Diffraction Efficiency of Polarization-Sensitive Azobenzene-Containing Copolymers in an Electric Field. **2018**, 85, 143-148		
567	Selective light-induced mass transport in amorphous As x Se 100□ films driven by the composition tuning: Effect of temperature on maximum acceleration. **2018**, 493, 86-93		9
566	Thermomechanically and electromagnetically actuated piezoresistive cantilevers for fast-scanning probe microscopy investigations. **2018**, 276, 237-245		7
565	Gas selectivity of SILAR grown CdS nano-bulk junction. **2018**, 39, 033002		1
564	Piezotransistive GaN microcantilevers based surface work function measurements. *Japanese Journal of Applied Physics*, **2018**, 57, 040301	1.4	7
563	Time-Resolved Electrostatic and Kelvin Probe Force Microscopy. **2018**, 119-143		9
562	Experimental Technique and Working Modes. **2018**, 3-22		2
561	Kelvin Probe Force Microscopy Characterization of Organic and Hybrid Perovskite Solar Cells. **2018**, 331-365		4
560	Imaging Charge Distribution Within Molecules by Scanning Probe Microscopy. **2018**, 499-518		1

559	Applications of KPFM-Based Approaches for Surface Potential and Electrochemical Measurements in Liquid. **2018**, 391-433		2
558	Dynamic Modes in Kelvin Probe Force Microscopy: Band Excitation and G-Mode. **2018**, 49-99		3
557	Photoelectric Properties of Film Composites Based on Poly(Vinyl Butyral) and Heterometallic Complexes. **2018**, 84, 1056-1060		
556	Controlling the electric charge of gold nanoplatelets on an insulator by field emission nc-AFM. *Applied Physics Letters*, **2018**, 112, 113101	3.4	3
555	Fines adsorption on nanoparticle-coated surface. **2018**, 13, 219-226		16
554	Effect of dopant density on contact potential difference across n-type GaAs homojunctions using Kelvin Probe Force Microscopy. **2018**, 535, 84-88		3
553	Separating the influence of electric charges in magnetic force microscopy images of inhomogeneous metal samples. **2018**, 446, 239-244		10
552	Imaging prototypical aromatic molecules on insulating surfaces: a review. **2018**, 81, 016501		16
551	Water on graphene: review of recent progress. **2018**, 5, 022001		88
550	The golden alloy Cu-5Zn-5Al-1Sn: A multi-analytical surface characterization. **2018**, 131, 94-103		13
549	Investigation of an n□layer in a silicon fast recovery diode under applied bias voltages using Kelvin probe force microscopy. *Japanese Journal of Applied Physics*, **2018**, 57, 08NB11	1.4	4
548	Nanoscale investigation of the power MOSFET by the AFM/KFM/SCFM. **2018**,		
547	In situ characterization of nanoscale contaminations adsorbed in air using atomic force microscopy. **2018**, 9, 2925-2935		4
546	Band profiling of p-Si/ITO interface by Kelvin probe force microscopy under light controlled conditions. **2018**,		
545	Modulating the Work Function of Graphene by Pulsed Plasma Aided Controlled Chlorination. **2018**, 8, 17392		10
544	Imaging of electronical and magnetic properties on sub-10 nanometer scale with scanning force microscopy in ambient. **2018**, 191, 92-103		
543	Artifacts in time-resolved Kelvin probe force microscopy. **2018**, 9, 1272-1281		6
542	Photophysical Properties of a Composite Based on Polyepoxypropylpyridobenzothiazole with the Squarylium Dye. **2018**, 85, 870-874		

541	Effect of Azo Dyes on the Photoconductivity and Diffraction Efficiency of Holographic Recording Media. **2018**, 54, 316-321	2
540	Surface potential of meso-dimensional ZnS:Mn particles obtained using SHS method. **2018**, 20, 1	1
539	Quantitative comparison of closed-loop and dual harmonic Kelvin probe force microscopy techniques. **2018**, 89, 123708	7
538	Exclusive Magnetic Excitation Enabled by Structured Light Illumination in a Nanoscale Mie Resonator. **2018**, 12, 12159-12168	18
537	Nanoscale Characterization of Active Doping Concentration in Boron-Doped Individual Si Nanocrystals. **2018**, 215, 1800531	2
536	Dynamic charge transfer between polyester and conductive fibres by Kelvin probe force microscopy. **2018**, 96, 30-39	2
535	Methods and Means for Inspecting the Phase Composition of Two- and Three-Phase Austenitic Steels. **2018**, 54, 108-120	1
534	A Scalable, High-Throughput, and Environmentally Benign Approach to Polymer Dielectrics Exhibiting Significantly Improved Capacitive Performance at High Temperatures. **2018**, 30, e1805672	145
533	Recent development of PeakForce Tapping mode atomic force microscopy and its applications on nanoscience. **2018**, 7, 605-621	35
532	The Interplay of Contact Layers: How the Electron Transport Layer Influences Interfacial Recombination and Hole Extraction in Perovskite Solar Cells. **2018**, 9, 6249-6256	45
531	Nanodroplet Hydrodynamic Transformation of Uniform Amorphous Bilayer into Highly Modulated Ge/Si Island-Chains. **2018**, 18, 6931-6940	13
530	Charge Transfer within the F4TCNQ-MoS2 van der Waals Interface: Toward Electrical Properties Tuning and Gas Sensing Application. **2018**, 28, 1806244	41
529	Optical and Electrical Properties of TiO2/Co/TiO2 Multilayer Films Grown by DC Magnetron Sputtering. **2018**, 2018, 1-8	2
528	Contact electrification and charge decay on polyester fibres: A KPFM study. **2018**, 96, 16-22	7
527	3D Magnetic Field Reconstruction Methodology Based on a Scanning Magnetoresistive Probe. **2018** , 18,	2
526	Electro- and Photophysical Properties of Polymeric Film Composites with Monomers of Pyrido[2,1-b]benzothiazole Derivatives. **2018**, 85, 401-406	
525	Surface Potential Measurement of a Silicon Fast Recovery Diode under Applied Bias Voltages by Kelvin Probe Force Microscopy. **2018**,	
524	Compression-Induced Modification of Boron Nitride Layers: A Conductive Two-Dimensional BN Compound. **2018**, 12, 5866-5872	14

523	Ultimate Decoupling between Surface Topography and Material Functionality in Atomic Force Microscopy Using an Inner-Paddled Cantilever. **2018**, 12, 5559-5569	5
522	Self-Assembled Monolayers at the Conjugated Polymer/Electrode Interface: Implications for Charge Transport and Band-Bending Behavior. *ACS Applied Materials & Interfaces*, **2018**, 10, 21458-21465 9.5	6
521	The Role of Hydrogen from ALD-Al2O3 in Kesterite Cu2ZnSnS4 Solar Cells: Grain Surface Passivation. **2018**, 8, 1701940	49
520	Controlled atmosphere high-temperature scanning probe microscopy (CAHT-SPM). **2018**, 203-223	1
519	Reduce the hysteresis effect with the PEIE interface dipole effect in the organic-inorganic hybrid perovskite CH3NH3PbI3-xClx solar cell. **2018**, 62, 630-636	11
518	Charge separation via asymmetric illumination in photocatalytic Cu2O particles. **2018**, 3, 655-663	191
517	Electrostatic Fields. **2018**, 223-243	
516	Features of deactivation of excited states of cationic polymethine dye in the matrices of halogen-containing derivatives of poly-N-epoxypropyl carbazole. **2018**, 203, 349-357	2
515	High-veracity functional imaging in scanning probe microscopy via Graph-Bootstrapping. **2018**, 9, 2428	11
514	Microscopy with a single-molecule scanning electrometer. **2018**, 4, eaat5472	32
513	Imaging photogenerated charge carriers on surfaces and interfaces of photocatalysts with surface photovoltage microscopy. **2018**, 47, 8238-8262	190
512	Plasmoelectric Potential Mapping of a Single Nanoparticle. **2018**, 5, 3519-3525	11
511	Photothermoplastic recording media and its application in the holographic method of determination of the refractive index of liquid objects. **2018**, 57, 1832-1837	11
510	Combined scanning probe electronic and thermal characterization of an indium arsenide nanowire. **2018**, 9, 129-136	6
509	Electro-optical interfacial effects on a graphene/□conjugated organic semiconductor hybrid system. **2018**, 9, 963-974	5
508	Multifrequency Kelvin probe force microscopy on self assembled molecular layers and quantitative assessment of images' quality. **2018**, 194, 100-107	1
507	Electrometry by optical charge conversion of deep defects in 4H-SiC. **2018**, 115, 7879-7883	30
506	Evaluation of surface charge shift of collagen fibrils exposed to glutaraldehyde. **2018**, 8, 10126	15

505	High resolution subsurface imaging using resonance-enhanced detection in 2nd-harmonic KPFM. **2018**, 29, 405702		5
504	High-Resolution Atomic Force Microscopy Imaging of Nucleic Acids. **2018**, 1814, 3-17		2
503	AFM-Based Characterization of Electrical Properties of Materials. **2018**, 1814, 99-127		
502	Visualizing charges accumulated in an electric double layer by three-dimensional open-loop electric potential microscopy. *Nanoscale*, **2018**, 10, 14736-14746	7.7	8
501	Scanning Kelvin Probe Microscopy: Challenges and Perspectives towards Increased Application on Biomaterials and Biological Samples. **2018**, 11,		25
500	Nanoscale investigation of bulk heterojunction organic solar cell by scanning capacitance force microscopy. *Japanese Journal of Applied Physics*, **2018**, 57, 08NB05	1.4	4
499	Towards nanoscale electrical measurements in liquid by advanced KPFM techniques: a review. **2018** , 81, 086101		45
498	High Resolution Imaging, Spectroscopy and Nuclear Quantum Effects of Interfacial Water. **2018**,		
497	General Method To Define the Type of Carrier Transport Materials for Perovskite Solar Cells via Kelvin Probes Microscopy. **2018**, 1, 3984-3991		13
496	Surface potential extraction from electrostatic and Kelvin-probe force microscopy images. **2018**, 123, 184301		9
495	Low-Temperature Reduction of Graphene Oxide: Electrical Conductance and Scanning Kelvin Probe Force Microscopy. **2018**, 13, 139		53
494	Nanoscale investigation of the silicon carbide double-diffused MOSFET with scanning capacitance force microscopy. *Japanese Journal of Applied Physics*, **2018**, 57, 08NB09	1.4	3
493	Effect of Structure on the Photovoltaic Properties of Merocyanine Dyes in Polymer Films. **2018**, 54, 178-185		4
492	Edge State Engineering of Graphene Nanoribbons. **2018**, 18, 5744-5751		27
491	Applying Second and Third Resonance Frequencies to Surface Potential Measurements with Kelvin Probe Force Microscopy. **2018**, 16, 339-342		1
490	Time resolved surface photovoltage measurements using a big data capture approach to KPFM. **2018**, 29, 445703		26
489	Know your full potential: Quantitative Kelvin probe force microscopy on nanoscale electrical devices. **2018**, 9, 1809-1819		21
488	Passivity of Metals and the Kelvin Probe Technique. **2018**, 414-422		2

487	Multiscale Functional Imaging of Interfaces through Atomic Force Microscopy Using Harmonic Mixing. *ACS Applied Materials & Interfaces*, **2018**, 10, 28850-28859	9.5	10
486	Two-degree-of-freedom control combining machine learning and extremum seeking for fast scanning quantum dot microscopy. **2018**,		5
485	Functional Scanning Force Microscopy for Energy Nanodevices. **2018**, 30, e1802490		22
484	Piezotronic graphene barristor: Efficient and interactive modulation of Schottky barrier. **2018**, 50, 598-605		21
483	Nanoscale Control of Oxygen Defects and Metal-Insulator Transition in Epitaxial Vanadium Dioxides. **2018**, 12, 7159-7166		31
482	Vibrational and electrical properties of CuTe films: experimental data and first principle calculations. **2018**, 8, 8093		24
481	Nanoscale charge transfer and diffusion at the MoS/SiO interface by atomic force microscopy: contact injection versus triboelectrification. **2018**, 29, 355701		9
480	Scanning probe microscopy based characterization of battery materials, interfaces, and processes. **2019**, 65, 103925		26
479	Exceeding 20% efficiency with in situ group V doping in polycrystalline CdTe solar cells. **2019**, 4, 837-845		125
478	Sensitivity and accuracy of Casimir force measurements in air. **2019**, 100,		4
477	Toward Electrochemical Studies on the Nanometer and Atomic Scales: Progress, Challenges, and Opportunities. **2019**, 13, 9735-9780		18
476	Space Charge at Nanoscale: Probing Injection and Dynamic Phenomena Under Dark/Light Configurations by Using KPFM and C-AFM. **2019**, 267-301		0
475	Review of time-resolved non-contact electrostatic force microscopy techniques with applications to ionic transport measurements. **2019**, 10, 617-633		14
474	Resolving the 3D Orientation of Terphenylthiol Molecules on Noble Metals with Kelvin Probe Force Microscopy. *Journal of Physical Chemistry C*, **2019**, 123, 19659-19667	3.8	5
473	Electrical AFM for the Analysis of Resistive Switching. **2019**, 205-229		
472	Local Work Function Measurements of Thin Oxide Films on Metal Substrates. *Journal of Physical Chemistry C*, **2019**, 123, 17823-17828	3.8	14
471	Photoelectric Properties of Film Composites Derived from Poly-N-Epoxypropylcarbazole and Zwitter-Ionic Dyes. **2019**, 55, 103-109		
470	Imaging the surface potential at the steps on the rutile TiO(110) surface by Kelvin probe force microscopy. **2019**, 10, 1228-1236		9

469	Surface pinning and triggered unwinding of skyrmions in a cubic chiral magnet. **2019**, 100,		1
468	A new twist on superlubricity. **2019**, 18, 774		2
467	Electrical Atomic Force Microscopy for Nanoelectronics. **2019**,		12
466	The theory of scanning quantum dot microscopy. **2019**, 31, 475901		2
465	Oxide Heteroepitaxy-Based Flexible Ferroelectric Transistor. *ACS Applied Materials & Interfaces* , **2019**, 11, 25882-25890	9.5	22
464	Nonlinearity in piezotransistive GaN microcantilevers. **2019**, 29, 125011		3
463	Photoelectric Properties of Composite Films Based on Poly(N-Epoxypropyl Carbazole) and Merocyanine Dyes. **2019**, 86, 578-583		2
462	The ORNL Lectures on Scanning Probe Microscopy, Part 2: The Force Dimension: Electronic and Ionic Transport Measurements via Kelvin Probe Force Microscopy. **2019**, 27, 18-23		
461	Viewpoint: Atomic-Scale Design Protocols toward Energy, Electronic, Catalysis, and Sensing Applications. **2019**, 58, 14939-14980		18
460	Photovoltaic Properties of Polymer Film Composites with a Tetranuclear Copper Complex Cu4L4(OCH3)4 (L□= N,N?-Dibenzyl-N?-Trichloroacetylphosphotriamide). **2019**, 55, 240-245		
459	Information Properties of Halogen-Containing Media for Photothermoplastic Recording of Holograms. **2019**, 86, 912-916		
458	Thermodynamic considerations of same-metal electrodes in an asymmetric cell. **2019**, 3,		3
457	Photophysical Properties of Composite Based on Poly-N-Epoxypropylcarbazole and Nickel Dithiolene. **2019**, 86, 493-498		
456	Triboelectrification of Two-Dimensional Chemical Vapor Deposited WS at Nanoscale. **2019**, 9, 12570		2
455	Advances in Atomic Force Microscopy: Weakly Perturbative Imaging of the Interfacial Water. **2019**, 7, 626		8
454	Direct study of the electrical properties of PC12 cells and hippocampal neurons by EFM and KPFM. **2019**, 1, 537-545		12
453	Toward Improving Ambient Volta Potential Measurements with SKPFM for Corrosion Studies. *Journal of the Electrochemical Society*, **2019**, 166, C3018-C3027	3.9	16
452	Local electrical characterization of two-dimensional materials with functional atomic force microscopy. **2019**, 14, 1		26

451	Steady-state and transient behavior in dynamic atomic force microscopy. **2019**, 125, 044301		8
450	SPM-unit combined with optical microscope objective. **2019**,		1
449	Cross-sectional observation in nanoscale for Si power MOSFET by atomic force microscopy/Kelvin probe force microscopy/scanning capacitance force microscopy. *Japanese Journal of Applied Physics* , **2019**, 58, SIIA04	1.4	3
448	Statistical procedure for comparison of potential difference between single-component sample surface. **2019**, 12, 075011		1
447	Building a Casimir metrology platform with a commercial MEMS sensor. *Microsystems and Nanoengineering*, **2019**, 5, 14	7.7	22
446	Short- and Long-Range Mechanical and Chemical Interphases Caused by Interaction of Boehmite (□AlOOH) with Anhydride-Cured Epoxy Resins. **2019**, 9,		8
445	Advanced Characterization Methods for Electrical and Sensoric Components and Devices at the Micro and Nano Scales. **2019**, 216, 1900106		2
444	A Simple □PTV Setup to Estimate Single-Particle Charge of Triboelectrically Charged Particles. **2019**, 7, 323		3
443	Electric potentials at the atomic scale. **2019**, 18, 773-774		3
442	Interface dipoles of Ir(ppy) on Cu(111). *Nanoscale*, **2019**, 11, 12695-12703	7.7	3
441	Lagrangian and Impedance-Spectroscopy Treatments of Electric Force Microscopy. **2019**, 11,		4
440	Optoelectronic Tunability of Hf-Doped ZnO for Photovoltaic Applications. *Journal of Physical Chemistry C*, **2019**, 123, 15258-15266	3.8	8
439	Influence of dislocations on hydrogen diffusion and trapping in an Al-Zn-Mg aluminium alloy. **2019**, 180, 107901		15
438	Imaging of triboelectric charge distribution induced in polyimide film by using optical second-harmonic generation: Electronic charge distribution and dipole alignment. *Applied Physics Letters*, **2019**, 114, 233301	3.4	3
437	Study of Local Charge Accumulation in ZrO2(Y) Films with Au Nanoparticles by Kelvin Probe Force Micros□py. **2019**, 13, 30-35		
436	Two fold characteristics of swift heavy ion irradiation on Co3O4/RGO nanocomposites. **2019**, 486, 474-481		1
435	Reversible switching of the Au(111) work function by near infrared irradiation with a bistable SAM based on a radical donor□cceptor dyad. **2019**, 7, 7418-7426		1
434	Electron Transfer in Nanoscale Contact Electrification: Photon Excitation Effect. **2019**, 31, e1901418		54

433	A case study of the electrical properties of astrocytes by multimode AFM. **2019**, 275, 75-81		3
432	Beyond imaging: Applications of atomic force microscopy for the study of Lithium-ion batteries. **2019**, 204, 34-48		20
431	Spin Filtering Magnetoresistance in Double-Well Resonant Structures. **2019**, 256, 1800560		
430	Operando Analysis of Electron Devices Using Nanodiamond Thin Films Containing Nitrogen-Vacancy Centers. **2019**, 4, 7459-7466		2
429	Thermal Conductivity of a Supported Multiwalled Carbon Nanotube. *Journal of Physical Chemistry C* , **2019**, 123, 12460-12465	3.8	10
428	Size-dependent surface potential of Si-doped InN nanorods and the role of inhomogeneous free-electron distribution. **2019**, 125, 164308		4
427	Exact, approximate and asymptotic solutions of the Klein–Gordon integral equation. **2019**, 115, 141-156		2
426	Microscopic View of Tin Phthalocyanine Adsorption on the Rutile TiO_2(011) Surface. *Journal of Physical Chemistry C*, **2019**, 123, 9209-9216	3.8	4
425	Electron Transfer in Nanoscale Contact Electrification: Effect of Temperature in the Metal-Dielectric Case. **2019**, 31, e1808197		94
424	Unifying Energetic Disorder from Charge Transport and Band Bending in Organic Semiconductors. **2019**, 29, 1901109		51
423	Chiral molecules and the electron spin. **2019**, 3, 250-260		226
422	Investigation of charges-driven interactions between graphene and different SiO_2 surfaces. **2019**, 148, 336-343		8
421	Probe assisted localized doping of aluminum into silicon substrates. **2019**, 125, 075706		0
420	Unraveling the Role of Sn Segregation in the Electronic Transport of Polycrystalline Hematite: Raising the Electronic Conductivity by Lowering the Grain-Boundary Blocking Effect. **2019**, 5, 1900065		21
419	Piezoresponse Force Microscopy (PFM). **2019**, 291-316		3
418	Multifunctional atomic force probes for Mn^{2+} doped perovskite solar cells. **2019**, 425, 130-137		7
417	Atomic force microscopy-based cancer diagnosis by detecting cancer-specific biomolecules and cells. **2019**, 1871, 367-378		13
416	One-step ion beam irradiation manufacture of 3D micro/nanopatterned structures in SiC with tunable work functions. **2019**, 148, 387-393		2

415	High-resolution, spatially-resolved surface potential investigations of high-strength metallurgical graphene using scanning tunnelling potentiometry. **2019**, 212, 1-8		1
414	Insights into Nano-Scale Physical and Mechanical Properties of Epoxy/Boehmite Nanocomposite Using Different AFM Modes. **2019**, 11,		16
413	Wake-Up in a Hf0.5Zr0.5O2 Film: A Cycle-by-Cycle Emergence of the Remnant Polarization via the Domain Depinning and the Vanishing of the Anomalous Polarization Switching. **2019**, 1, 275-287		51
412	A dielectric-defined lateral heterojunction in a monolayer semiconductor. **2019**, 2, 60-65		53
411	Probing vacancy behavior across complex oxide heterointerfaces. **2019**, 5, eaau8467		12
410	Kelvin probe force microscopy for perovskite solar cells. **2019**, 62, 776-789		52
409	Sculpturing graphene wrinkle patterns into compliant substrates. **2019**, 146, 772-778		9
408	Nanometer-Scale Imaging of Inhomogeneous Active Charge Carriers in Arsenic-Doped CdTe Thin Films. **2019**,		
407	. **2019**,		
406	Investigation the Structure and Property of Two-dimensional Materials Using Scanning Probe Techniques. **2019**,		
405	Increasing the SNR of Electrical AFM Methods by Active Mechanical Q-control. **2019**, 52, 307-312		
404	Characterization of Intact Eukaryotic Cells with Subcellular Spatial Resolution by Photothermal-Induced Resonance Infrared Spectroscopy and Imaging. **2019**, 24,		4
403	Dynamically visualizing battery reactions by operando Kelvin probe force microscopy. **2019**, 2,		12
402	Development of atomic force microscopy combined with scanning electron microscopy for investigating electronic devices. *AIP Advances*, **2019**, 9, 115011	1.5	2
401	Signal reversal in Kelvin-probe force microscopy. **2019**, 90, 113703		3
400	Internal electric field engineering for steering photogenerated charge separation and enhancing photoactivity. **2019**, 1, e12007		47
399	Advances in Scanning Thermal Microscopy Measurements for Thin Films. **2019**,		2
398	Probing the origins of electroresistance switching behavior in ferroelectric thin films. *Applied Physics Letters*, **2019**, 115, 242901	3.4	7

397	Tuning Hole Transport Layer Using Urea for High-Performance Perovskite Solar Cells. **2019**, 29, 1806740	71
396	Atomic Force Microscopy Meets Biophysics, Bioengineering, Chemistry, and Materials Science. **2019** , 12, 603-611	13
395	Nanomorphology in A□D□A type small molecular acceptors-based bulk heterojunction polymer solar cells. **2019**, 35, 104-123	19
394	Surface-enhanced Raman scattering in graphene deposited on Al Ga1□N/GaN axial heterostructure nanowires. **2019**, 475, 559-564	6
393	Understanding the relation between pitting corrosion resistance and phase fraction of S32101 duplex stainless steel. **2019**, 149, 226-235	27
392	Effect of Window-Layer Materials on p-n Junction Location in Cu(In,Ga)Se2 Solar Cells. **2019**, 9, 308-312	6
391	Tailored amorphous ITAZO transparent conductive electrodes. **2019**, 90, 252-258	6
390	Field emission properties of single crystalline W5O14 and W18O49 nanowires. **2020**, 241, 146837	6
389	ELECTRONIC AND STRUCTURAL PROPERTIES OF Si□Cd□O ELECTRON EMITTER. **2020**, 27, 1950089	
388	Direct growth of mm-size twisted bilayer graphene by plasma-enhanced chemical vapor deposition. **2020**, 156, 212-224	15
387	Effect of large work function modulation of MoS2 by controllable chlorine doping using a remote plasma. **2020**, 8, 1846-1851	11
386	Mechanical Exfoliation of Select MAX Phases and Mo Ce Al C Single Crystals to Produce MAXenes. **2020**, 16, e1905784	15
385	The effect of work function difference between cathode and anode materials on the potential window of the supercapacitor. **2020**, 332, 135479	7
384	Piezoelectric displacement mapping of compliant surfaces by constant-excitation frequency-modulation piezoresponse force microscopy. **2020**, 31, 075707	1
383	Study on energy level bending at heterojunction of solution-processed phthalocyanine thin film and n-Si by Kelvin probe force microscopy. **2020**, 78, 105599	1
382	Combined measurement of electronic and ionic work functions, w(e)□and w(Li+), for lithium phosphate. **2020**, 128, 115108	
381	Algal Biophotovoltaic Devices: Surface Potential Studies. **2020**, 8, 10511-10520	6
380	Field-induced reorientation of helimagnetic order in Cu2OSeO3 probed by magnetic force microscopy. **2020**, 102,	5

379	Macroscopic manifestation of domain-wall magnetism and magnetoelectric effect in a Nˆ el-type skyrmion host. **2020**, 5,		13
378	Measurement of electrostatic tip-sample interactions by time-domain Kelvin probe force microscopy. **2020**, 11, 911-921		1
377	Developments and Recent Progresses in Microwave Impedance Microscope. **2020**, 8,		
376	Application of AFM-Based Techniques in Studies of Corrosion and Corrosion Inhibition of Metallic Alloys. **2020**, 1, 345-372		8
375	Detection of the Electric Potential Surface Distribution with a Local Probe Based on a Field Effect Transistor with a Nanowire Channel. **2020**, 65, 832-838		
374	Strain-Work Function Relationship in Single-Crystal Tetracene. *ACS Applied Materials & Interfaces*, **2020**, 12, 40607-40612	9.5	3
373	Effects of Surface Functional Groups on Electron Transfer at Liquid-Solid Interfacial Contact Electrification. **2020**, 14, 10733-10741		45
372	DNA-Based Fabrication for Nanoelectronics. **2020**, 20, 5604-5615		13
371	Sensitivity Analysis of Kelvin Probe Force Microscopy Using Different Probes under Air or UHV Condition. **2020**,		
370	Surface potential imaging and characterizations of a GaN p-n junction with Kelvin probe force microscopy. *AIP Advances*, **2020**, 10, 085010	1.5	2
369	Atomically Asymmetric Inversion Scales up to Mesoscopic Single-Crystal Monolayer Flakes. **2020**, 14, 13834-13840		5
368	Tailoring the Grain Boundaries of Wide-Bandgap Perovskite Solar Cells by Molecular Engineering. **2020**, 4, 2000384		6
367	Bayesian inference in band excitation scanning probe microscopy for optimal dynamic model selection in imaging. **2020**, 128, 054105		4
366	Low-Pressure Mechanical Switching of Ferroelectric Domains in PbZr0.48Ti0.52O3. **2020**, 6, 2000523		7
365	Nanoelectronic Characterization: Using Near-Field Microwave Microscopy for Nanotechnological Research. **2020**, 21, 36-51		5
364	Modulation of Electrical Properties with Controllable Local Doping in Multilayer MoTe2 Transistors. **2020**, 6, 2000532		5
363	Injection and Retention Characterization of Trapped Charges in Electret Films by Electrostatic Force Microscopy and Kelvin Probe Force Microscopy. **2020**, 217, 2000190		3
362	Atomic Force Microscopy Based Top-Illumination Electrochemical Tip-Enhanced Raman Spectroscopy. **2020**, 92, 12548-12555		13

361	Uncovering topographically hidden features in 2D MoSe2 with correlated potential and optical nanoprobes. **2020**, 4,		8
360	Electrical Access to Ising Anyons in Kitaev Spin Liquids. **2020**, 125, 227202		2
359	Noncontact atomic force microscopy: Bond imaging and beyond. **2020**, 75, 100509		7
358	Bottom-tracking: the possibilities and physical meaning of keeping the bottom of the frequency shift in atomic force microscopy. *Japanese Journal of Applied Physics*, **2020**, 59, SN1012	1.4	
357	Volta potential mapping of the gradient strengthened layer in 20CrMnTi by using SKPFM. **2020**, 55, 12403-12420		4
356	Analytical Investigations in Rechargeable Batteries. **2020**, 217-235		
355	Peak Force Infrared‐Kelvin Probe Force Microscopy. **2020**, 132, 16217-16224		5
354	Peak Force Infrared-Kelvin Probe Force Microscopy. **2020**, 59, 16083-16090		5
353	The notion of potential. **2020**, 63-89		
352	Carrier distribution measurement in semiconductor materials and devices. **2020**, 153-174		
351	Strain relaxation, extended defects and doping effects in InxGa1-xN/GaN heterostructures investigated by surface photovoltage. **2020**, 515, 146016		1
350	Doping of MoTe via Surface Charge Transfer in Air. *ACS Applied Materials & Interfaces*, **2020**, 12, 18182-18193	9.5	9
349	Surface Potential/Charge Sensing Techniques and Applications. **2020**, 20,		4
348	Method to Quantify Nanoscale Surface Charge in Liquid with Atomic Force Microscopy. **2020**, 36, 4123-4134		3
347	Electrical Potential and Topography of the Surface of a Calcium-Phosphate Coating Deposited with RF-Magnetron Discharge. **2020**, 14, 200-206		3
346	Pulsed Plasma Assisted Cl-Doped Graphene Nano Dots with Semiconducting Property. **2020**, 49, 648-651		1
345	Kelvin probe force microscopic investigation of graphene-based derivatives. *Japanese Journal of Applied Physics*, **2020**, 59, SN1002	1.4	5
344	Prevention of Electrostatic Charge Generation in Filtration of Low-Conductivity Oils by Surface Modification of Modern Filter Media. **2020**, 63, 393-402		

343	Tunable Optoelectronic Properties of WS2 by Local Strain Engineering and Folding. **2020**, 6, 1901381		18
342	Scanning nonlinear dielectric potentiometry for measurement of the potential induced by atomic dipole moments. **2020**, 113-140		
341	High-speed digitization of the amplitude and frequency in open-loop sideband frequency-modulation Kelvin probe force microscopy. **2020**, 31, 385706		2
340	Inhomogeneous probe surface induced effect in Kelvin probe force microscopy. **2020**, 127, 184302		1
339	Nanoscale Characteristics of Ocular Lipid Thin Films Using Kelvin Probe Force Microscopy. **2020**, 9, 41		0
338	Single-step fabrication and work function engineering of Langmuir-Blodgett assembled few-layer graphene films with Li and Au salts. **2020**, 10, 8476		4
337	Correlated Electrical and Chemical Nanoscale Properties in Potassium-Passivated, Triple-Cation Perovskite Solar Cells. **2020**, 7, 2000515		3
336	Visualizing Charge Transport and Nanoscale Electrochemistry by Hyperspectral Kelvin Probe Force Microscopy. *ACS Applied Materials & Interfaces*, **2020**, 12, 33361-33369	9.5	5
335	A Method for Reconstructing the Potential Profile of Surfaces Coated with a Dielectric Layer. **2020**, 75, 70-75		1
334	Evaluation of silicon carbide Schottky barrier diode within guard ring by multifunctional scanning probe microscopy. *Japanese Journal of Applied Physics*, **2020**, 59, SN1014	1.4	0
333	Effect of Chiral Molecules on the Electron's Spin Wavefunction at Interfaces. **2020**, 11, 1550-1557		33
332	Development of dual bias modulation electrostatic force microscopy for variable frequency measurements of capacitance. **2020**, 91, 023702		6
331	Development of scanning capacitance force microscopy using the dissipative force modulation method. *Measurement Science and Technology*, **2020**, 31, 035904	2	
330	Imaging hole-density inhomogeneity in arsenic-doped CdTe thin films by scanning capacitance microscopy. *Solar Energy Materials and Solar Cells*, **2020**, 209, 110468	6.4	4
329	Manipulating and Probing the Distribution of Excess Electrons in an Electrically Isolated Self-Assembled Molecular Structure. **2020**, 20, 1839-1845		5
328	Towards standardisation of contact and contactless electrical measurements of CVD graphene at the macro-, micro- and nano-scale. **2020**, 10, 3223		6
327	Surface potential microscopy of surfactant-controlled single gold nanoparticle. **2020**, 31, 215706		5
326	Quantifying electron-transfer in liquid-solid contact electrification and the formation of electric double-layer. **2020**, 11, 399		149

325	Production and processing of graphene and related materials. **2020**, 7, 022001		179
324	The Overlapped Electron-Cloud Model for Electron Transfer in Contact Electrification. **2020**, 30, 1909724		26
323	Pulsed Force Kelvin Probe Force Microscopy. **2020**, 14, 4839-4848		15
322	Imaging mechanism for hyperspectral scanning probe microscopy via Gaussian process modelling. **2020**, 6,		9
321	A facile fabrication procedure for platinum nanoprobes with high-aspect-ratio and low tip radii via electrochemical etching. **2020**, 91, 033702		
320	Nanoscale Probing of Magnetic and Electrical Properties of YIG/Si (100) Thin Films Grown by Pulsed Laser Deposition. **2020**, 11, 1-5		1
319	Surface Potential and Interfacial Water Order at the Amorphous TiO Nanoparticle/Aqueous Interface.. *Journal of Physical Chemistry C*, **2020**, 124, 10961-10974	3.8	13
318	Photoconducting polymeric nanocomposites and their application in holographic interferometry. **2020**, 345-417		1
317	Visualizing Piezoelectricity on 2D Crystals Nanobubbles. **2021**, 31, 2005053		7
316	Unexpected Coulomb Interactions in Nonpolar Solvent for Highly Efficient Nanoxerography of Perovskite Quantum Dots. **2021**, 12, 59-64		2
315	Tuning halide perovskite energy levels. **2021**, 14, 1429-1438		38
314	Polyelectrolyte-calcium complexes as a pre-precursor induce biomimetic mineralization of collagen. *Nanoscale*, **2021**, 13, 953-967	7.7	14
313	Short- and Long-Range Particle-Matrix Interphases. **2021**, 143-178		1
312	Investigation of electronic properties of chemical vapor deposition grown single layer graphene via doping of thin transparent conductive films. **2021**, 11, 3096-3103		3
311	Co-evaporation of CHNHPbI: How Growth Conditions Impact Phase Purity, Photostriction, and Intrinsic Stability. *ACS Applied Materials & Interfaces*, **2021**, 13, 2642-2653	9.5	2
310	Modulation of MoTe/MoS van der Waals heterojunctions for multifunctional devices using NO plasma with an opposite doping effect. *Nanoscale*, **2021**, 13, 7851-7860	7.7	2
309	Determination of Lithium Diffusion Coefficients in Single Battery Active Material Particles by Using an AFM-Based Steady-State Diffusion Depolarization Technique. *Journal of Physical Chemistry C*, **2021**, 125, 2230-2239	3.8	1
308	Revealing Surface Charge Population on Flake-Like BiVO4 Photocatalysts by Single Particle Imaging Spectroscopies. **2021**, 4, 2543-2551		5

307	Balanced Ambipolar Charge Transport in Phenacene/Perylene Heterojunction-Based Organic Field-Effect Transistors. *ACS Applied Materials & Interfaces*, **2021**, 13, 8631-8642	9.5	5
306	Achieving High Power Density and Long-Term Stable Flexible Triboelectric Nanogenerators through Surface Functionalization of High Work-Function Electrode with Cationic Thiol-Based Self-Assembled Monolayer. **2021**, 6, 2000985		3
305	Alignment method for the accurate and precise quantification of tip-surface forces. **2021**, 103,		1
304	Work function difference of naphthyl end-capped oligothiophene in different crystal alignments studied by Kelvin probe force microscopy. **2021**, 89, 106060		1
303	Modulating Nanoinhomogeneity at Electrode⍰Solid Electrolyte Interfaces for Dendrite-Proof Solid-State Batteries and Long-Life Memristors. **2021**, 11, 2003811		18
302	Imaging Graphene Moirˆ 'Superlattices via Scanning Kelvin Probe Microscopy. **2021**, 21, 3280-3286		3
301	Piezo-electric fields and state-filling photo-luminescence in natural InP/GaInP2 Wigner molecule structures. *Applied Physics Letters*, **2021**, 118, 121101	3.4	2
300	Photophysical Properties of Composites Derived from Poly-N-Epoxypropylcarbazole and Molecules of Organic Conductors. **2021**, 88, 70-76		
299	Charge injection and decay of nanoscale dielectric films resolved via dynamic scanning probe microscopy. **2021**, 104, 5157-5167		2
298	Compensating for artifacts in scanning near-field optical microscopy due to electrostatics. **2021**, 6, 036102		3
297	Direct observation of surface charge redistribution in active nanoscale conducting channels by Kelvin Probe Force Microscopy. **2021**, 32,		1
296	SCREENING EFFECTS AT ORGANIC⍰D MATERIAL HETEROINTERFACES. **2021**, 28, 2140008		
295	Atomic-Scale Local Work Function Characterizations of Br Islands on Cu(111). *Journal of Physical Chemistry C*, **2021**, 125, 7944-7949	3.8	1
294	Kelvin probe force microscopy studies on the influence of hydrocarbon chain length on 1-alkene self-assembled monolayers on Si (111). *Japanese Journal of Applied Physics*, **2021**, 60, SE1005	1.4	2
293	Functionalized silicon substrates with stripe-patterned surface-near electrostatic forces for the self-organized, stable immobilization of biomolecules. **2021**, 545, 148729		1
292	Local-probe based electrical characterization of a multiphase intermetallic ⍰TiAl based alloy. **2021**, 129, 205107		
291	Role of Decomposition Product Ions in Hysteretic Behavior of Metal Halide Perovskite. **2021**, 15, 9017-9026		3
290	Highly sensitive NO2 sensor based on ZnO nanostructured thin film prepared by SILAR technique. **2021**, 335, 129678		7

289	Scanning triboelectric nanogenerator as a nanoscale probe for measuring local surface charge density on a dielectric film. *Applied Physics Letters*, **2021**, 118, 193901	3.4	6
288	Scanning probe microscopy. **2021**, 1,		31
287	Edge channels of broken-symmetry quantum Hall states in graphene visualized by atomic force microscopy. **2021**, 12, 2852		3
286	Twisted graphene in graphite: Impact on surface potential and chemical stability. **2021**, 176, 431-439		3
285	A modelling approach to describe the DC current-voltage behaviour of low-voltage zinc oxide varistors. **2021**, 6, 100113		3
284	Weak ferroelectric charge transfer in layer-asymmetric bilayers of 2D semiconductors. **2021**, 11, 13422		6
283	Quantification of Interactions at the Polymer–Substrate Interface: Implications for Nanoscale Behavior. **2021**, 54, 6257-6266		0
282	Room Temperature Processed Transparent Amorphous InGaTiO Cathodes for Semi-Transparent Perovskite Solar Cells. *ACS Applied Materials & Interfaces*, **2021**, 13, 27353-27363	9.5	5
281	Environmental temperature effect on dimensional measurements of atomic force microscopy. **2021**, 4, 023003		
280	Application of Atomic Force Microscopy in Organic and Perovskite Photovoltaics.		0
279	Water at charged interfaces. **2021**, 5, 466-485		50
278	Detecting the Liquid–Solid Contact Electrification Charges in a Liquid Environment. *Journal of Physical Chemistry C*, **2021**, 125, 14098-14104	3.8	8
277	Integrated Tapping Mode Kelvin Probe Force Microscopy with Photoinduced Force Microscopy for Correlative Chemical and Surface Potential Mapping. **2021**, 17, e2102495		2
276	Second Harmonic Generation Spectroscopy. **2021**, 225-244		
275	Fabrication of the FET-based SPM probe by CMOS standard process and its performance evaluation. **2021**, 30, 236-242		
274	Kinetics of Nanoscale Probe-Based Contact Electrification between Metal and Polymethyl Methacrylate under Bias. **2021**, 73, 40-40		
273	Observing Electrochemical Reactions on Suspended Graphene: An Operando Kelvin Probe Force Microscopy Approach. **2021**, 8, 2100662		0
272	Charge Behavior of Terminal Hydroxyl on Rutile TiO(110). **2021**, 37, 10588-10593		0

271	Strong phonon-cavity coupling and parametric interaction in a single microcantilever under ambient conditions. *Journal Physics D: Applied Physics*, **2021**, 54, 475307	3	1
270	On-Surface Synthesis of a Dicationic Diazahexabenzocoronene Derivative on the Au(111) Surface. **2021**, 60, 25551-25556		2
269	Energy landscape in silver-bismuth-iodide rudorffites: Combining scanning tunneling spectroscopy and Kelvin probe force microscopy. **2021**, 5,		1
268	Decoding the shift-invariant data: applications for band-excitation scanning probe microscopy.		4
267	On-Surface Synthesis of a Dicationic Diazahexabenzocoronene Derivative on the Au(111) Surface.		0
266	Photovoltaic distribution on an amorphous-silicon solar cell in near-band-edge excitation observed by conductive-probe atomic force microscopy combined with a fine-wavelength-tunable light source. **2021**, 92, 095103		
265	Quantitative amplitude-modulation scanning Kelvin probe microscopy via the second eigenmode excitation. **2021**, 230, 113399		0
264	Nanoscale Mapping of Potential Barrier Degradation at BaTiO3□Ni Interfaces.		3
263	The impact of Kelvin probe force microscopy operation modes and environment on grain boundary band bending in perovskite and Cu(In,Ga)Se2 solar cells. **2021**, 88, 106270		6
262	Metal induced charge transfer doping in graphene-ruthenium hybrid interconnects. **2021**, 183, 999-1011		1
261	Effect of hydrogen peroxide on bovine serum albumin adsorption on Ti6Al4V alloy: A scanning Kelvin probe force microscopy study. **2021**, 563, 150364		6
260	Observation of Power MOSFET Composed of Silicon Carbide with a Planar Type in the Voltage Applying State Using a Scanning Probe Microscope. **2021**, 141, 349-355		1
259	Chemically tailored molecular surface modification of cellulose nanofibrils for manipulating the charge density of triboelectric nanogenerators. **2021**, 89, 106369		25
258	Li2S doping into CZTSe drives the large improvement of VOC of solar cell. **2021**, 62, 637-644		2
257	Absolute work function measurement by using photoelectron spectroscopy. **2021**, 31, 52-59		5
256	Interpreting Kelvin probe force microscopy on semiconductors by Fourier analysis. **2021**, 129, 034301		0
255	Torsional Harmonic Kelvin Probe Force Microscopy for High-Sensitivity Mapping of Surface Potential. **2021**, 1-1		1
254	Kelvin probe force microscopy to study electrostatic interactions of DNA with lipid-gemini surfactant monolayers for gene delivery. **2021**, 17, 826-833		0

253	Atomic, molecular, charge manipulation and application of atomic force microscopy. **2021**, 70, 136802-136802	2
252	AFM and STM in Photochemistry Including Photon Tunneling. 119-177	6
251	SFM-Based Methods for Ferroelectric Studies. **2005**, 223-249	1
250	Scanning Probe Microscopy Principle of Operation, Instrumentation, and Probes. **2005**, 41-115	5
249	Scanning Probe Microscopy Principle of Operation, Instrumentation, and Probes. **2004**, 325-369	3
248	Nanoscale Characterization of Electronic and Electrical Properties of III-Nitrides by Scanning Probe Microscopy. **2007**, 690-714	1
247	High-Sensitivity Electric Force Microscopy of Organic Electronic Materials and Devices. **2007**, 788-830	9
246	Electrical SPM-Based Nanofabrication Techniques. **2007**, 833-857	1
245	Frequency-Dependent Transport Imaging by Scanning Probe Microscopy. **2007**, 132-172	4
244	Scanning Force Microscopies for Imaging and Characterization of Nanostructured Materials. **2007**, 223-256	1
243	Dynamic-Contact Electrostatic Force Microscopy and its Application to Ferroelectric Domain. **2004**, 157-182	5
242	Scanning Probe Microscopy in Materials Science. **2019**, 1239-1277	6
241	Scanning Probe Microscopy in Practical Diagnostic: 3D Topography Imaging and Nanometrology. **2014**, 179-219	1
240	Defects on Bulk MgO(001) Imaged by nc-AFM. **2015**, 215-239	2
239	Atomic Resolution on Molecules with Functionalized Tips. **2015**, 223-246	5
238	The Phantom Force. **2015**, 71-92	1
237	Scanning Probe MicroscopyPrinciple of Operation, Instrumentation, and Probes. **2017**, 33-93	4
236	Scanning Probe Microscopy Principle of Operation, Instrumentation, and Probes. **2007**, 591-636	5

235	Dynamic Force Microscopy for Molecular-Scale Investigations of Organic Materials in Various Environments. **2007**, 205-245	2
234	Novel AFM Nanoprobes. **2007**, 77-134	1
233	Application of Scanning Capacitance Microscopy to Analysis at the Nanoscale. **2008**, 377-420	3
232	Carbon Nanotubes as SPM Tips: Mechanical Properties of Nanotube Tips and Imaging. **2008**, 137-181	5
231	Scanning Probe Microscopy on Polymer Solar Cells. **2008**, 183-215	1
230	Scanning Probe Microscopy Principle of Operation, Instrumentation, and Probes. **2008**, 37-110	2
229	Piezoresponse Force Microscopy of Functional Ceramics. **2009**, 229-282	1
228	Scanning Probe Microscopy Principle of Operation, Instrumentation, and Probes. **2010**, 573-617	11
227	Contact Potential Difference Techniques as Probing Tools in Tribology and Surface Mapping. **2010**, 687-720	5
226	Conductive Atomic-Force Microscopy Investigation of Nanostructures in Microelectronics. **2011**, 691-721	15
225	Scanning Probe Microscopy Principle of Operation, Instrumentation, and Probes. **2011**, 37-110	13
224	Progress in Experimental Measurements of the SurfaceSurface Casimir Force: Electrostatic Calibrations and Limitations to Accuracy. **2011**, 219-248	11
223	Mesoscopic Work Function Measurement by Scanning Tunneling Microscopy. **2000**, 167-191	3
222	Related Scanning Techniques. **1992**, 209-231	3
221	Study of Thin Organic Films by Various Scanning Force Microscopes. **1995**, 567-591	6
220	Optical Near-Field Imaging by Force Detection. **1995**, 109-122	1
219	Effects of dielectric stoichiometry on the photoluminescence properties of encapsulated WSe2 monolayers. **2018**, 11, 1399-1414	10
218	SXM: An Introduction. **1993**, 1-124	3

217	Photoinduced Electron Transfer in Monolayer Assemblies and its Application to Artificial Photosynthesis and Molecular Devices. **1995**, 239-277	11
216	EXTENSIONS OF STM. **1993**, 77-94	1
215	Microscale surface potential gradient disturbances observed in bilayer graphene. **2020**, 510, 145504	1
214	Surface-enhanced Raman scattering of graphene caused by self-induced nanogating by GaN nanowire array. **2018**, 128, 70-77	6
213	Restoration of the graphitic structure by defect repair during the thermal reduction of graphene oxide. **2020**, 166, 74-90	49
212	Effect of carbo-nitride-rich and oxide-rich inclusions on the pitting susceptibility of depleted uranium. **2017**, 124, 160-166	6
211	Effect of surface potential distribution on corrosion behavior of Cu/Al interface in Cu wire bonding applications. **2020**, 113, 113942	2
210	Design and implementation of a Kelvin microprobe for contact potential measurements at the submicron scale. **1994**, 5, 509-517	10
209	Atomic-level characterization of liquid/solid interface. **2020**, 29, 116803	2
208	Atomic structure, work function and magnetism in layered single crystal VOCl. **2021**, 8, 015027	7
207	Surface potential measurement by heterodyne frequency modulation Kelvin probe force microscopy in MHz range. **2020**, 4, 075015	4
206	Calibrated Kelvin-probe force microscopy of 2D materials using Pt-coated probes. **2020**, 4, 095025	3
205	Interaction of organic molecules with layer silicates, oxides and hydroxides and related surface-nano-characterization techniques. 313-334	4
204	Application of Kelvin Probe Microscopy for Nitride Heterostructures. **2005**, 108, 541-554	2
203	Implementation of NSOM to Biological Samples. **2012**, 121, 533-538	4
202	In Vitro Biocompatibility of Si Alloyed Multi-Principal Element Carbide Coatings. **2016**, 11, e0161151	30
201	Latent Fingerprint Detection Using a Scanning Kelvin Microprobe. **2001**, 46, 15103J	82
200	Graphene layers fabricated from the Ni/a-SiC bilayer precursor. **2013**, 16, 322-330	2

199	Light-induced mass transport in amorphous chalcogenides/gold nanoparticles composites. **2013**, 16, 354-361		2
198	Macroscopic versus microscopic photovoltaic response of heterojunctions based on mechanochemically prepared nanopowders of kesterite and n-type semiconductors. **2017**, 20, 418-423		2
197	Morphology and optical constants of G▯nanocrystalline films deposited on S▯(001). **2016**, 8(23), 218-222		1
196	Surface Potential and Topography Measurements of Gallium Nitride on Sapphire by Scanning Probe Microscopy. **2016**, 136, 96-101		1
195	An Electrostatic Force Probe for Surface Profile Measurement in Noncontact Condition. **2013**, 7, 714-719		3
194	Contact Electrification by Quantum-Mechanical Tunneling. **2019**, 2019, 6528689		10
193	A mode-localized MEMS electrical potential sensor based on three electrically coupled resonators. **2017**, 6, 1-8		10
192	Surface potential contrasts between 1-alkene, 1-thiol and 1-alcohol self-assembled monolayers on silicon (111) substrate. *Japanese Journal of Applied Physics*, **2020**, 59, SDDC06	1.4	1
191	Measurements of Electrostatic Potential Across p▯ Junctions on Oxidized Si Surfaces by Scanning Multimode Tunneling Spectroscopy. *Japanese Journal of Applied Physics*, **2011**, 50, 04DA04	1.4	8
190	Surface Potential Measurement of Tris(8-hydroxyquinolinato)aluminum and Bis[N-(1-naphthyl)-N-phenyl]benzidine Thin Films Fabricated on Indium▯in Oxide by Kelvin Probe Force Microscopy. *Japanese Journal of Applied Physics*, **2011**, 50, 071601	1.4	4
189	Photoassisted Kelvin Probe Force Microscopy on Multicrystalline Si Solar Cell Materials. *Japanese Journal of Applied Physics*, **2011**, 50, 08LA05	1.4	5
188	Single-Electron Charging in Phosphorus Donors in Silicon Observed by Low-Temperature Kelvin Probe Force Microscope. *Japanese Journal of Applied Physics*, **2011**, 50, 08LB10	1.4	3
187	Development of Scanning Tunneling Potentiometry for Semiconducting Samples. *Japanese Journal of Applied Physics*, **2012**, 51, 125202	1.4	2
186	Probing of Surface Potential Using Atomic Force Microscopy. **2014**, 44, 100-104		3
185	Kelvin probe force microscopy for material characterization.. **2022**, 71, i165-i173		0
184	Improving the Performance of the ToGoFET Probe: Advances in Design, Fabrication, and Signal Processing. **2021**, 12,		
183	Open-loop amplitude-modulation Kelvin probe force microscopy operated in single-pass PeakForce tapping mode. **2021**, 12, 1115-1126		0
182	Far-Infrared Near-Field Optical Imaging and Kelvin Probe Force Microscopy of Laser-Crystallized and -Amorphized Phase Change Material GeSbTe. **2021**, 21, 9012-9020		1

181	Local Ga Ion Implantation as a Source of Diverse Ferroelectric Properties of Hafnium Oxide. 2100485	1
180	Imaging Techniques for Detecting Prokaryotic Viruses in Environmental Samples. **2021**, 13,	2
179	Present State of the Surface Potential Measurements by Kelvin Force Microscopy. Potential Measurement of Si Nano-structures by Kelvin Probe Force Microscopy.. **2001**, 22, 301-308	
178	Present State of the Surface Potential Measurements by Kelvin Force Microscopy. Atomic-scale Potential Imaging by Ultrahigh Vacuum Scanning Probe Microscopy.. **2001**, 22, 292-300	
177	Present State of the Surface Potential Measurements by Kelvin Force Microscopy. Potential Measurements by KFM on InAs Thin Film Surfaces Grown on (110) GaAs Substrates.. **2001**, 22, 309-314	2
176	Present State of the Surface Potential Measurements by Kelvin Force Microscopy. Analysis of Corrosion Reaction on Metal by Kelvin Force Microscopy.. **2001**, 22, 282-291	2
175	Integrated and Functional Probes. **2002**, 111-135	1
174	Capacitive Probe Microscopy.	
173	Nanoscale Characterization of Nanostructures and Nanodevices by Scanning Probe Microscopy. **2003**, 191-211	
172	AFM Observation of Ge/Si(105) Surfaces. **2005**, 26, 486-491	
171	Chapter 4 Use of tip-enhanced vibrational spectroscopy for analytical applications in chemistry, biology, and materials science. **2006**, 115-155	
170	Application of Noncontact Atomic Force Microscopy to Catalyst Research. **2006**, 27, 348-353	
169	Investigations of Organic Materials by Kelvin Probe Force Microscopy using Frequency Modulation Method. **2007**, 28, 253-263	2
168	Electrostatic Force Imaging of Nano-scale Adsorbates on Insulating Substrates-Application to Biological Molecules-. **2008**, 29, 246-252	
167	Nanomechanical Interaction between a Tip and a Sample with Changing Bias Voltage Observed by Using Scanning Probe Microscopy. **2008**, 29, 239-245	
166	Surface features on Sahara soil dust particles made visible by atomic force microscope (AFM) phase images.	
165	Atomic Manipulation on an Insulator Surface. **2009**, 217-226	
164	Colossal Permittivity in Advanced Functional Heterogeneous Materials: The Relevance of the Local Measurements at Submicron Scale. **2010**, 613-646	

163	Microscopic Investigation of SiC Epitaxial Layers On-Axis 4H-SiC Substrates Using Kelvin Probe Force Microscopy. **2009**, 116, S-69-S-71		
162	Established and Emerging Techniques of Studying Latex Film Formation. **2010**, 27-94		
161	Microscopic Electrical Characterization of Inorganic Semiconductor-Based Solar Cell Materials and Devices Using AFM-Based Techniques. **2011**, 723-790		
160	Chapter 3:Surface Charge Measurements on Biomaterials in Dry and Wet Conditions. **2011**, 26-44		
159	Scanning Probe Methods for Characterization of Electrical Propeties in Nano-Materials. 163-173		
158	Interference Phenomena Observed on an Atomic Force Microscope Cantilever by Laser Confocal Microscopy. *Japanese Journal of Applied Physics*, **2011**, 50, 08LB17	1.4	1
157	Material and Doping Contrast in III/V Nanowires Probed by Kelvin Probe Force Microscopy. **2012**, 185-206		
156	Potential Characterization of Interconnect Corrosion by Kelvin Probe and Electrostatic Force Microscopies. *Japanese Journal of Applied Physics*, **2012**, 51, 04DB05	1.4	
155	Scanning Probe Microscopy History, Background, and State of the Art. 499-538		0
154	General Introduction. **2013**, 1-16		
153	Vapor Phase Deposition Synthesis of Bismuth-Based Topological Insulator Nanoplates and Their Electrostatic Properties. **2013**, 281-304		
152	Work function engineering of MoS2 nanoflakes with different layers. **2013**,		
151	Temporal Changes of Charge Distribution in High Density Self-aligned Si-based Quantum Dots as Evaluated by AFM/KFM. **2013**, 38, 393-396		
150	Single-Electron Tunneling Transistors Utilizing Individual Dopant Potentials. **2013**, 305-324		1
149	Silicon-Based Single-Dopant Devices and Integration with Photons. **2013**,		
148	Carbon Nanotubes for Photovoltaics. **2014**, 268-311		
147	Study of Langmuir-Blodgett films with various scanning probe microscopes. **1994**, 489-494		
146	Related Scanning Techniques. **1995**, 209-231		

145 Imaging Local Electric Forces in Organic Thin Films by Scanning Maxwell Stress Microscopy. **1995**, 113-118 1

144 Photons and Local Probes. **1998**, 155-174

143 Metal-Molecule Heterostructures: Charge Transfer. 2522-2534

142 Electrostatic and Thermodynamic Potentials of Electrons in Materials. **2014**, 11-44

141 EVALUATION OF TRIBOELECTRICITY IN DIAMOND-LIKE COATINGS CONTAINING SILVER NANOPARTICLES USING AFM AND KPFM.

140 Trend of Toxic Nanomaterial Detecting Sensors. **2014**, 24, 977-984

139 MICROSCOPIA DE FORˆ □A ATˆ □MICA: UMA PODEROSA FERRAMENTA PARA CARACTERIZAˆ □□O ELˆ □TRICA. **2015**, 43-74

138 Reconstruction of dopant vertical position from Kelvin probe force microscope images. **2016**, 373-378

137 Dopant-Atom Silicon Tunneling Nanodevices. **2015**, 181-206

136 Electrical Homo-Junction Delineation Techniques: A Comparative Study. **2016**, 07, 326-347 1

135 Doped Two-Dimensional Silicon Nanostructures as a Platform for Next-Generation Sensors. **2017**, 143-148

134 Nanolithography and Decoration of Generated Nanostructures by Dye Molecules. **2016**, 295-352

133 Simulation and Verification of Tip-Induced Polarization During Kelvin Probe Force Microscopy Measurements on Film Capacitors. **2017**, 215-221

132 Kelvin Probe. **2016**, 692-695

131 Analytical Nanoscopic Techniques: Nanoscale Properties. 211-228

130 Influence of Softening Temperature of Azobenzene Polymers and External Electric Field on Diffraction Efficiency of Polarization Holograms. **2017**, 12, 58-63

129 Recent progress in nanoelectrical characterizations of CdTe and Cu(In,Ga)Se2. **2017**,

128 Scanning Probe Microscopy. **2018**, 23-41

127	Introduction to Scanning Probe Microscopy. **2019**, 709-724		
126	Tactile Surface Metrology. **2019**, 43-55		
125	Recent advances in perovskite solar cells: Space potential and optoelectronic conversion mechanism. **2019**, 68, 158401		0
124	Photovoltaic Properties of Polymer Composites with a Tetranuclear Copper Complex. **2020**, 87, 229-235		
123	Frequency-modulation Kelvin probe force microscopy under tapping mode operation for surfaces with large protrusions. *Japanese Journal of Applied Physics*, **2020**, 59, 090906	1.4	2
122	Enhanced terahertz radiation from InAs (100) with an embedded InGaAs hole blocking layer. **2020**, 28, 25750-25756		0
121	Low cost electrical probe station using etched tungsten nanoprobes: role of cathode geometry. **2020**, 1, 020042		
120	Electrophysical properties of Janus-like silver nanoparticles. 1000, 012011		
119	Observation of Power MOSFET Composed of Silicon Carbide with a Planar Type in the Voltage Applying State Using a Scanning Probe Microscope. **2021**,		
118	Charge Transfer at the Hetero-Interface of WSe2/InSe Induces Efficient Doping to Achieve Multi-Functional Lateral Homo-Junctions. **2021**, 7, 2100584		1
117	Scanning probe microscopy for electrocatalysis. **2021**, 4, 3483-3514		1
116	Scanning Capacitance Force Microscopy and Kelvin Probe Force Microscopy of Nanostructures Embedded in SiO2. **2005**, 405-411		
115	Scanning Probe Microscopy on Low-Dimensional Electron Systems in IIIV Semiconductors. **2007**, 349-371		1
114	Probing Electrical Transport Properties at the Nanoscale by Current-Sensing Atomic Force Microscopy. **2008**, 421-450		1
113	High resolution Kelvin force microscopy. 743-744		
112	Impurity Doping in Semiconductor Nanowires. **2021**, 143-181		0
111	Space-charge accumulation and band bending at conductive P3HT/PDIF-CN2 interfaces investigated by scanning-Kelvin probe microscopy.		0
110	Real-space imaging of anisotropic charge of hole by means of Kelvin probe force microscopy. **2021**, 374, 863-867		18

109	Electrostatic Discovery Atomic Force Microscopy. **2021**,		1
108	Microwave impedance microscopy and its application to quantum materials.		4
107	Study of High-Low KPFM on a pn-Patterned Si Surface.. **2022**,		0
106	Surface Contamination: A Natural Way toward High-Resolution Electric Force Microscopy in Contact-Resonant Mode.		
105	Photoluminescence and charge transfer in the prototypical 2D/3D semiconductor heterostructure MoS2/GaAs. *Applied Physics Letters*, **2021**, 119, 233101	3.4	0
104	Patterning Functionalized Surfaces of 2D Materials by Nanoshaving. **2022**, 5, 23		
103	Applications of Atomic Force Microscopy in Corrosion Research. **2022**, 187-201		
102	Electronic structure of epitaxially grown and regrown GaN pn junctions characterized by scanning Kelvin probe and capacitance microscopy. **2022**, 131, 015704		1
101	A GaSe/Si-based vertical 2D/3D heterojunction for high-performance self-driven photodetectors. **2022**, 4, 479-490		1
100	Research on multi-frequency EFM dynamic process measurement method based on wavelet transform. **2022**,		
99	In Situ Atomic Force Microscopy Analysis of the Corrosion Processes at the Buried Interface of an Epoxy-like Model Organic Film and AA2024-T3 Aluminum Alloy. 2101342		0
98	Quantitative analysis on surface potentials of impurities and intermetallic compounds dispersed in Mg alloys using scanning Kelvin probe force microscopy and ultraviolet photoelectron spectroscopy. *Materials Chemistry and Physics*, **2022**, 279, 125760	4.4	1
97	Experimental verification of a new theory of acoustic signal detection in the inner ear related to noncontact detection of potential changes on the tectorial membrane. *Applied Acoustics*, **2022**, 190, 108659	3.1	
96	Vertical field inhomogeneity associated with threading dislocations in GaN high electron mobility transistor epitaxial stacks. *Applied Physics Letters*, **2021**, 119, 243502	3.4	3
95	charge transport imaging of atomically thin dopant nanostructures in silicon.. *Nanoscale*, **2022**,	7.7	0
94	Application of the Standard Tapping Mode of an Atomic-Force Microscope for Local Investigations of the Electronic System of Carbon Nanotubes under Vacuum Conditions. *Instruments and Experimental Techniques*, **2022**, 65, 152-156	0.5	
93	Implementation of an experimental setup to qualitatively detect hydrogen permeation along grain boundaries in nickel using Scanning Kelvin Probe Force Microscopy under varying atmospheres. *International Journal of Hydrogen Energy*, **2022**,	6.7	3
92	Surface potential and local conductivity measurements of micropatterned aromatic monolayers covalently attached to n-Si(111) via Si-C and Si-O bonds. *Japanese Journal of Applied Physics*,	1.4	

91	Time-resolved photo-assisted Kelvin probe force microscopy on Cu(In,Ga)Se2 solar cells. *Japanese Journal of Applied Physics*,	1.4	
90	Peak-tracking scanning capacitance force microscopy with multibias modulation technique. *Measurement Science and Technology*, **2022**, 33, 065405	2	1
89	Albumin Protein Adsorption on CoCrMo Implant Alloy: Impact on the Corrosion Behaviour at Localized Scale. *Journal of the Electrochemical Society*, **2022**, 169, 031507	3.9	1
88	Highly Reliable Flexible Device with a Charge Compensation Layer.. *ACS Applied Materials & Interfaces*, **2022**,	9.5	0
87	Single CdSe Quantum Dots Positioned in Nanostructured Heterogeneous Templates: Implications for High-Precision Nanoassembly. *ACS Applied Nano Materials*,	5.6	2
86	Resolving surface potential variation in Ge/MoS2 heterostructures with Kelvin probe force microscopy. *AIP Advances*, **2021**, 11, 125105	1.5	0
85	[illegible]HPHT-[illegible] [illegible]*Reports National Academy of Science of Ukraine*, **2021**, 68-77	0.2	
84	Nonlinear optical techniques for characterization of organic electronic and photonic devices. *European Physical Journal: Special Topics*, 1	2.3	0
83	Review[illegible]Multiscale Characterization of Li-Ion Batteries through the Combined Use of Atomic Force Microscopy and X-ray Microscopy and Considerations for a Correlative Analysis of the Reviewed Data. *Journal of the Electrochemical Society*, **2021**, 168, 126522	3.9	2
82	Simultaneous mapping of nanoscale dielectric, electrochemical, and ferroelectric surface properties of van der Waals layered ferroelectric via advanced SPM. *Applied Physics Letters*, **2021**, 119, 252905	3.4	0
81	Nanotribological properties and scratch resistance of MoS2 bilayer on a SiO2/Si substrate. *Friction*,	5.6	
80	Local galvanic corrosion analysis on cast Mg-Ca binary alloy using scanning Kelvin probe force microscopy. *Materials Letters*, **2022**, 319, 132266	3.3	1
79	Data_Sheet_1.pdf. **2019**,		
78	Laser-Crystallized Epitaxial Germanium on Silicon-Based Near-infrared Photodetector. *IEEE Sensors Journal*, **2022**, 1-1	4	2
77	Investigating the Role of Copper in Arsenic Doped Cd(Se,Te) Photovoltaics. *SSRN Electronic Journal*,	1	
76	Electronic Interactions and Stability Issues at the Copper-Graphene Interface in Air and in Alkaline Solution Under Electrochemical Control. *SSRN Electronic Journal*,	1	
75	Resolution of Intramolecular Dipoles and a Push-Back Effect of Individual Molecules on a Metal Surface. *Journal of Physical Chemistry C*, **2022**, 126, 7667-7673	3.8	
74	Electron Transfer Driven by Tip-Induced Flexoelectricity in Contact Electrification. *Journal Physics D: Applied Physics*,	3	3

73	Enhancing sensitivity in atomic force microscopy for planar tip-on-chip probes.. *Microsystems and Nanoengineering*, **2022**, 8, 51	7.7	
72	Imaging Spatial Distribution of Photogenerated Carriers in Monolayer MoS2 with Kelvin Probe Force Microscopy. *ACS Applied Materials & Interfaces*,	9.5	0
71	Corrosion behaviors of 2205 duplex stainless steel in biotic and abiotic NaCl solutions. *Construction and Building Materials*, **2022**, 342, 127699	6.7	0
70	Investigation of a vertical 2D/3D semiconductor heterostructure based on GaSe and Ga2O3. *Journal Physics D: Applied Physics*,	3	0
69	Atomic force microscopy in energetic materials research: A review. *Energetic Materials Frontiers*, **2022**,	3.3	1
68	DC-Bias-free Surface Potential Measurements by Heterodyne AC Kelvin Probe Force Microscopy. **2022**,		1
67	Three-Dimensional Kelvin Probe Force Microscopy. *ACS Applied Materials & Interfaces*,	9.5	1
66	Evaluation and Analytical Method for Hydrogen Embrittlement. *Zairyo/Journal of the Society of Materials Science, Japan*, **2022**, 71, 645-651	0.1	
65	Investigating the role of copper in arsenic doped Cd(Se,Te) photovoltaics. *Solar Energy Materials and Solar Cells*, **2022**, 246, 111886	6.4	2
64	Revealing and Controlling Energy Barriers and Valleys at Grain Boundaries in Ultrathin Organic Films. **2022**, 18, 2200605		
63	Electrostatic Actuation of AFM Cantilevers in Aqueous Solutions. **2022**,		
62	Direct measurement of surface photovoltage by AC bias Kelvin probe force microscopy. 13, 712-720		1
61	Understanding the Feedback Circuit in an Atomic Force Microscope. **2022**, 31, 99-102		
60	Multidimensionality of the Contact Potential Difference at the Nanoscale in Inorganic Oxides. **2022**, 4, 4085-4093		
59	Electronic gap characterization at mesoscopic scale via scanning probe microscopy under ambient conditions. **2022**, 13,		0
58	Advanced Atomic Force Microscopies and their Applications in Two-Dimensional Materials: A Review.		0
57	Scanning probe microscopy in probing low-dimensional carbon-based nanostructures and nanomaterials. **2022**, 1, 032301		1
56	Photovoltaic and photothermal effects induced by visible laser radiation in atomic force microscopy probes. **2022**, 241, 113601		

55	A universal substrate for the nanoscale investigation of two-dimensional materials. **2022**, 604, 154585	
54	Electronic interactions and stability issues at the copper-graphene interface in air and in alkaline solution under electrochemical control. **2022**, 431, 141145	0
53	Influence of self-doping on band-edges and Fermi energy of CsPbBr3. **2022**, 248, 112014	0
52	Progress of functionalized atomic force microscopy in the study of the properties of nanometric dielectric materials. **2022**, 0	0
51	Progress of functionalized atomic force microscopy in the study of the properties of nanometric dielectric materials. **2022**, 0	0
50	Two-liquid wetting and phase electrowetting as a probe for surface chemistry of hydrophobic materials. **2022**, 24, 23323-23328	0
49	Optimisation method for carbon black distribution of´polypropylene-based semi-conductive screen materials and its effect on charge emission behaviour at screen/insulation interface.	0
48	Electrostatic potential difference between tumor and paratumor regulates cancer stem cell behavior and prognose tumor spread.	0
47	Comparing the performance of single and multifrequency Kelvin probe force microscopy techniques in air and water. 13, 922-943	1
46	Synergistic Effect of Work Function and Acoustic Impedance Mismatch for Improved Thermoelectric Performance in GeTe-WC Composite. **2022**, 14, 44527-44538	0
45	Bayesian Active Learning for Scanning Probe Microscopy: From Gaussian Processes to Hypothesis Learning. **2022**, 16, 13492-13512	0
44	Nanoscale electric field imaging with an ambient scanning quantum sensor microscope. **2022**, 8,	2
43	Formation of CuIn(1⊠)GaxS2 Thin Films through a Solution Approach: Nonlinear Variation of Fermi Energy and Band Gap Bowing. **2022**, 38, 11909-11916	0
42	Time-dependent measurement of plasmon-induced charge separation on a gold nanoparticle/TiO2 interface by electrostatic force microscopy. **2022**, 12,	0
41	Local Impedance Measurement by Direct Detection of Oscillating Electrostatic Potential Using Kelvin Probe Force Microscopy.	0
40	Nanoscale electrical characterization of graphene-based materials by atomic force microscopy.	0
39	AFM advanced modes for dental and biomedical applications. **2022**, 136, 105475	1
38	AC Kelvin Probe Force Microscopy Enables Charge Mapping in Water.	1

37	Influence of Imaging Parameters on AFM Surface Potential Measurements in Aqueous Solutions. **2022**,	1
36	Local Tuning of the Surface Potential in Silicon Carriers by Ion Beam Induced Intrinsic Defects. **2022** , 12, 289-305	0
35	Molecular Doping of CVD-Graphene Surfaces by Perfluoroalkyl-Substituted Perylene Diimides Derivatives. **2022**, 12, 4239	0
34	Cellulose Nanocrystals Examined by Atomic Force Microscopy: Applications and Fundamentals. **2022**, 2, 1789-1818	2
33	Structural Characterization of Defects in the Topological Insulator Bi2Se3 at the Picometer Scale.	0
32	Observing reduced field fluctuation in interfacial engineered organic–inorganic dielectric nanocomposite for enhanced breakdown strength. **2022**, 121, 243905	0
31	Quantitative measurement of local conductivity of SnO2 nanobelt field effect transistor utilizing microwave atomic force microscopy. **2023**, 16, 016501	0
30	The conductivity and electrophysical characteristics of Janus-like TaSi2/Si nanoparticles. **2023**, 38, 015019	0
29	Dual-bias modulation heterodyne Kelvin probe force microscopy in FM mode. **2022**, 121, 241602	0
28	Utilizing the surface potential of a solid electrolyte region as the potential reference in Kelvin probe force microscopy. 13, 1558-1563	0
27	Extended Work Function Shift of Large-Area Biofunctionalized Surfaces Triggered by a Few Single-Molecule Affinity Binding Events. 2201829	0
26	AtomAI framework for deep learning analysis of image and spectroscopy data in electron and scanning probe microscopy. **2022**, 4, 1101-1112	2
25	Heterodyne AC Kelvin Probe Force Microscopy for Nanoscale Surface Potential Imaging in Liquids. **2023**, 72, 1-8	0
24	Methods—On the Application of Ambient Scanning Kelvin Probe Force Microscopy to Understand Micro-Galvanic Corrosion Phenomena: Interpretation and Challenges.	0
23	Electrochemical scanning probe microscopies for artificial photosynthesis.	0
22	Structural identification of graphene films and nanoislands on 6H-SiC(0001) by direct height measurement.	0
21	Recent Advances in In Situ/Operando Surface/Interface Characterization Techniques for the Study of Artificial Photosynthesis. **2023**, 11, 16	0
20	Characterization of 2D transition metal dichalcogenides. **2023**, 97-139	0

19	Morpho-structural Characterization. **2023**, 61-87	0
18	Microstructure characterization and corrosion behavior of Alx(CoCrFeNi)100▯ (x´=´0, 5, 10, 15, 20) high entropy alloys in 0.5´M´H2SO4 solution. **2023**, 944, 169247	0
17	Experimental Guides for Metallic Materials: 1. Microstructural Observation: 1-9 Other Microstructural Observation Techniques. **2023**, 62, 113-121	0
16	Constructing Robust Bi Active Sites In Situ on ▯Bi2O3 for Efficient and Selective Photoreduction of CO2 to CH4 via Directional Transfer of Electrons. **2023**, 13, 2513-2522	0
15	Methods for Characterization of Surface Charge and Solid▯Liquid Interaction Studies of Biomaterials. **2023**, 111-164	0
14	Imaging ferroelectric domains with a single-spin scanning quantum sensor.	0
13	Bubbles as a platform for investigating work function tunability of 2D materials under biaxial strains. **2023**, 60, 101978	0
12	A simple KPFM-based approach for electrostatic- free topographic measurements: the case of MoS2 on SiO2. **2023**, 34, 215705	0
11	Learning the right channel in multimodal imaging: automated experiment in piezoresponse force microscopy. **2023**, 9,	1
10	GaN-on-Si Quasi-Vertical p-n Diode With Junction Termination Extension Based on Hydrogen Plasma Treatment and Diffusion. **2023**, 70, 1636-1640	0
9	In Situ and Operando Characterizations of Metal Halide Perovskite and Solar Cells: Insights from Lab-Sized Devices to Upscaling Processes. **2023**, 123, 3160-3236	0
8	Accurate Electrostatic Force Measurements by Atomic Force Microscopy Using Proper Distance Control. **2023**, 72, 1-8	0
7	Nanoscale Corrosion Mechanism at Grain Boundaries of the Al▯Zn▯Mg Alloy Investigated by Open-Loop Electric Potential Microscopy. **2023**, 127, 5281-5288	0
6	Progress and Insight of Van der Waals Heterostructures Containing Interlayer Transition for Near Infrared Photodetectors. 2300686	0
5	Investigation of ultrafast excited-state dynamics at the nanoscale with terahertz field-induced electron tunneling and photon emission. **2023**, 133, 110903	0
4	Work Function: Fundamentals, Measurement, Calculation, Engineering, and Applications. **2023**, 19,	1
3	Visualizing the atomic-scale origin of metallic behavior in Kondo insulators. **2023**, 379, 1214-1218	0
2	Carrier Dynamics in the Space Charge Layer of MoS2 Flakes Studied by Time-Resolved ▯Surface Photovoltage. **2023**, 127, 7319-7326	0

1	Recent advances in the application of scanning probe microscopy in interfacial electroanalytical chemistry. **2023**, 938, 117443	0